TOTAL DOSE RADIATION TEST REPORT

Part Type : Am29F016D

2M x 8-Bit Flash Memory

Package : TSOP- 40

Manufacturer: AMD

Report Reference : ESA_QCA0314T_C

Issue : 01

Date : July 23rd 2003

ESA Contract No 13528/99/NL/MV COO-13 dated 11/10/02

European Space Agency Contract Report

The work described in this report was done under ESA contract.
Responsibility for the contents resides in the author or organization that prepared it

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CHANGE RECORD

Issue	Date	Page	DESCRIPTION OF CHANGES
01	July 23rd 2003	All	Original Issue.

TOTAL DOSE RADIATION TEST REPORT
on
AMD Am29F016D 2M x 8-Bit Flash Memory

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1 Abstract

Under ESA Contract No 13528/99/NL/MV COO-13 dated 11/10/02 covering "Radiation Evaluation of COTS Semiconductor Components: “Radiation evaluation of parts for new VME design“, Flash Memories were radiation assessed.

Results from these assessments covering Single Event Effects on AMD Am29F016D and Am29F032B can be found in ESA-QCA0211S_C and on STMicroelectronics on M29F016B and M29F032D in ESA_QCA0212S_C.
Here Total Ionizing Dose effects (TID) will be reported for AMD Am29F016D.

2 Introduction

A total dose radiation verification test of the AMD Am29F016D 2M x 8-Bit Flash Memory has been performed with an accumulated dose of about 10 Krad(Si) at an average dose rate of 300 rad(Si)/hour, in response to ESA Contract No 13528/99/NL/MV COO-13 dated 11/10/02.

The purpose of this test was to evaluate total dose withstanding of this component, to investigate its suitability for being used in space applications. This test was conducted on samples provided by ESA.
Test has been performed in accordance with Hirex total dose irradiation test plan referenced: TDP n° 0080 issue 01 dated 03/06/2003.
A complete set of electrical measurements together with graphical representation of measured parameters with respect to total dose received, are provided for all samples.

3 Applicable and Reference Documents

3.1 Applicable Documents

- Hirex Total Dose Irradiation Test Plan TDP n° 0080 issue 01 dated 03/06/2003.
- Hirex proposal: HRX/PRO/0509 dated 16/09/2002.

3.2 Reference Documents

- Datasheet from AMD dated 03/23/2001, Pub.: 21444, Rev.: E, Amend.: +2

4 Test Samples

6 samples of the Am29F016D device were tested (4 ON + 1 OFF + 1 control sample).

TID Serial Number	Allocation
Ref. 1	Control
2	Bias ON
3	Bias ON
4	Bias ON
5	Bias ON
6	Bias OFF

Identification of the Am29F016D is given below:

Part Number: AM29F016D

Top Marking: AM29F016D -70E4C
0121FPA H 1999
AMD

Date Code: 1999

Project: NA

5 Experimental Conditions

5.1 Radiation Source Dose Rate and Annealing

The dose exposures were performed at CERT-ONERA. In this irradiation facility, a Cobalt 60 source is used with the possibility to vary the dose rate by simply adjusting the distance to the source.
The irradiation conditions used for this test are provided in the following table:

Irradiation Steps	Dose rate	Annealing steps	Temperature
krads	krads/h	hours	°C
0			
5	0,30		25
10	0,30		25
		24	25
		168	100

5.2 Bias during Dose Exposures and Measurements conditions

5.2.1 Bias conditions

During exposures dedicated test board was used mounted on a special board-holder made for irradiation. The test board allowed to bias the devices in accordance with the electrical circuit provided in Figure 1.
During annealing steps the same stress conditions were applied at 25°C and 100°C.

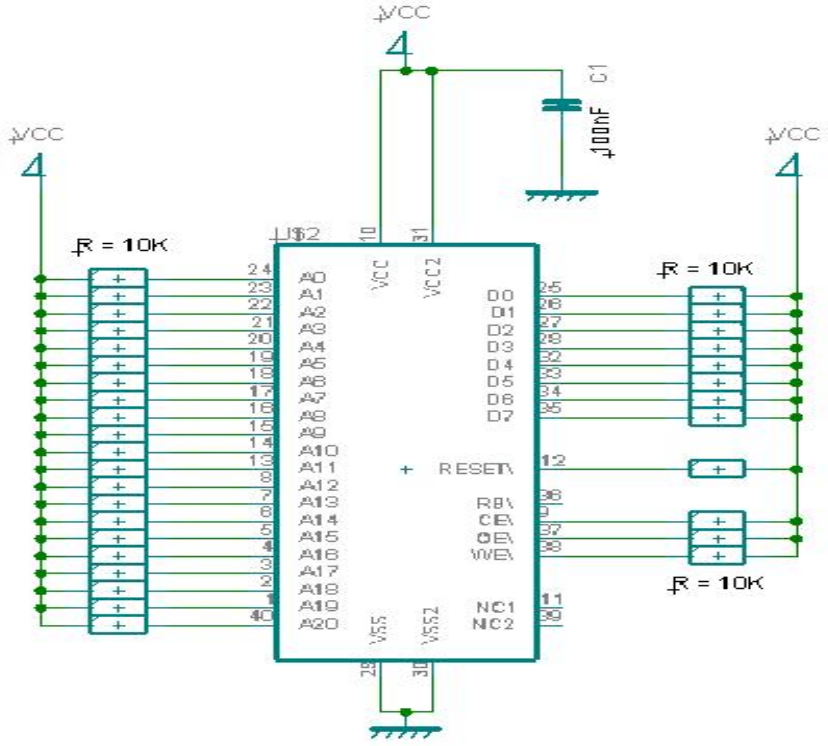


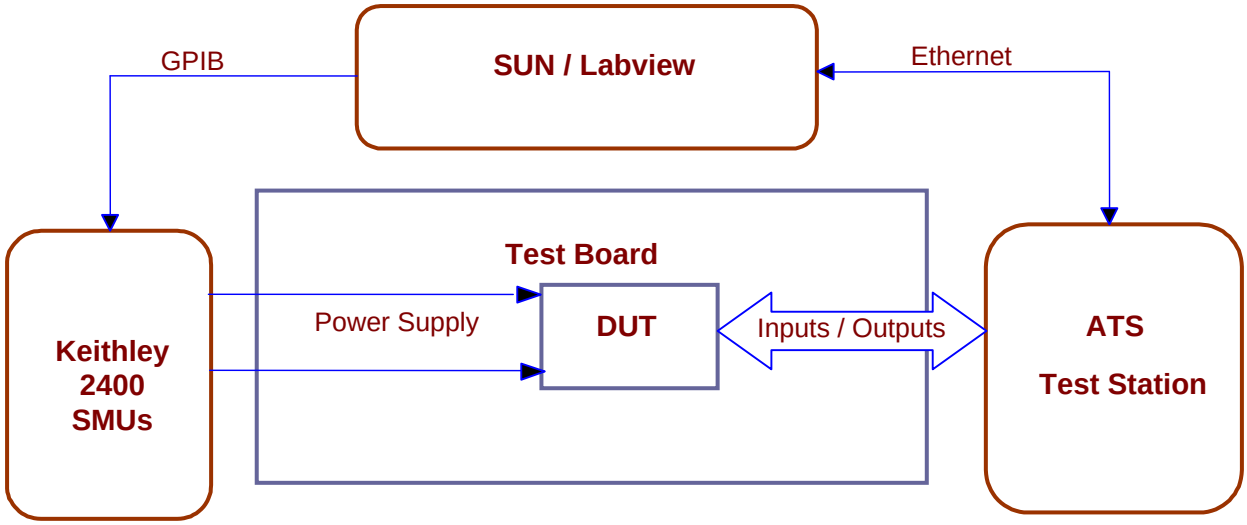
Figure 1 : Bias Conditions during Irradiation Exposures and Annealing steps

5.2.2 Electrical Measurements

Electrical parameters test program principle for Am29F016D is provided in Figure 2.

The test Setup for this DUT includes an IMS ATS Test Station, a SUN workstation, a DC test system Keithley 2400 and a dedicated test fixture board.

Figure 2 : Am29F016D test program principle



Electrical parameters test conditions and limits used for performing this test are given in the following tables.

Electrical Parameters to be tested					
Parameter Description	Symbol	Test Condition	Min.	Max.	Unit
Functional Test (Read & Write)	FT_00	Pattern : 00	-	-	-
Functional Test (Erase & Read)	FT_FF	Pattern : FF	-	-	-
Retention Test (Read)	FT_Ret	Patterns : 00; $V_{IN} = V_{IL}$ or V_{IH} (Note 1)	-	-	-
Input Leakage Current	I_{LI}	$V_{IN} = V_{CC}$ or Gnd, $V_{CC} = V_{CCMax}$	-1	1	µA
Supply Current (Read)	$I_{CC}1$	CE* = V_{IL}, OE* = V_{IH}	-	40	mA
Supply Current (Program/Erase)	$I_{CC}2$	CE* = V_{IL}, OE* = V_{IH}	-	60	mA
Standby Current (CE* Controlled)	$I_{CC}3$	CE* = V_{IH}, RESET* = V_{IH}, $V_{CC} = V_{CCMax}$	-	1	mA
Input Low Voltage	V_{IL}	-	0.8	-	V
Input High Voltage	V_{IH}	-	-	2	V
Output Low Voltage	V_{OL}	I_{OL} = 12mA, $V_{CC} = V_{CCMin}$	-	0.45	V
Output High Voltage	V_{OH}	I_{OH} = -2.5mA, $V_{CC} = V_{CCMin}$	0.85 V_{CC}	-	V
Read Cycle Time	t_{AVAV}	-	-	70	ns
Address to Output Delay	t_{AVQV}	CE* = V_{IL}, OE* = V_{IL}	-	70	ns
Chip Enable to Output Delay	t_{ELQV}	OE* = V_{IL}	-	70	ns
Output Enable to Output Delay	t_{GLQV}	-	-	40	ns
Output Enable to Output HiZ	t_{GHQZ}	-	-	20	ns
Chip Enable to Output HiZ	t_{EHQZ}	-	-	20	ns
Write Cycle Time	t_{AVAV}	-	-	70	ns
Address Setup Time	t_{AVWL}	-	-	0	ns
Address Hold Time	t_{WLAX}	-	-	40	ns
Data Setup Time	t_{DVWH}	-	-	40	ns
Data Hold Time	t_{WHDX}	-	-	0	ns
CE* Setup Time	t_{ELWL}	-	-	0	ns
CE* Hold Time	t_{WHEH}	-	-	0	ns
Write Pulse Width	t_{WLWH}	-	-	40	ns
Write Pulse Width High	t_{WHWL}	-	-	20	ns

Note 1: This test consists in Writing 00 at exposure Step S-1 and Reading memory content at exposure Step S.

Table 1: Measured electrical parameters

5.2.3 Electrical measurements test sequence

The test sequence organisation applied for each memory at any electrical measurement steps after exposures and annealing is provided in figure 3.

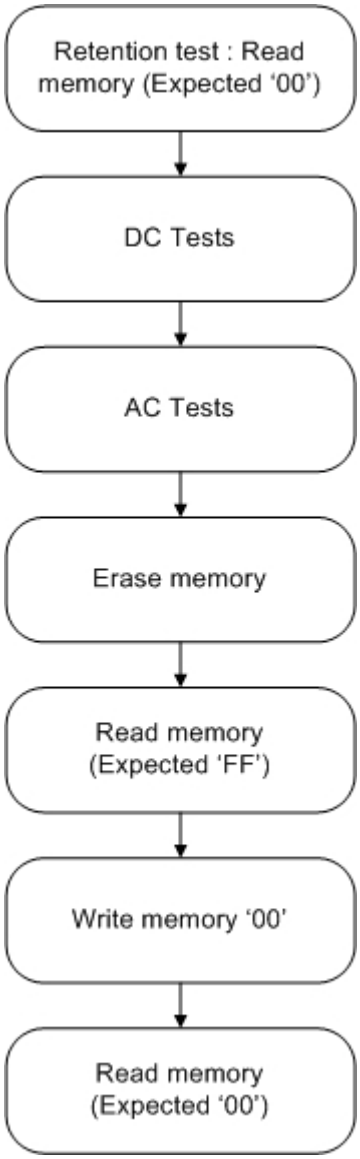


Figure 3 : Electrical measurements test sequence

6 Conclusion

A Total Ionizing Dose verification test was carried out by Hirex Engineering under ESA contract on the AMD Am29F016D 2M x 8-Bit Flash Memory in TSOP-40 package.

5 samples plus one control sample were used during testing. They were exposed to radiation using a Co-60 source at an average dose rate of 300 rad(Si)/hour at room temperature.

Functionality of the memories was lost at 10Krad(Si) step. Thus, writing into and reading from the memory became impossible.
It should be noted that no recovery of this functionality (including retention) was observed during annealing steps.

The most affected parameter was I_{CC3} (standby current CE* controlled) at 10Krad(Si), where a significant drift was observed but within specification limits. This parameter has partially recovered during annealing.

In correlation with functional failures observed, some parameters were found out of specification limits, in particular: Output low and high voltages (V_{oh}, V_{ol}) and most of the timing parameters.

It is important to highlight that sample #6 biased off during exposures and annealing remained functional and did not exhibit any parametric failure during testing.

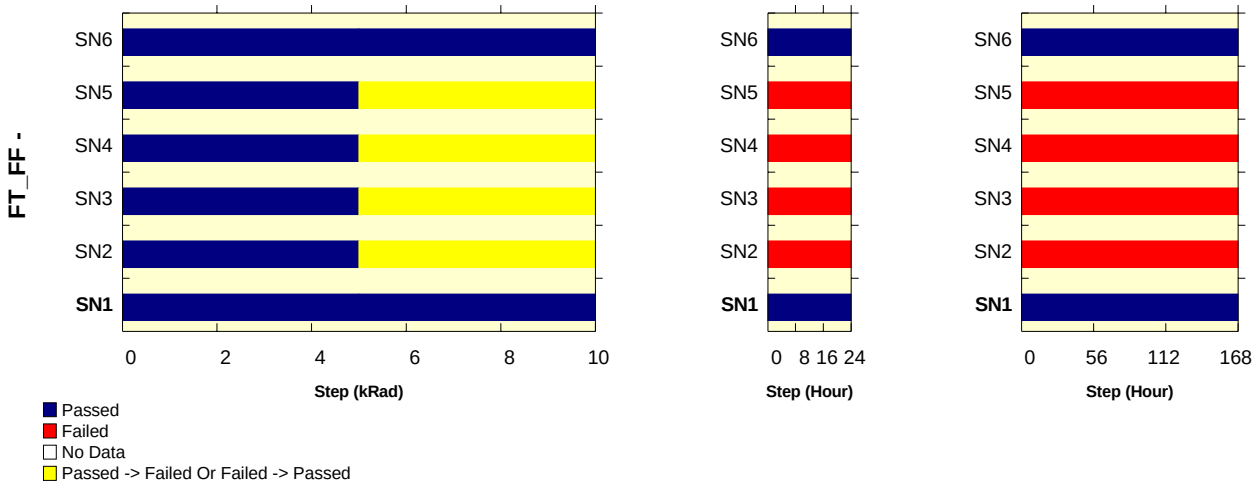
All other parameters remained within specification limits all along testing.

7 Test Results

Test results including tables and graphics are provided in this section for each measured parameter.

Note on tables and graphics:
In some cases, it may appear missing points in tables and graphs, this situation corresponds to a failure corresponding to an out of range measurement.
I_{LIL} data has been inverted for a better visibility with log plots.

Test conditions : TID
Parameter : Functional Test : FT_FF
Pattern = FF. Vin = Vil or Vih
Unit :
No spec limit applicable.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	PASS	PASS	PASS
SN2	PASS	PASS	FAIL
SN3	PASS	PASS	FAIL
SN4	PASS	PASS	FAIL
SN5	PASS	PASS	FAIL
SN6	PASS	PASS	PASS

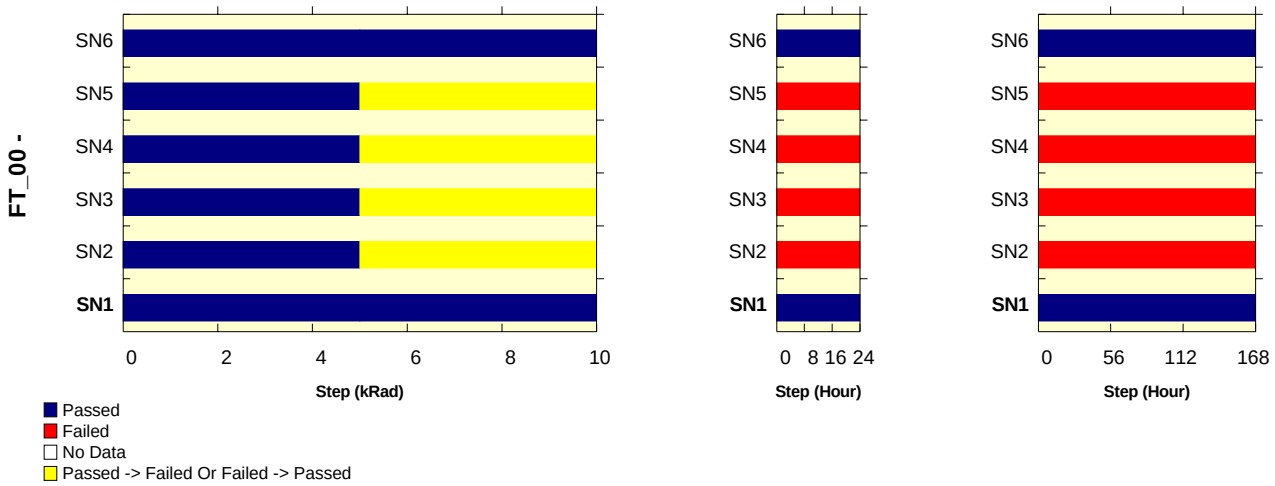
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	PASS	PASS
SN2	FAIL	FAIL
SN3	FAIL	FAIL
SN4	FAIL	FAIL
SN5	FAIL	FAIL
SN6	PASS	PASS

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	PASS	PASS
SN2	FAIL	FAIL
SN3	FAIL	FAIL
SN4	FAIL	FAIL
SN5	FAIL	FAIL
SN6	PASS	PASS

Test conditions : TID
Parameter : Functional Test : FT_00
Pattern = 00, Vin = Vil or Vih
Unit :
No spec limit applicable.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	PASS	PASS	PASS
SN2	PASS	PASS	FAIL
SN3	PASS	PASS	FAIL
SN4	PASS	PASS	FAIL
SN5	PASS	PASS	FAIL
SN6	PASS	PASS	PASS

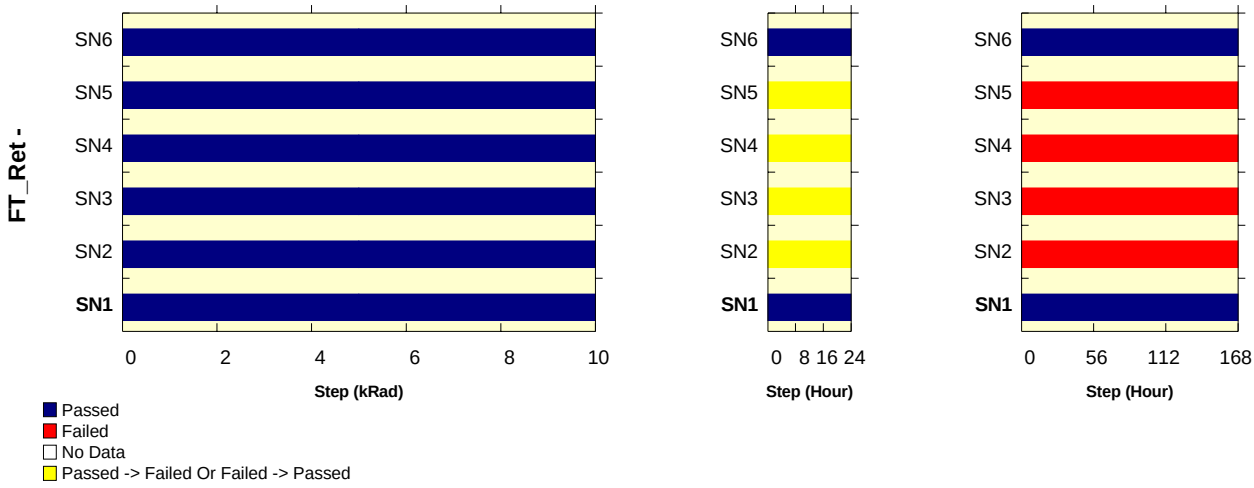
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	PASS	PASS
SN2	FAIL	FAIL
SN3	FAIL	FAIL
SN4	FAIL	FAIL
SN5	FAIL	FAIL
SN6	PASS	PASS

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	PASS	PASS
SN2	FAIL	FAIL
SN3	FAIL	FAIL
SN4	FAIL	FAIL
SN5	FAIL	FAIL
SN6	PASS	PASS

Test conditions : TID
Parameter : Functional Test : FT_Ret
Retention Test. Pattern = 00. Vin = Vil or Vih
Unit :
No spec limit applicable.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	PASS	PASS	PASS
SN2	PASS	PASS	PASS
SN3	PASS	PASS	PASS
SN4	PASS	PASS	PASS
SN5	PASS	PASS	PASS
SN6	PASS	PASS	PASS

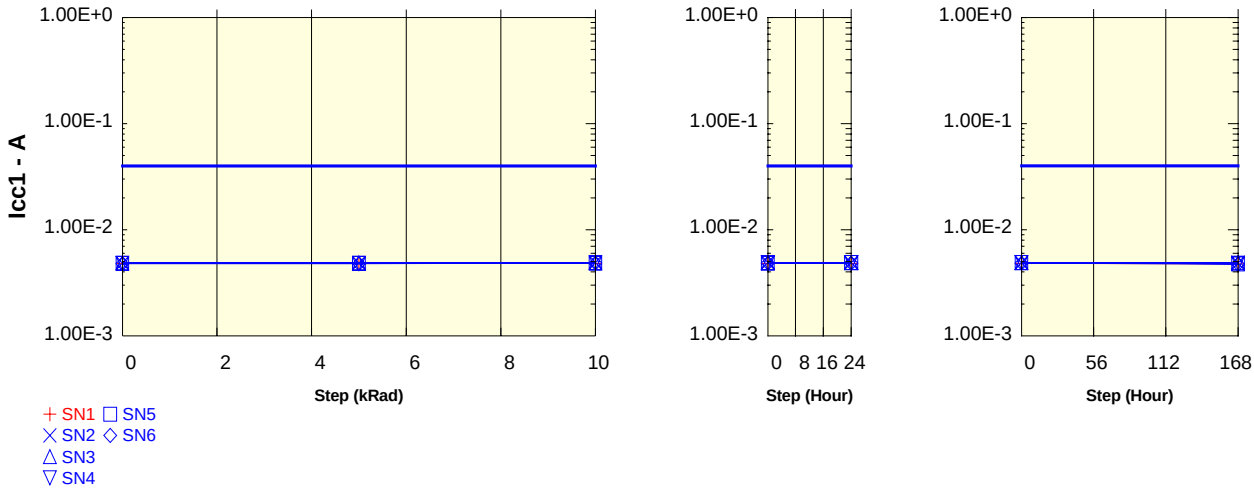
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	PASS	PASS
SN2	PASS	FAIL
SN3	PASS	FAIL
SN4	PASS	FAIL
SN5	PASS	FAIL
SN6	PASS	PASS

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	PASS	PASS
SN2	FAIL	FAIL
SN3	FAIL	FAIL
SN4	FAIL	FAIL
SN5	FAIL	FAIL
SN6	PASS	PASS

Test conditions : TID
Parameter : Supply Current (Read) : Icc1
CE* = Vil. OE* = Vih
Unit : A
Spec Limit Max : 4.00E-2
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.82E-3	4.82E-3	4.82E-3
SN2	4.84E-3	4.84E-3	4.89E-3
SN3	4.86E-3	4.86E-3	4.90E-3
SN4	4.82E-3	4.82E-3	4.87E-3
SN5	4.82E-3	4.82E-3	4.85E-3
SN6	4.80E-3	4.80E-3	4.84E-3
Statistics			
Min	4.80E-3	4.80E-3	4.84E-3
Max	4.86E-3	4.86E-3	4.90E-3
Mean	4.83E-3	4.83E-3	4.87E-3
Sigma	2.25E-5	2.26E-5	2.56E-5

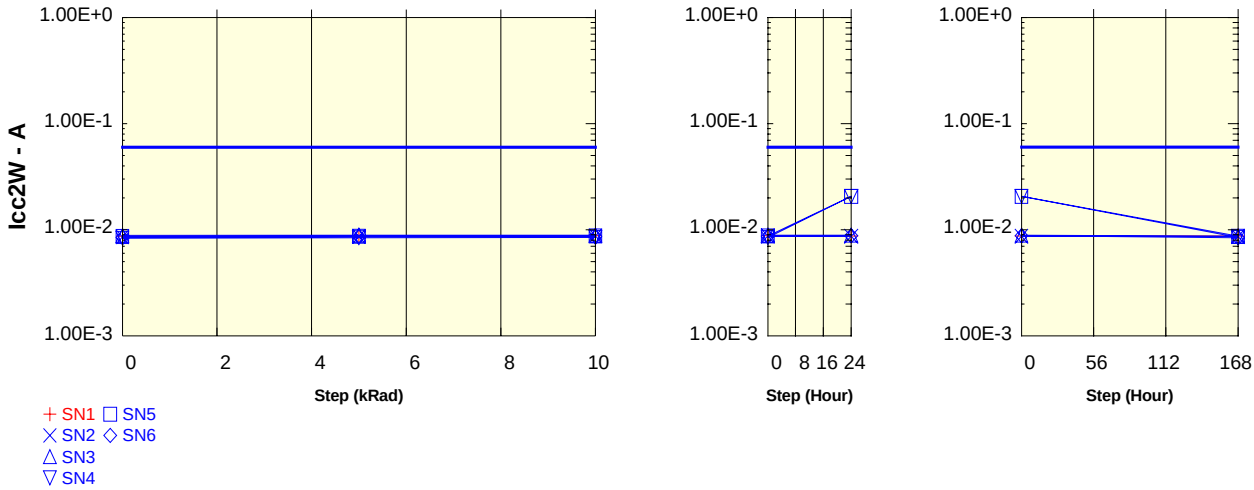
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.82E-3	4.82E-3
SN2	4.89E-3	4.89E-3
SN3	4.90E-3	4.90E-3
SN4	4.87E-3	4.91E-3
SN5	4.85E-3	4.90E-3
SN6	4.84E-3	4.83E-3
Statistics		
Min	4.84E-3	4.83E-3
Max	4.90E-3	4.91E-3
Mean	4.87E-3	4.89E-3
Sigma	2.56E-5	3.04E-5

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.82E-3	4.77E-3
SN2	4.89E-3	4.85E-3
SN3	4.90E-3	4.89E-3
SN4	4.91E-3	4.86E-3
SN5	4.90E-3	4.76E-3
SN6	4.83E-3	4.75E-3
Statistics		
Min	4.83E-3	4.75E-3
Max	4.91E-3	4.89E-3
Mean	4.89E-3	4.82E-3
Sigma	3.04E-5	6.23E-5

Test conditions : TID
Parameter : Supply Current (Program) : Icc2W
CE* = Vil. OE* = Vih
Unit : A
Spec Limit Max : 6.00E-2
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	8.70E-3	8.64E-3	8.77E-3
SN2	8.56E-3	8.66E-3	8.72E-3
SN3	8.83E-3	8.89E-3	8.91E-3
SN4	8.29E-3	8.42E-3	8.46E-3
SN5	8.65E-3	8.71E-3	8.76E-3
SN6	8.51E-3	8.58E-3	8.63E-3
Statistics			
Min	8.29E-3	8.42E-3	8.46E-3
Max	8.83E-3	8.89E-3	8.91E-3
Mean	8.57E-3	8.65E-3	8.70E-3
Sigma	1.95E-4	1.73E-4	1.66E-4

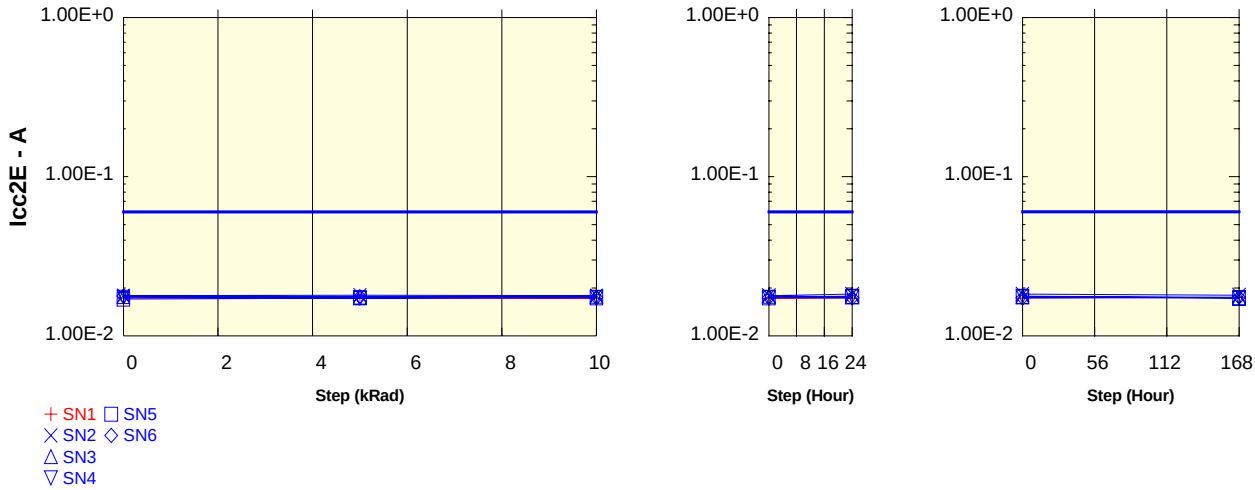
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	8.77E-3	8.75E-3
SN2	8.72E-3	8.70E-3
SN3	8.91E-3	8.87E-3
SN4	8.46E-3	2.06E-2
SN5	8.76E-3	2.06E-2
SN6	8.63E-3	8.77E-3
Statistics		
Min	8.46E-3	8.70E-3
Max	8.91E-3	2.06E-2
Mean	8.70E-3	1.35E-2
Sigma	1.66E-4	6.50E-3

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	8.75E-3	8.72E-3
SN2	8.70E-3	8.65E-3
SN3	8.87E-3	8.70E-3
SN4	2.06E-2	8.45E-3
SN5	2.06E-2	8.70E-3
SN6	8.77E-3	8.40E-3
Statistics		
Min	8.70E-3	8.40E-3
Max	2.06E-2	8.70E-3
Mean	1.35E-2	8.58E-3
Sigma	6.50E-3	1.44E-4

Test conditions : TID
Parameter : Supply Current (Erase) : Icc2E
CE* = Vil. OE* = Vih
Unit : A
Spec Limit Max : 6.00E-2
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.73E-2	1.73E-2	1.71E-2
SN2	1.79E-2	1.80E-2	1.79E-2
SN3	1.77E-2	1.75E-2	1.78E-2
SN4	1.75E-2	1.73E-2	1.75E-2
SN5	1.70E-2	1.73E-2	1.73E-2
SN6	1.78E-2	1.76E-2	1.74E-2
Statistics			
Min	1.70E-2	1.73E-2	1.73E-2
Max	1.79E-2	1.80E-2	1.79E-2
Mean	1.76E-2	1.75E-2	1.76E-2
Sigma	3.38E-4	2.93E-4	2.24E-4

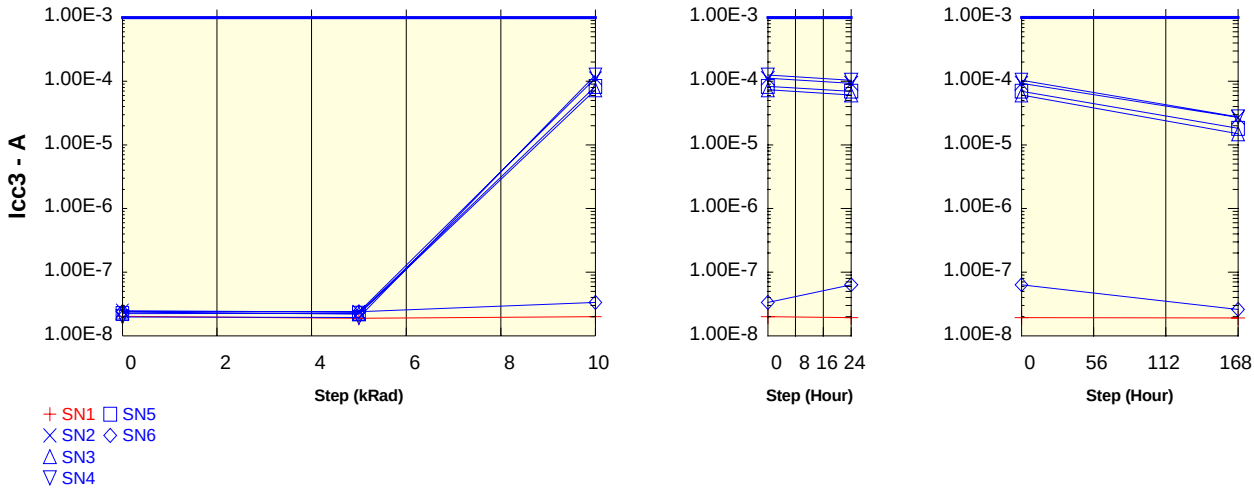
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.71E-2	1.73E-2
SN2	1.79E-2	1.83E-2
SN3	1.78E-2	1.76E-2
SN4	1.75E-2	1.77E-2
SN5	1.73E-2	1.76E-2
SN6	1.74E-2	1.73E-2
Statistics		
Min	1.73E-2	1.73E-2
Max	1.79E-2	1.83E-2
Mean	1.76E-2	1.77E-2
Sigma	2.24E-4	3.66E-4

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.73E-2	1.74E-2
SN2	1.83E-2	1.80E-2
SN3	1.76E-2	1.73E-2
SN4	1.77E-2	1.74E-2
SN5	1.76E-2	1.72E-2
SN6	1.73E-2	1.74E-2
Statistics		
Min	1.73E-2	1.72E-2
Max	1.83E-2	1.80E-2
Mean	1.77E-2	1.75E-2
Sigma	3.66E-4	3.07E-4

Test conditions : TID
Parameter : Standby Current (CE* Controlled) : Icc3
CE* = Vih. RESET* = Vih. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-3
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.03E-8	1.89E-8	2.00E-8
SN2	2.47E-8	2.37E-8	1.11E-4
SN3	2.36E-8	2.21E-8	7.35E-5
SN4	1.99E-8	1.94E-8	1.25E-4
SN5	2.24E-8	2.27E-8	8.27E-5
SN6	2.42E-8	2.39E-8	3.34E-8
Statistics			
Min	1.99E-8	1.94E-8	3.34E-8
Max	2.47E-8	2.39E-8	1.25E-4
Mean	2.29E-8	2.23E-8	7.86E-5
Sigma	1.92E-9	1.83E-9	4.87E-5

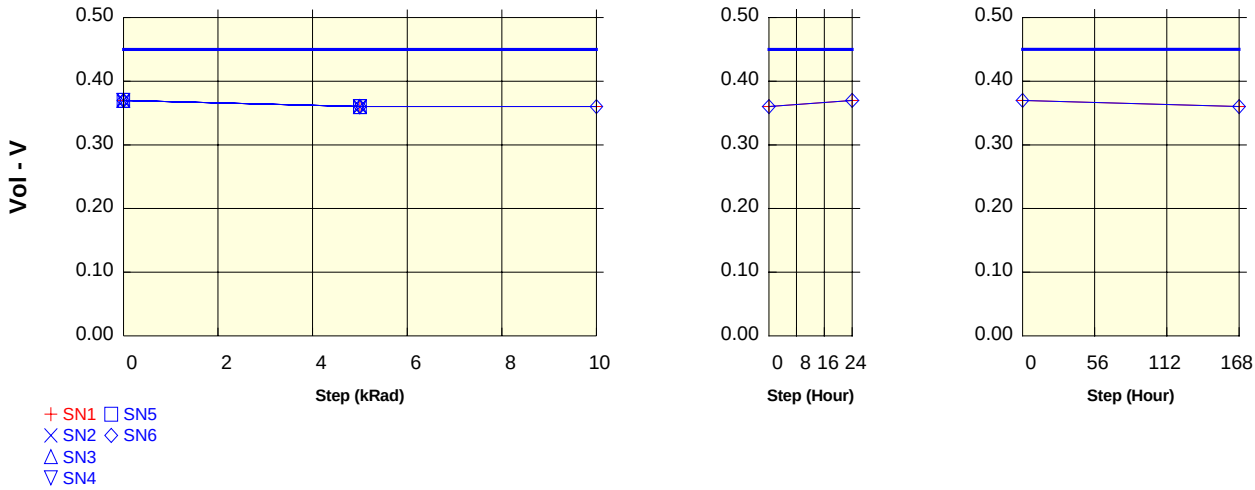
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-8	1.93E-8
SN2	1.11E-4	9.28E-5
SN3	7.35E-5	6.09E-5
SN4	1.25E-4	1.04E-4
SN5	8.27E-5	6.97E-5
SN6	3.34E-8	6.35E-8
Statistics		
Min	3.34E-8	6.35E-8
Max	1.25E-4	1.04E-4
Mean	7.86E-5	6.55E-5
Sigma	4.87E-5	4.05E-5

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.93E-8	1.91E-8
SN2	9.28E-5	2.69E-5
SN3	6.09E-5	1.49E-5
SN4	1.04E-4	2.76E-5
SN5	6.97E-5	1.82E-5
SN6	6.35E-8	2.61E-8
Statistics		
Min	6.35E-8	2.61E-8
Max	1.04E-4	2.76E-5
Mean	6.55E-5	1.75E-5
Sigma	4.05E-5	1.12E-5

Test conditions : TID
Parameter : Output Low Voltage : VolDQ7
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.37	0.36	0.36
SN2	0.37	0.36	
SN3	0.37	0.36	
SN4	0.37	0.36	
SN5	0.37	0.36	
SN6	0.37	0.36	0.36
Statistics			
Min	0.37	0.36	0.00
Max	0.37	0.36	0.36
Mean	0.37	0.36	0.07
Sigma	0.00	0.00	0.16

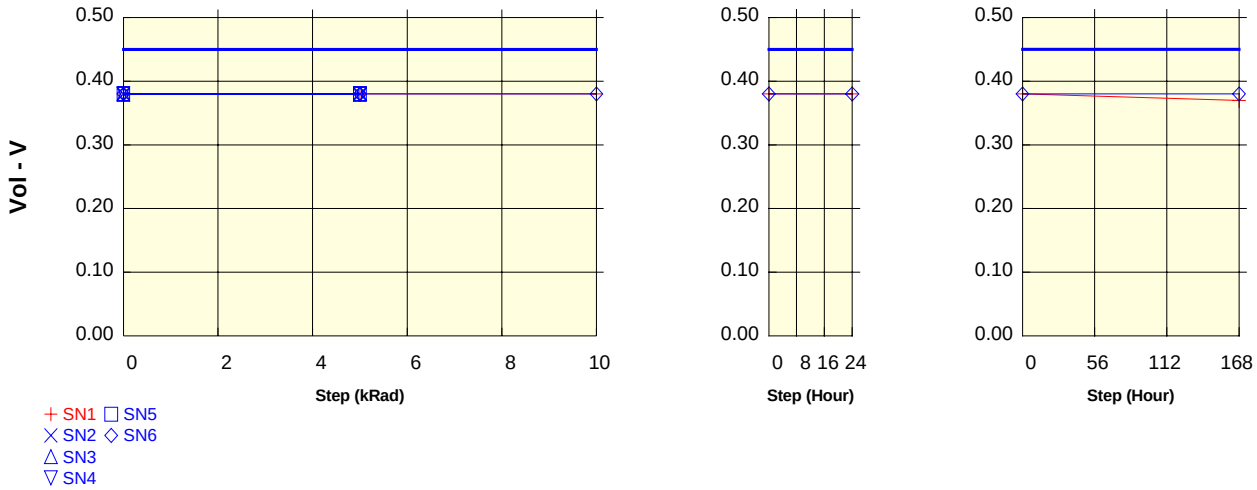
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.36	0.37
SN2		
SN3		
SN4		
SN5		
SN6	0.36	0.37
Statistics		
Min	0.00	0.00
Max	0.36	0.37
Mean	0.07	0.07
Sigma	0.16	0.17

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.37	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.37	0.36
Statistics		
Min	0.00	0.00
Max	0.37	0.36
Mean	0.07	0.07
Sigma	0.17	0.16

Test conditions : TID
Parameter : Output Low Voltage : VolDQ6
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.38	0.38	0.38
SN2	0.38	0.38	
SN3	0.38	0.38	
SN4	0.38	0.38	
SN5	0.38	0.38	
SN6	0.38	0.38	0.38
Statistics			
Min	0.38	0.38	0.00
Max	0.38	0.38	0.38
Mean	0.38	0.38	0.08
Sigma	0.00	0.00	0.17

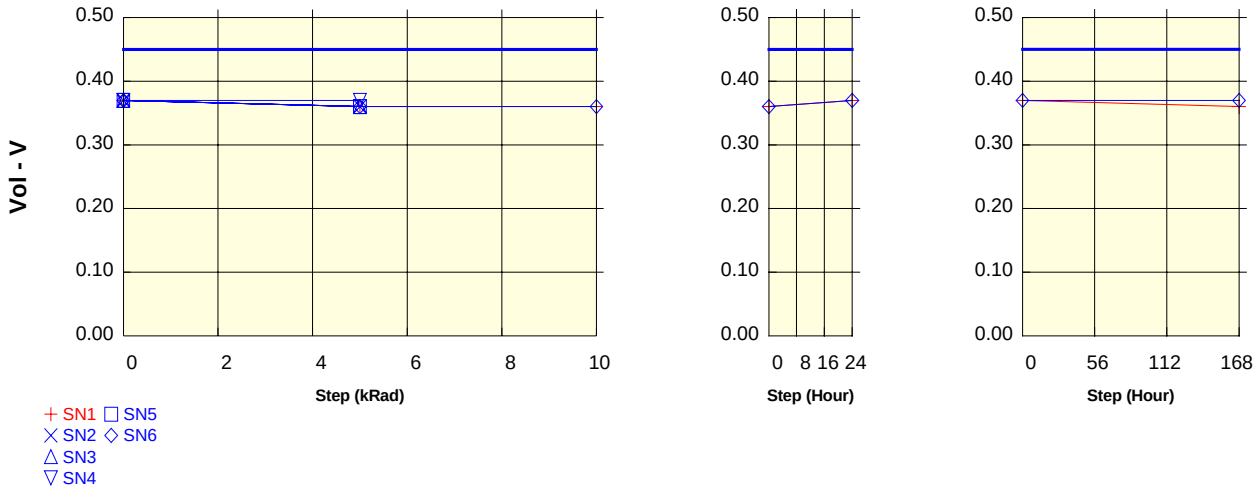
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.38	0.38
SN2		
SN3		
SN4		
SN5		
SN6	0.38	0.38
Statistics		
Min	0.00	0.00
Max	0.38	0.38
Mean	0.08	0.08
Sigma	0.17	0.17

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.38	0.37
SN2		
SN3		
SN4		
SN5		
SN6	0.38	0.38
Statistics		
Min	0.00	0.00
Max	0.38	0.38
Mean	0.08	0.08
Sigma	0.17	0.17

Test conditions : TID
Parameter : Output Low Voltage : VolDQ5
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.37	0.36	0.36
SN2	0.37	0.36	
SN3	0.37	0.36	
SN4	0.37	0.37	
SN5	0.37	0.36	
SN6	0.37	0.36	0.36
Statistics			
Min	0.37	0.36	0.00
Max	0.37	0.37	0.36
Mean	0.37	0.36	0.07
Sigma	0.00	0.00	0.16

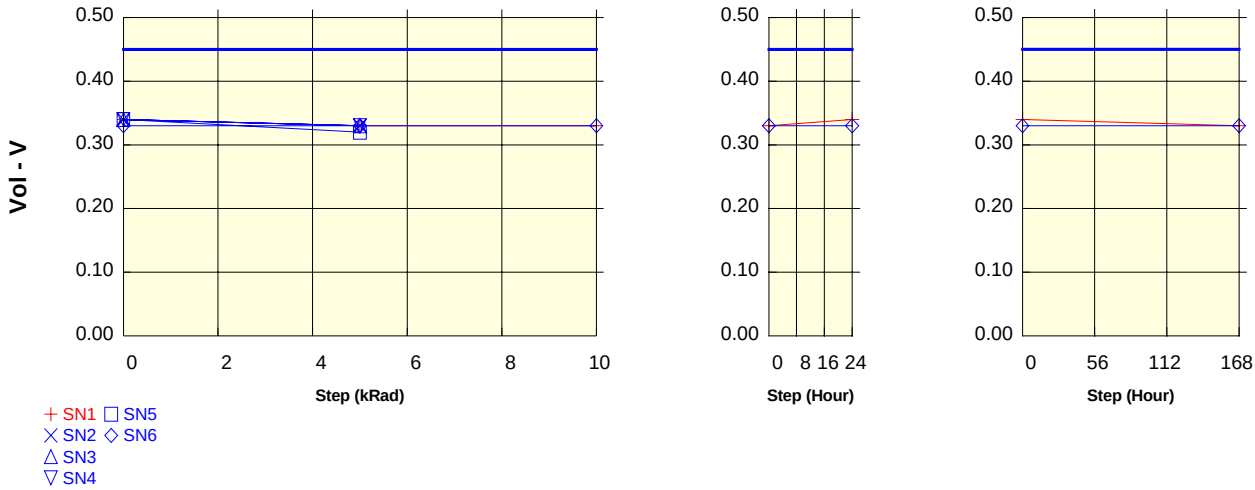
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.36	0.37
SN2		
SN3		
SN4		
SN5		
SN6	0.36	0.37
Statistics		
Min	0.00	0.00
Max	0.36	0.37
Mean	0.07	0.07
Sigma	0.16	0.17

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.37	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.37	0.37
Statistics		
Min	0.00	0.00
Max	0.37	0.37
Mean	0.07	0.07
Sigma	0.17	0.17

Test conditions : TID
Parameter : Output Low Voltage : VolDQ4
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.34	0.33	0.33
SN2	0.34	0.33	
SN3	0.34	0.33	
SN4	0.34	0.33	
SN5	0.34	0.32	
SN6	0.33	0.33	0.33
Statistics			
Min	0.33	0.32	0.00
Max	0.34	0.33	0.33
Mean	0.34	0.33	0.07
Sigma	0.00	0.00	0.15

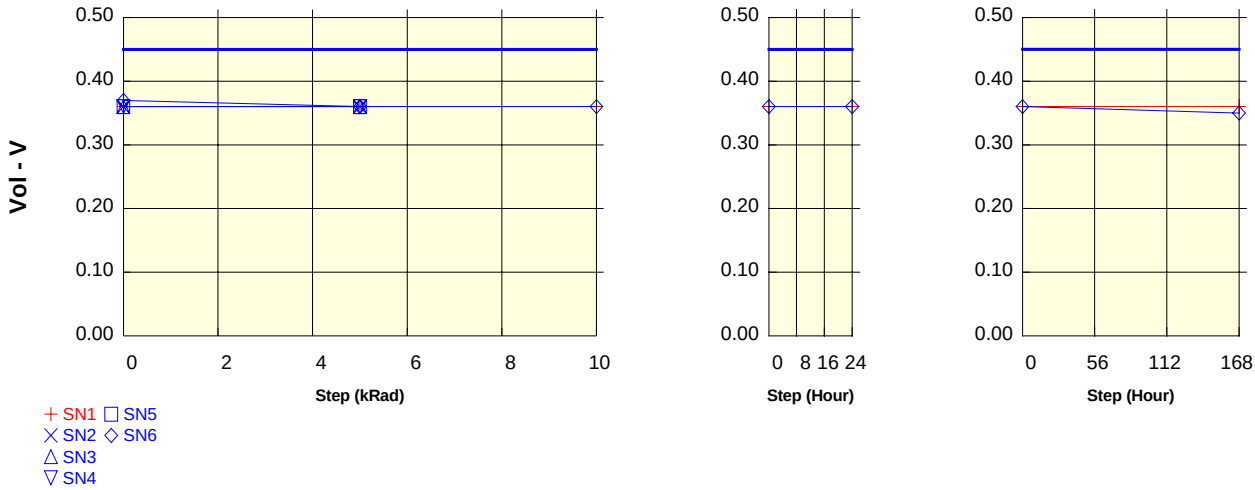
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.33	0.34
SN2		
SN3		
SN4		
SN5		
SN6	0.33	0.33
Statistics		
Min	0.00	0.00
Max	0.33	0.33
Mean	0.07	0.07
Sigma	0.15	0.15

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.34	0.33
SN2		
SN3		
SN4		
SN5		
SN6	0.33	0.33
Statistics		
Min	0.00	0.00
Max	0.33	0.33
Mean	0.07	0.07
Sigma	0.15	0.15

Test conditions : TID
Parameter : Output Low Voltage : VolDQ3
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.36	0.36	0.36
SN2	0.36	0.36	
SN3	0.36	0.36	
SN4	0.36	0.36	
SN5	0.36	0.36	
SN6	0.37	0.36	0.36
Statistics			
Min	0.36	0.36	0.00
Max	0.37	0.36	0.36
Mean	0.36	0.36	0.07
Sigma	0.00	0.00	0.16

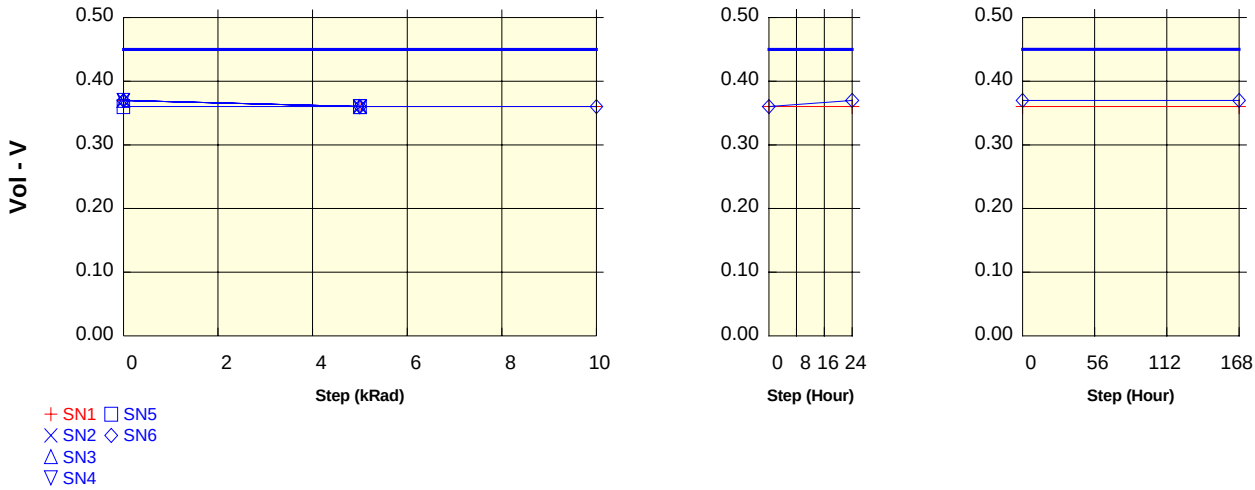
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.36	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.36	0.36
Statistics		
Min	0.00	0.00
Max	0.36	0.36
Mean	0.07	0.07
Sigma	0.16	0.16

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.36	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.36	0.35
Statistics		
Min	0.00	0.00
Max	0.36	0.35
Mean	0.07	0.07
Sigma	0.16	0.16

Test conditions : TID
Parameter : Output Low Voltage : VolDQ2
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.37	0.36	0.36
SN2	0.37	0.36	
SN3	0.37	0.36	
SN4	0.37	0.36	
SN5	0.36	0.36	
SN6	0.37	0.36	0.36
Statistics			
Min	0.36	0.36	0.00
Max	0.37	0.36	0.36
Mean	0.37	0.36	0.07
Sigma	0.00	0.00	0.16

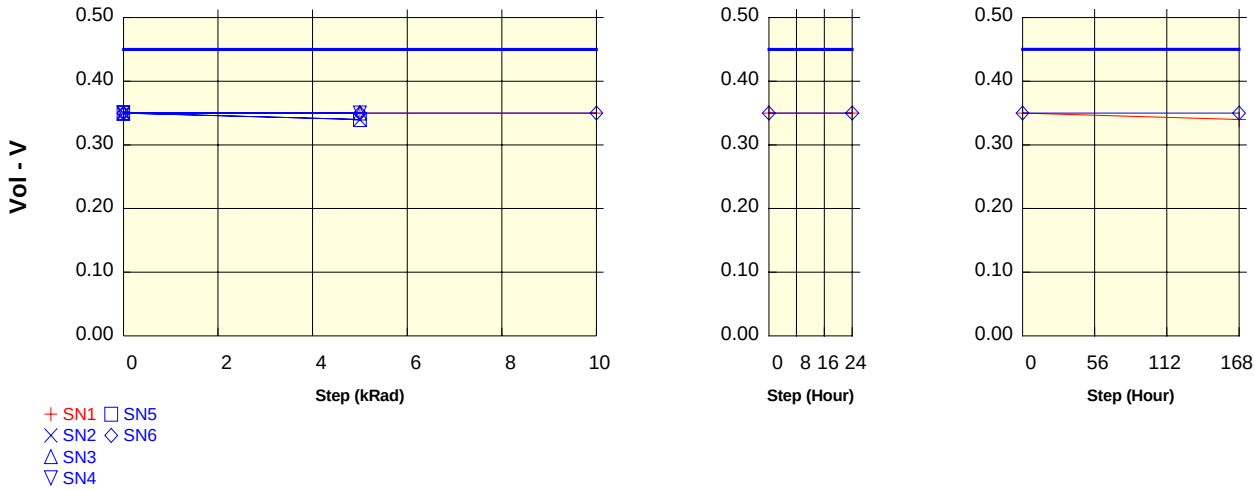
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.36	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.36	0.37
Statistics		
Min	0.00	0.00
Max	0.36	0.37
Mean	0.07	0.07
Sigma	0.16	0.17

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.36	0.36
SN2		
SN3		
SN4		
SN5		
SN6	0.37	0.37
Statistics		
Min	0.00	0.00
Max	0.37	0.37
Mean	0.07	0.07
Sigma	0.17	0.17

Test conditions : TID
Parameter : Output Low Voltage : VolDQ1
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.35	0.35	0.35
SN2	0.35	0.34	
SN3	0.35	0.35	
SN4	0.35	0.35	
SN5	0.35	0.34	
SN6	0.35	0.35	0.35
Statistics			
Min	0.35	0.34	0.00
Max	0.35	0.35	0.35
Mean	0.35	0.35	0.07
Sigma	0.00	0.01	0.16

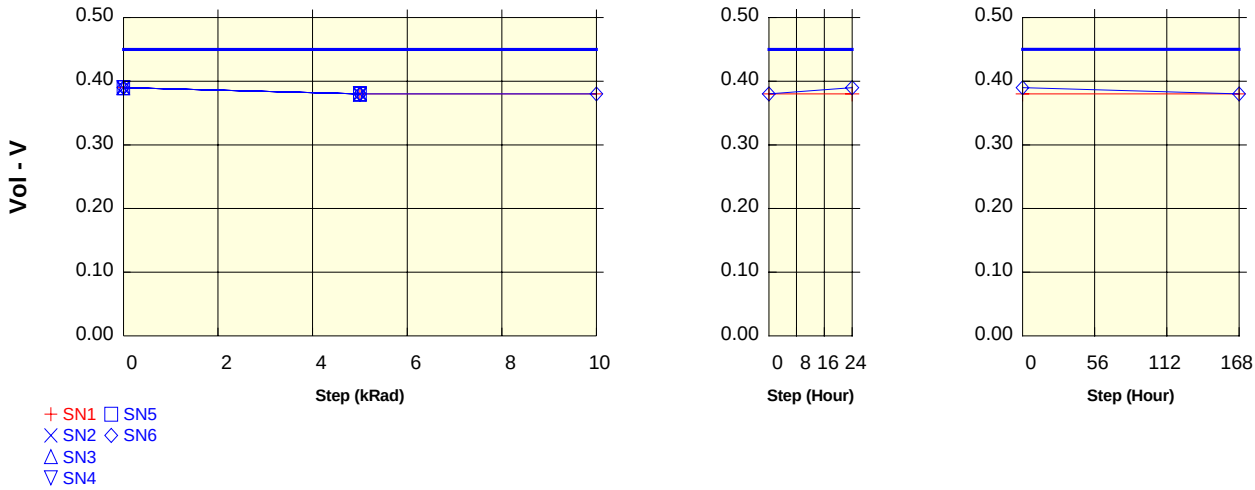
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.35	0.35
SN2		
SN3		
SN4		
SN5		
SN6	0.35	0.35
Statistics		
Min	0.00	0.00
Max	0.35	0.35
Mean	0.07	0.07
Sigma	0.16	0.16

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.35	0.34
SN2		
SN3		
SN4		
SN5		
SN6	0.35	0.35
Statistics		
Min	0.00	0.00
Max	0.35	0.35
Mean	0.07	0.07
Sigma	0.16	0.16

Test conditions : TID
Parameter : Output Low Voltage : VolDQ0
Iol = 12mA. Vcc = VccMin
Unit : V
Spec Limit Max : 0.45
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	0.39	0.38	0.38
SN2	0.39	0.38	
SN3	0.39	0.38	
SN4	0.39	0.38	
SN5	0.39	0.38	
SN6	0.39	0.38	0.38
Statistics			
Min	0.39	0.38	0.00
Max	0.39	0.38	0.38
Mean	0.39	0.38	0.08
Sigma	0.00	0.00	0.17

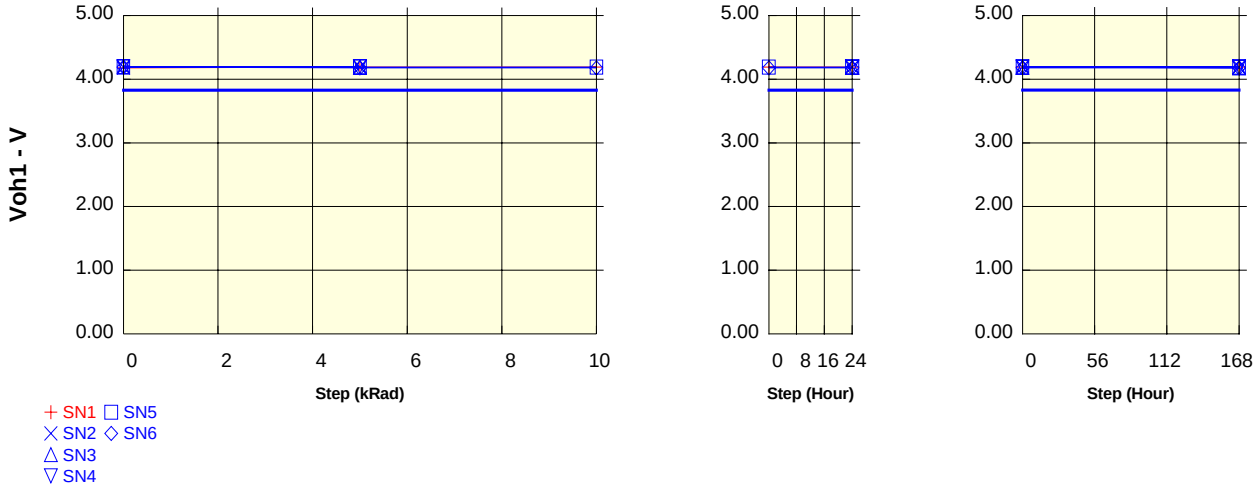
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	0.38	0.38
SN2		
SN3		
SN4		
SN5		
SN6	0.38	0.39
Statistics		
Min	0.00	0.00
Max	0.38	0.39
Mean	0.08	0.08
Sigma	0.17	0.17

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	0.38	0.38
SN2		
SN3		
SN4		
SN5		
SN6	0.39	0.38
Statistics		
Min	0.00	0.00
Max	0.39	0.38
Mean	0.08	0.08
Sigma	0.17	0.17

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ7
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.18	4.19	4.19
SN2	4.19	4.19	
SN3	4.19	4.19	
SN4	4.19	4.20	
SN5	4.20	4.19	4.19
SN6	4.19	4.18	4.18
Statistics			
Min	4.19	4.18	0.00
Max	4.20	4.20	4.19
Mean	4.19	4.19	1.67
Sigma	0.00	0.01	2.29

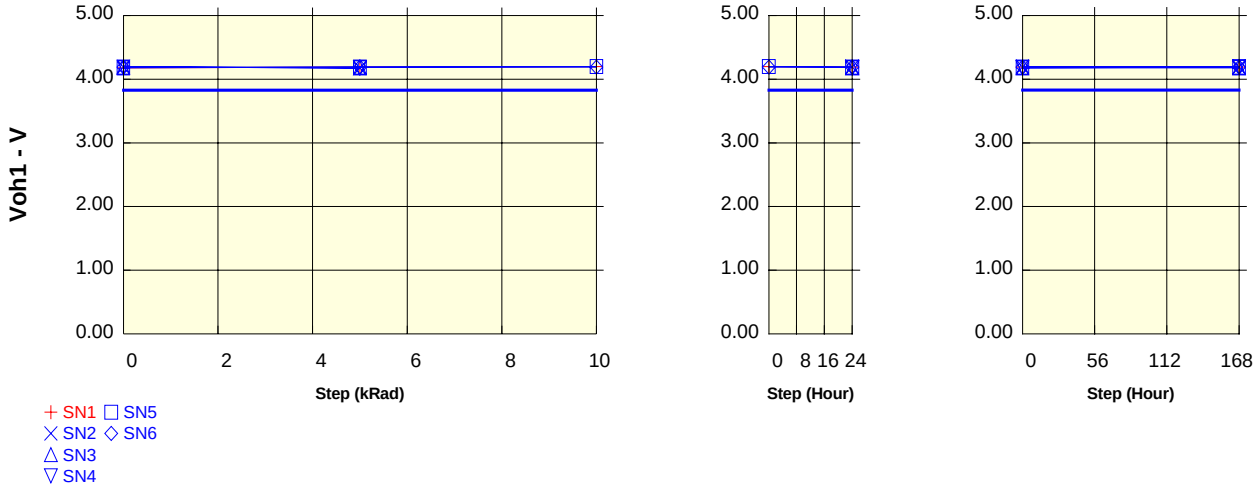
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.19	4.19
SN2		4.19
SN3		4.19
SN4		4.19
SN5	4.19	4.19
SN6	4.18	4.18
Statistics		
Min	0.00	4.18
Max	4.19	4.19
Mean	1.67	4.19
Sigma	2.29	0.00

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.19	4.19
SN3	4.19	4.18
SN4	4.19	4.19
SN5	4.19	4.19
SN6	4.18	4.18
Statistics		
Min	4.18	4.18
Max	4.19	4.19
Mean	4.19	4.19
Sigma	0.00	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ6
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.18	4.19	4.20
SN2	4.19	4.18	
SN3	4.19	4.18	
SN4	4.19	4.18	
SN5	4.18	4.19	4.20
SN6	4.19	4.19	4.19
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.19	4.20
Mean	4.19	4.18	1.68
Sigma	0.00	0.01	2.30

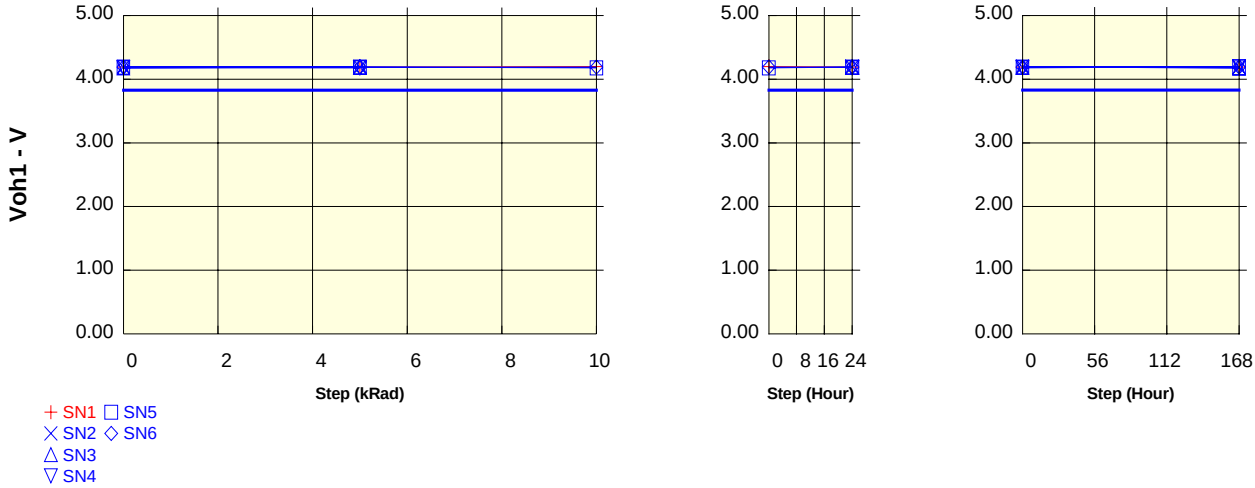
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.20	4.19
SN2		4.19
SN3		4.18
SN4		4.18
SN5	4.20	4.19
SN6	4.19	4.19
Statistics		
Min	0.00	4.18
Max	4.20	4.19
Mean	1.68	4.19
Sigma	2.30	0.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.19	4.19
SN3	4.18	4.18
SN4	4.18	4.19
SN5	4.19	4.19
SN6	4.19	4.19
Statistics		
Min	4.18	4.18
Max	4.19	4.19
Mean	4.19	4.19
Sigma	0.01	0.00

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ5
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.19	4.19	4.20
SN2	4.19	4.19	
SN3	4.18	4.19	
SN4	4.18	4.18	
SN5	4.19	4.19	4.18
SN6	4.19	4.19	4.19
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.19	4.19
Mean	4.19	4.19	1.67
Sigma	0.01	0.00	2.29

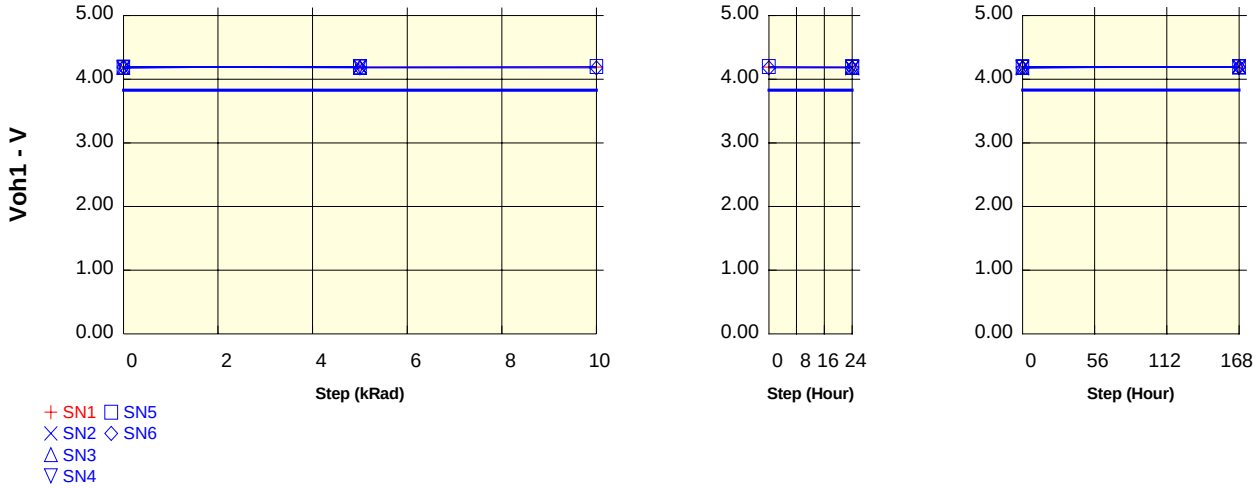
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.20	4.19
SN2		4.19
SN3		4.19
SN4		4.18
SN5	4.18	4.19
SN6	4.19	4.19
Statistics		
Min	0.00	4.18
Max	4.19	4.19
Mean	1.67	4.19
Sigma	2.29	0.00

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.19	4.19
SN3	4.19	4.18
SN4	4.18	4.20
SN5	4.19	4.18
SN6	4.19	4.19
Statistics		
Min	4.18	4.18
Max	4.19	4.20
Mean	4.19	4.19
Sigma	0.00	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ4
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.19	4.19	4.19
SN2	4.18	4.20	
SN3	4.19	4.19	
SN4	4.18	4.20	
SN5	4.19	4.19	4.20
SN6	4.19	4.18	4.18
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.20	4.20
Mean	4.19	4.19	1.68
Sigma	0.01	0.01	2.29

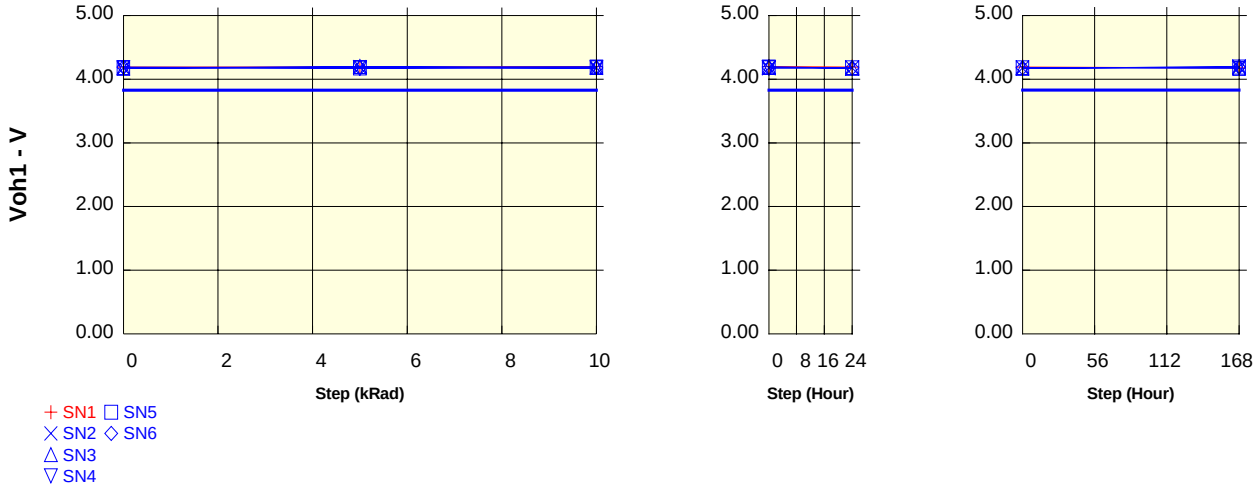
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.19	4.19
SN2		4.18
SN3		4.19
SN4		4.19
SN5	4.20	4.19
SN6	4.18	4.18
Statistics		
Min	0.00	4.18
Max	4.20	4.19
Mean	1.68	4.19
Sigma	2.29	0.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.18	4.20
SN3	4.19	4.19
SN4	4.19	4.19
SN5	4.19	4.20
SN6	4.18	4.19
Statistics		
Min	4.18	4.19
Max	4.19	4.20
Mean	4.19	4.19
Sigma	0.01	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ3
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.19	4.19	4.20
SN2	4.18	4.19	4.18
SN3	4.18	4.20	4.19
SN4	4.18	4.18	4.18
SN5	4.18	4.18	4.19
SN6	4.19	4.18	4.18
Statistics			
Min	4.18	4.18	4.18
Max	4.19	4.20	4.19
Mean	4.18	4.19	4.18
Sigma	0.00	0.01	0.01

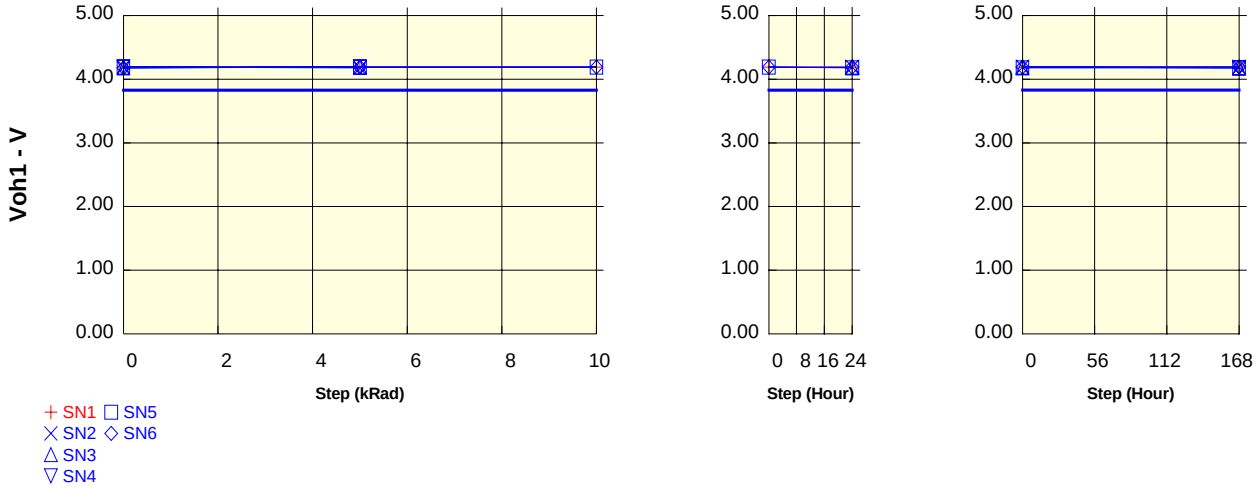
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.20	4.19
SN2	4.18	4.18
SN3	4.19	4.18
SN4	4.18	
SN5	4.19	4.18
SN6	4.18	4.18
Statistics		
Min	4.18	0.00
Max	4.19	4.18
Mean	4.18	3.34
Sigma	0.01	1.87

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.18
SN2	4.18	4.19
SN3	4.18	4.19
SN4		4.19
SN5	4.18	4.17
SN6	4.18	4.19
Statistics		
Min	0.00	4.17
Max	4.18	4.19
Mean	3.34	4.19
Sigma	1.87	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ2
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.19	4.19	4.19
SN2	4.19	4.18	
SN3	4.18	4.19	
SN4	4.19	4.19	
SN5	4.19	4.19	4.19
SN6	4.18	4.19	4.19
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.19	4.19
Mean	4.19	4.19	1.68
Sigma	0.01	0.00	2.29

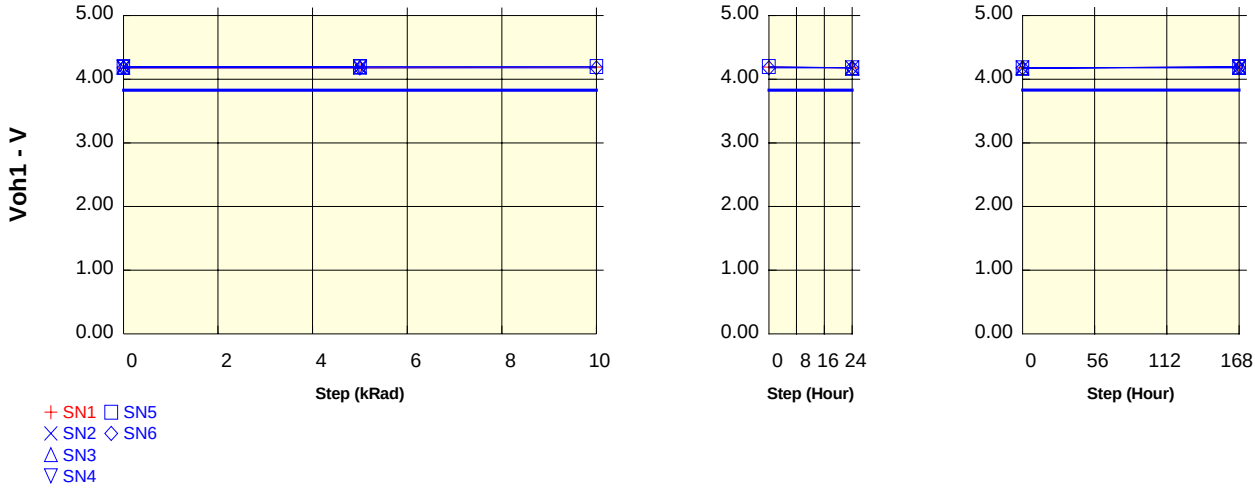
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.19	4.19
SN2		4.19
SN3		4.19
SN4		
SN5	4.19	4.18
SN6	4.19	4.19
Statistics		
Min	0.00	0.00
Max	4.19	4.19
Mean	1.68	3.35
Sigma	2.29	1.87

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.19	4.19
SN3	4.19	4.18
SN4		4.18
SN5	4.18	4.18
SN6	4.19	4.19
Statistics		
Min	0.00	4.18
Max	4.19	4.19
Mean	3.35	4.18
Sigma	1.87	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ1
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.18	4.18	4.19
SN2	4.19	4.19	
SN3	4.19	4.19	
SN4	4.19	4.19	
SN5	4.19	4.20	4.20
SN6	4.18	4.18	4.18
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.20	4.20
Mean	4.19	4.19	1.68
Sigma	0.00	0.01	2.29

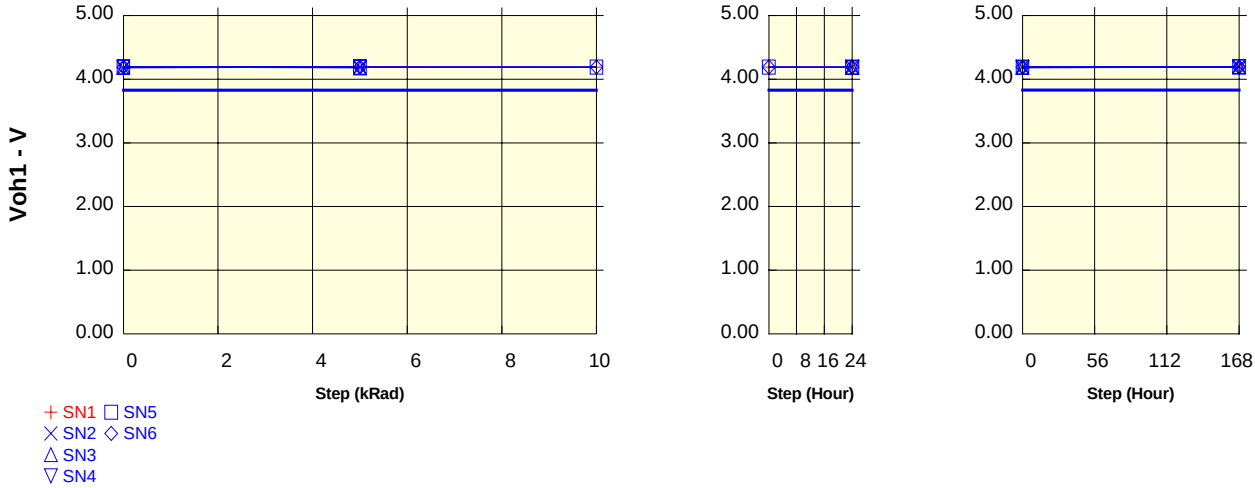
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.19	4.18
SN2		4.18
SN3		4.18
SN4		
SN5	4.20	4.18
SN6	4.18	4.18
Statistics		
Min	0.00	0.00
Max	4.20	4.18
Mean	1.68	3.34
Sigma	2.29	1.87

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.18	4.19
SN2	4.18	4.19
SN3	4.18	4.19
SN4		4.19
SN5	4.18	4.19
SN6	4.18	4.18
Statistics		
Min	0.00	4.18
Max	4.18	4.19
Mean	3.34	4.19
Sigma	1.87	0.00

Test conditions : TID
Parameter : Output High Voltage : Voh1DQ0
Ioh = -2.5mA. Vcc = VccMin
Unit : V
Spec Limit Min : 3.83
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.19	4.20	4.19
SN2	4.18	4.19	
SN3	4.19	4.18	
SN4	4.19	4.19	
SN5	4.19	4.19	4.19
SN6	4.19	4.19	4.19
Statistics			
Min	4.18	4.18	0.00
Max	4.19	4.19	4.19
Mean	4.19	4.19	1.68
Sigma	0.00	0.00	2.29

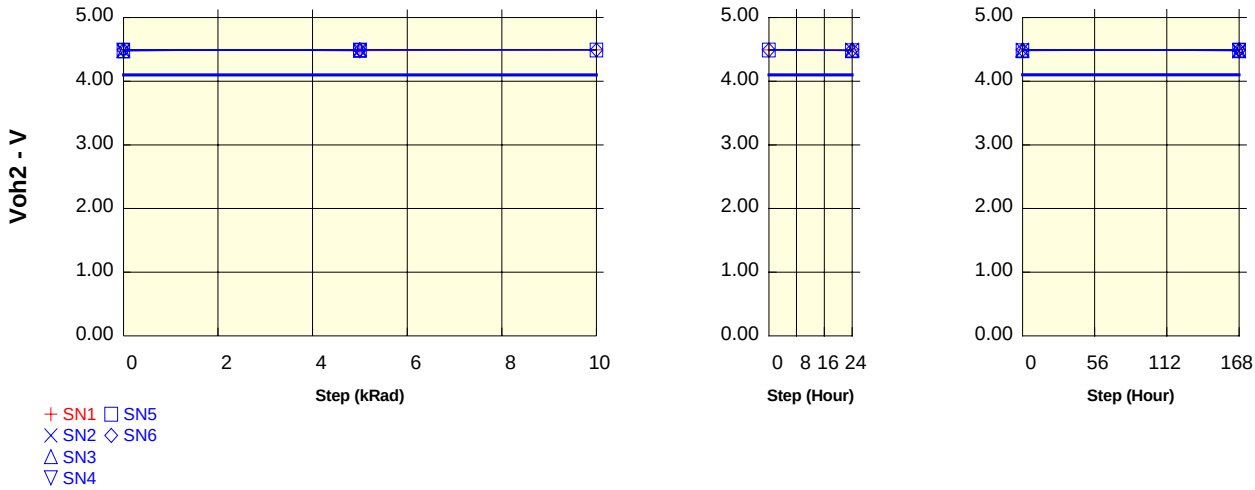
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.19	4.19
SN2		4.19
SN3		4.19
SN4		4.18
SN5	4.19	4.19
SN6	4.19	4.19
Statistics		
Min	0.00	4.18
Max	4.19	4.19
Mean	1.68	4.19
Sigma	2.29	0.00

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.19	4.19
SN2	4.19	4.20
SN3	4.19	4.19
SN4	4.18	4.19
SN5	4.19	4.20
SN6	4.19	4.19
Statistics		
Min	4.18	4.19
Max	4.19	4.20
Mean	4.19	4.19
Sigma	0.00	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ7
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.49	4.48	4.49
SN2	4.48	4.49	
SN3	4.48	4.49	
SN4	4.49	4.48	
SN5	4.48	4.49	4.49
SN6	4.49	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.49
Mean	4.48	4.49	1.80
Sigma	0.01	0.00	2.46

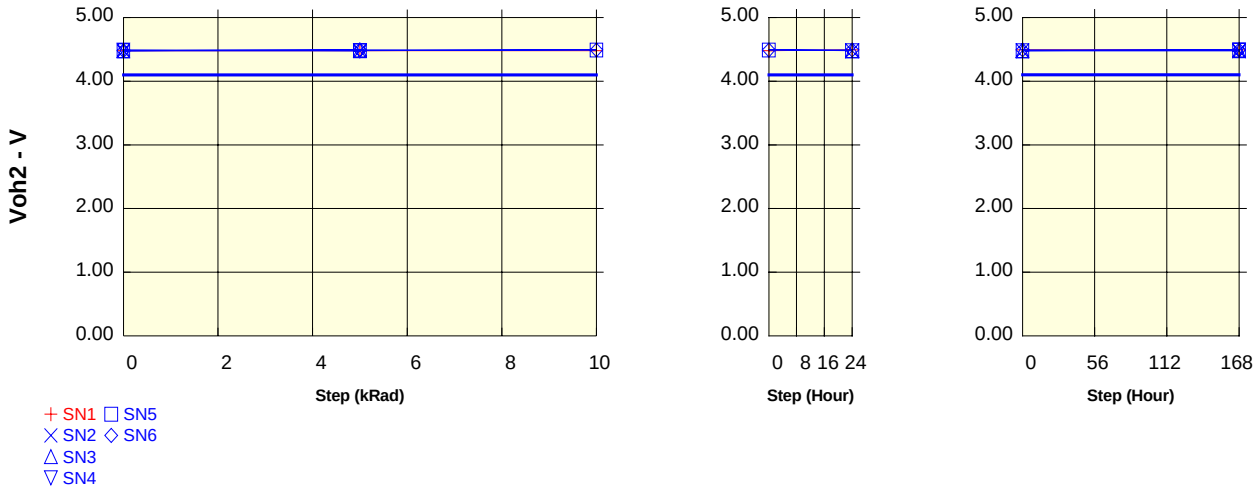
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.49	4.49
SN2		4.49
SN3		4.49
SN4		
SN5	4.49	4.48
SN6	4.49	4.49
Statistics		
Min	0.00	0.00
Max	4.49	4.49
Mean	1.80	3.59
Sigma	2.46	2.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.49
SN2	4.49	4.48
SN3	4.49	4.48
SN4		4.48
SN5	4.48	4.49
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	3.59	4.48
Sigma	2.01	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ6
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.48	4.48	4.48
SN2	4.48	4.48	
SN3	4.48	4.49	
SN4	4.49	4.48	
SN5	4.48	4.48	4.49
SN6	4.48	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.49
Mean	4.48	4.48	1.80
Sigma	0.00	0.01	2.46

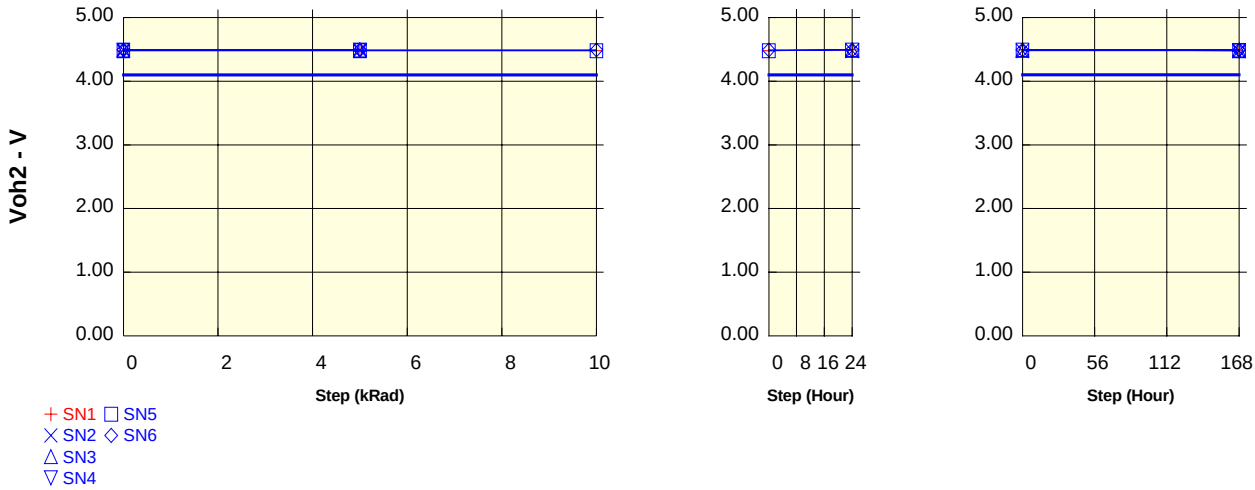
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.48	4.49
SN2		4.48
SN3		4.48
SN4		
SN5	4.49	4.48
SN6	4.49	4.49
Statistics		
Min	0.00	0.00
Max	4.49	4.49
Mean	1.80	3.59
Sigma	2.46	2.00

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.49
SN2	4.48	4.48
SN3	4.48	4.48
SN4		4.49
SN5	4.48	4.49
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	3.59	4.49
Sigma	2.00	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ5
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.48	4.48	4.48
SN2	4.49	4.49	
SN3	4.49	4.49	
SN4	4.49	4.49	
SN5	4.48	4.48	4.48
SN6	4.49	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.49
Mean	4.49	4.49	1.79
Sigma	0.00	0.00	2.46

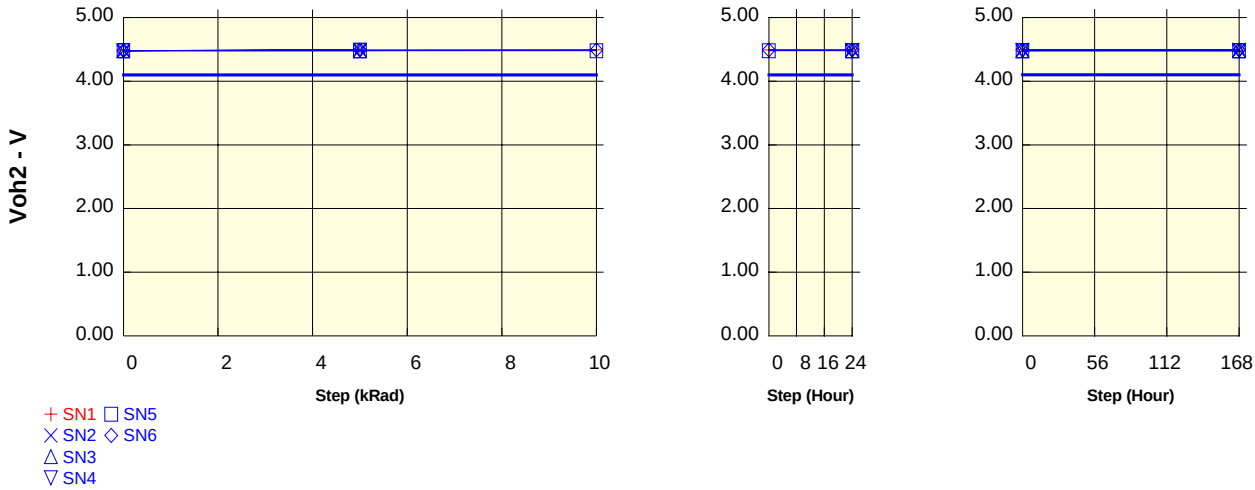
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.48	4.49
SN2		4.48
SN3		4.49
SN4		
SN5	4.48	4.49
SN6	4.49	4.49
Statistics		
Min	0.00	0.00
Max	4.49	4.49
Mean	1.79	3.59
Sigma	2.46	2.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.48
SN2	4.48	4.48
SN3	4.49	4.49
SN4		4.48
SN5	4.49	4.48
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	3.59	4.48
Sigma	2.01	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ4
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.48	4.48	4.49
SN2	4.48	4.49	
SN3	4.48	4.48	
SN4	4.48	4.49	
SN5	4.48	4.48	4.48
SN6	4.48	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.48	4.49	4.49
Mean	4.48	4.49	1.79
Sigma	0.00	0.01	2.46

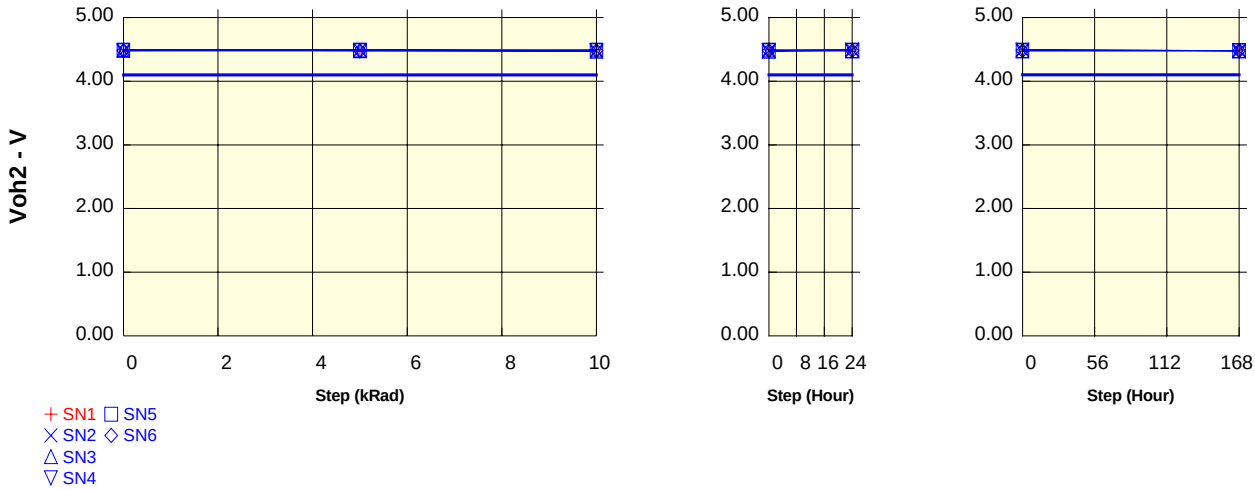
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.49	4.49
SN2		4.49
SN3		4.48
SN4		4.48
SN5	4.48	4.48
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	1.79	4.48
Sigma	2.46	0.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.48
SN2	4.49	4.49
SN3	4.48	4.48
SN4	4.48	4.48
SN5	4.48	4.48
SN6	4.49	4.49
Statistics		
Min	4.48	4.48
Max	4.49	4.49
Mean	4.48	4.48
Sigma	0.01	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ3
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.49	4.48	4.49
SN2	4.48	4.49	4.48
SN3	4.49	4.48	4.47
SN4	4.48	4.48	4.48
SN5	4.49	4.49	4.49
SN6	4.48	4.48	4.48
Statistics			
Min	4.48	4.48	4.47
Max	4.49	4.49	4.49
Mean	4.48	4.48	4.48
Sigma	0.01	0.01	0.01

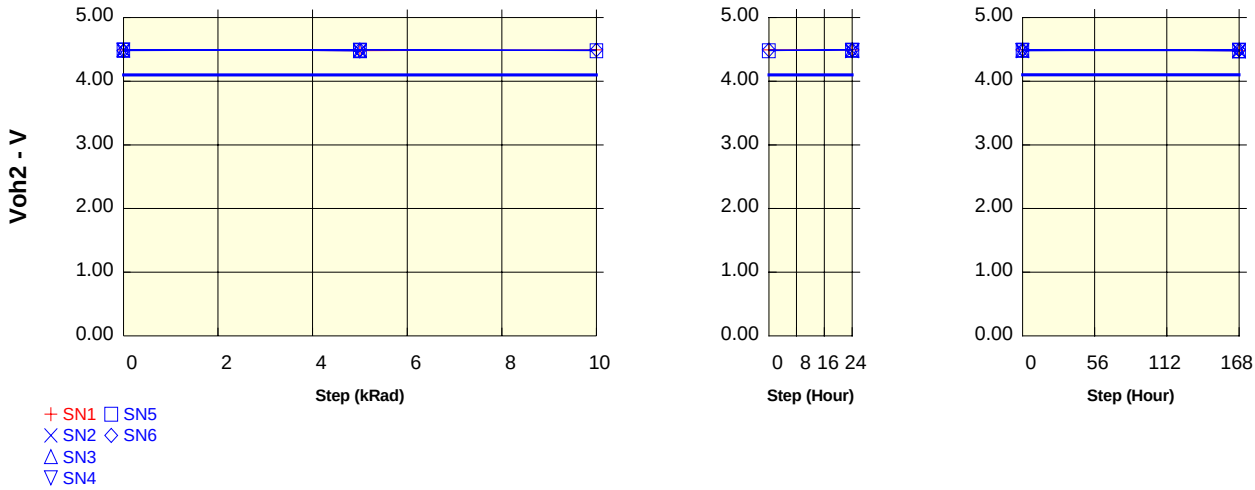
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.49	4.49
SN2	4.48	4.49
SN3	4.47	4.48
SN4	4.48	4.49
SN5	4.49	4.48
SN6	4.48	4.48
Statistics		
Min	4.47	4.48
Max	4.49	4.49
Mean	4.48	4.48
Sigma	0.01	0.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.48
SN2	4.49	4.48
SN3	4.48	4.48
SN4	4.49	4.48
SN5	4.48	4.48
SN6	4.48	4.48
Statistics		
Min	4.48	4.48
Max	4.49	4.48
Mean	4.48	4.48
Sigma	0.01	0.00

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ2
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.49	4.48	4.49
SN2	4.49	4.48	
SN3	4.49	4.48	
SN4	4.49	4.48	
SN5	4.49	4.49	4.48
SN6	4.48	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.49
Mean	4.49	4.48	1.79
Sigma	0.00	0.01	2.46

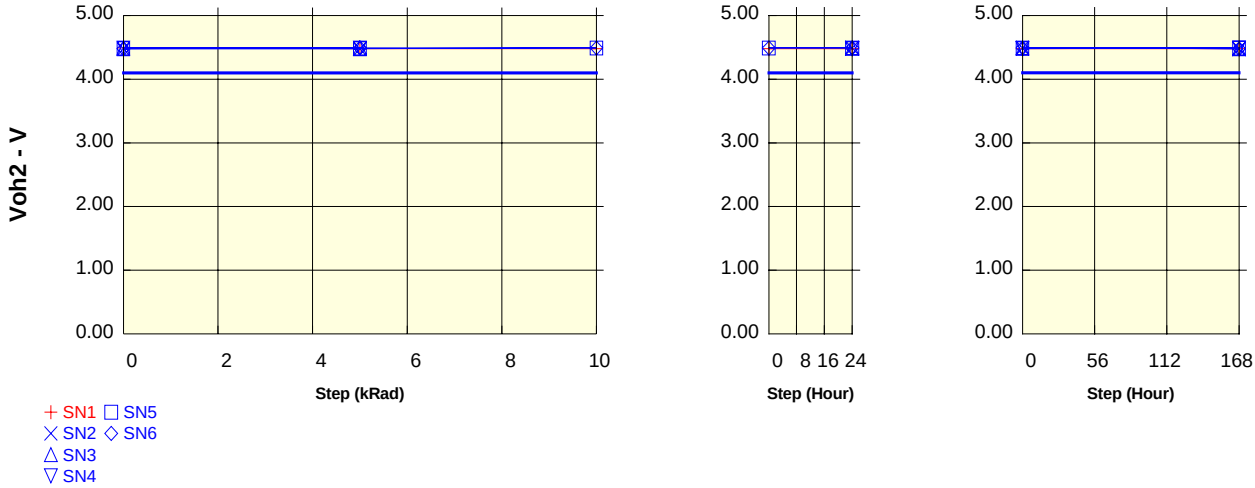
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.49	4.49
SN2		4.48
SN3		4.49
SN4		4.48
SN5	4.48	4.49
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	1.79	4.49
Sigma	2.46	0.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.49	4.48
SN2	4.48	4.48
SN3	4.49	4.48
SN4	4.48	4.49
SN5	4.49	4.48
SN6	4.49	4.49
Statistics		
Min	4.48	4.48
Max	4.49	4.49
Mean	4.49	4.48
Sigma	0.01	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ1
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.49	4.48	4.48
SN2	4.48	4.48	
SN3	4.49	4.49	
SN4	4.49	4.49	
SN5	4.48	4.48	4.49
SN6	4.48	4.49	4.49
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.49
Mean	4.48	4.49	1.80
Sigma	0.01	0.01	2.46

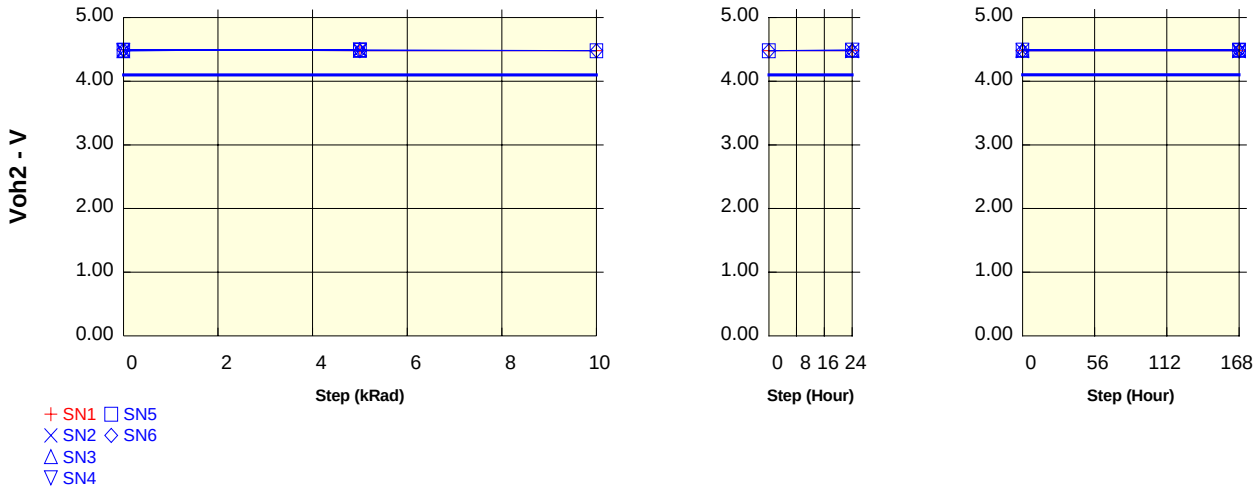
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.48	4.48
SN2		4.49
SN3		4.49
SN4		4.48
SN5	4.49	4.49
SN6	4.49	4.49
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	1.80	4.49
Sigma	2.46	0.00

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.48	4.48
SN2	4.49	4.48
SN3	4.49	4.48
SN4	4.48	4.49
SN5	4.49	4.49
SN6	4.49	4.48
Statistics		
Min	4.48	4.48
Max	4.49	4.49
Mean	4.49	4.48
Sigma	0.00	0.01

Test conditions : TID
Parameter : Output High Voltage : Voh2DQ0
Ioh = -100µA. Vcc = VccMin
Unit : V
Spec Limit Min : 4.10
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.49	4.48	4.48
SN2	4.48	4.49	
SN3	4.48	4.49	
SN4	4.48	4.49	
SN5	4.49	4.49	4.48
SN6	4.49	4.48	4.48
Statistics			
Min	4.48	4.48	0.00
Max	4.49	4.49	4.48
Mean	4.48	4.49	1.79
Sigma	0.01	0.00	2.45

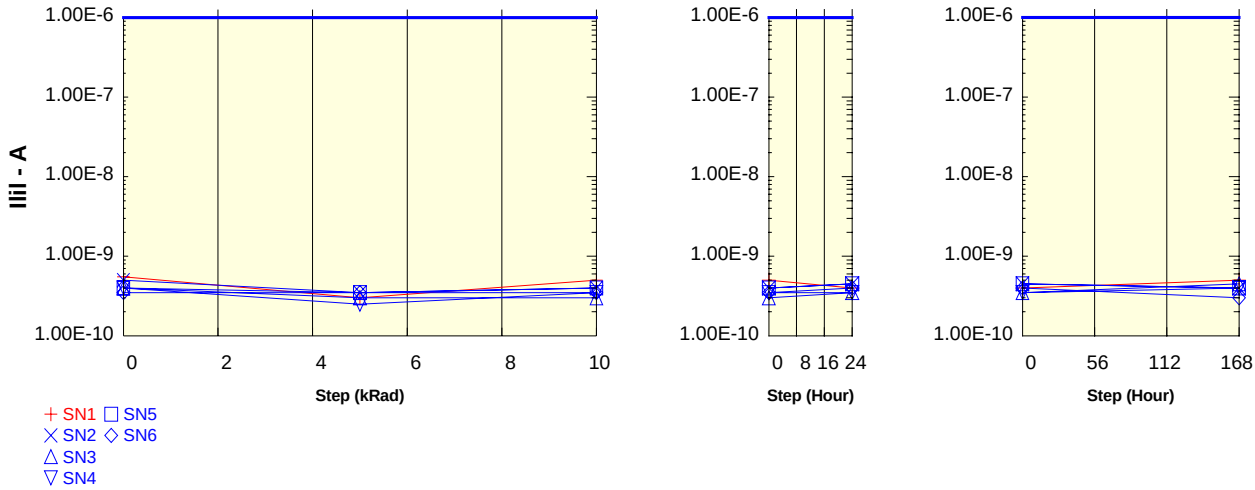
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.48	4.48
SN2		4.48
SN3		4.49
SN4		
SN5	4.48	4.49
SN6	4.48	4.48
Statistics		
Min	0.00	0.00
Max	4.48	4.49
Mean	1.79	3.59
Sigma	2.45	2.01

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.48	4.48
SN2	4.48	4.48
SN3	4.49	4.49
SN4		4.48
SN5	4.49	4.49
SN6	4.48	4.48
Statistics		
Min	0.00	4.48
Max	4.49	4.49
Mean	3.59	4.48
Sigma	2.01	0.01

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA20
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	5.50E-10	3.00E-10	5.00E-10
SN2	5.00E-10	3.50E-10	4.00E-10
SN3	4.00E-10	3.00E-10	3.00E-10
SN4	4.00E-10	2.50E-10	3.50E-10
SN5	4.00E-10	3.50E-10	4.00E-10
SN6	3.50E-10	3.50E-10	3.50E-10
Statistics			
Min	3.50E-10	2.50E-10	3.00E-10
Max	5.00E-10	3.50E-10	4.00E-10
Mean	4.10E-10	3.20E-10	3.60E-10
Sigma	5.48E-11	4.47E-11	4.18E-11

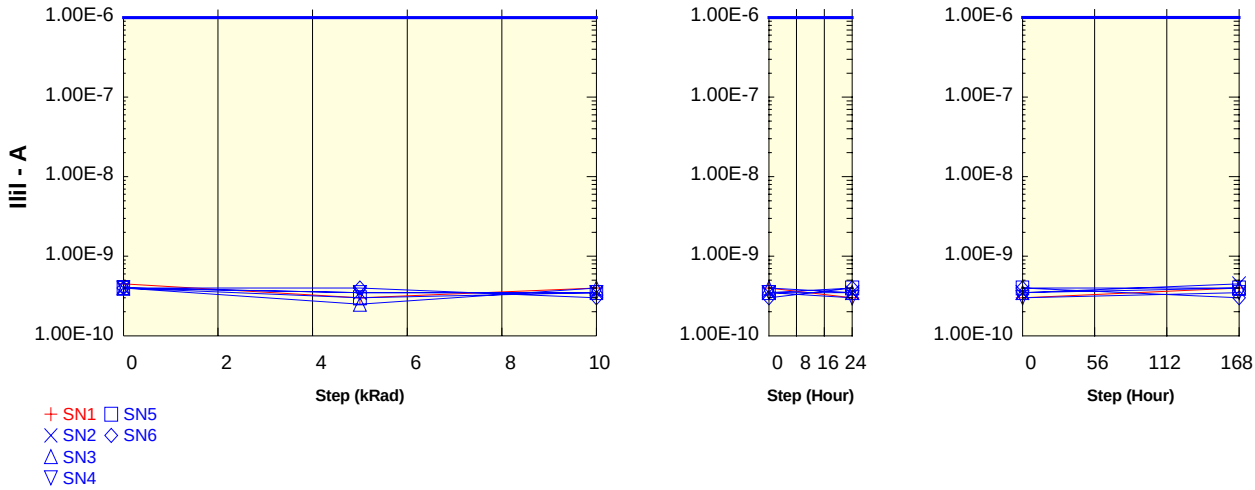
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	5.00E-10	4.00E-10
SN2	4.00E-10	4.50E-10
SN3	3.00E-10	3.50E-10
SN4	3.50E-10	3.50E-10
SN5	4.00E-10	4.50E-10
SN6	3.50E-10	4.00E-10
Statistics		
Min	3.00E-10	3.50E-10
Max	4.00E-10	4.50E-10
Mean	3.60E-10	4.00E-10
Sigma	4.18E-11	5.00E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.00E-10	5.00E-10
SN2	4.50E-10	4.00E-10
SN3	3.50E-10	4.50E-10
SN4	3.50E-10	4.00E-10
SN5	4.50E-10	4.00E-10
SN6	4.00E-10	3.00E-10
Statistics		
Min	3.50E-10	3.00E-10
Max	4.50E-10	4.50E-10
Mean	4.00E-10	3.90E-10
Sigma	5.00E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA19
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.50E-10	3.00E-10	4.00E-10
SN2	4.00E-10	3.50E-10	3.50E-10
SN3	4.00E-10	2.50E-10	4.00E-10
SN4	4.00E-10	3.50E-10	3.50E-10
SN5	4.00E-10	3.00E-10	3.50E-10
SN6	4.00E-10	4.00E-10	3.00E-10
Statistics			
Min	4.00E-10	2.50E-10	3.00E-10
Max	4.00E-10	4.00E-10	4.00E-10
Mean	4.00E-10	3.30E-10	3.50E-10
Sigma	0.00E+0	5.70E-11	3.54E-11

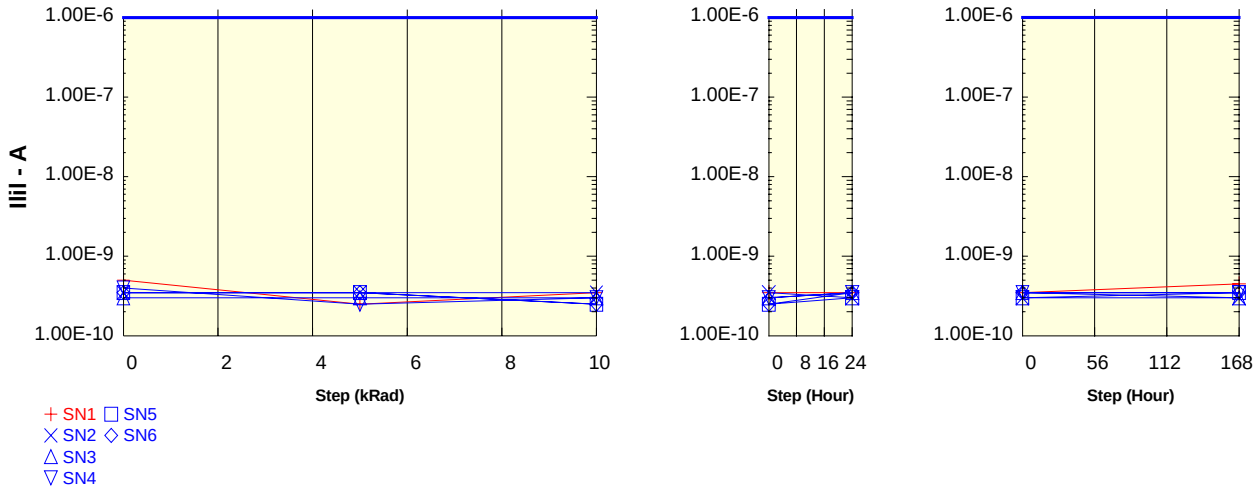
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.00E-10	3.00E-10
SN2	3.50E-10	3.50E-10
SN3	4.00E-10	3.50E-10
SN4	3.50E-10	3.00E-10
SN5	3.50E-10	4.00E-10
SN6	3.00E-10	4.00E-10
Statistics		
Min	3.00E-10	3.00E-10
Max	4.00E-10	4.00E-10
Mean	3.50E-10	3.60E-10
Sigma	3.54E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	4.00E-10
SN2	3.50E-10	4.50E-10
SN3	3.50E-10	4.00E-10
SN4	3.00E-10	3.50E-10
SN5	4.00E-10	4.00E-10
SN6	4.00E-10	3.00E-10
Statistics		
Min	3.00E-10	3.00E-10
Max	4.00E-10	4.50E-10
Mean	3.60E-10	3.80E-10
Sigma	4.18E-11	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA18
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	5.00E-10	2.50E-10	3.50E-10
SN2	3.50E-10	3.50E-10	3.50E-10
SN3	3.00E-10	3.00E-10	3.00E-10
SN4	4.00E-10	2.50E-10	3.00E-10
SN5	3.50E-10	3.50E-10	2.50E-10
SN6	3.50E-10	3.50E-10	2.50E-10
Statistics			
Min	3.00E-10	2.50E-10	2.50E-10
Max	4.00E-10	3.50E-10	3.50E-10
Mean	3.50E-10	3.20E-10	2.90E-10
Sigma	3.54E-11	4.47E-11	4.18E-11

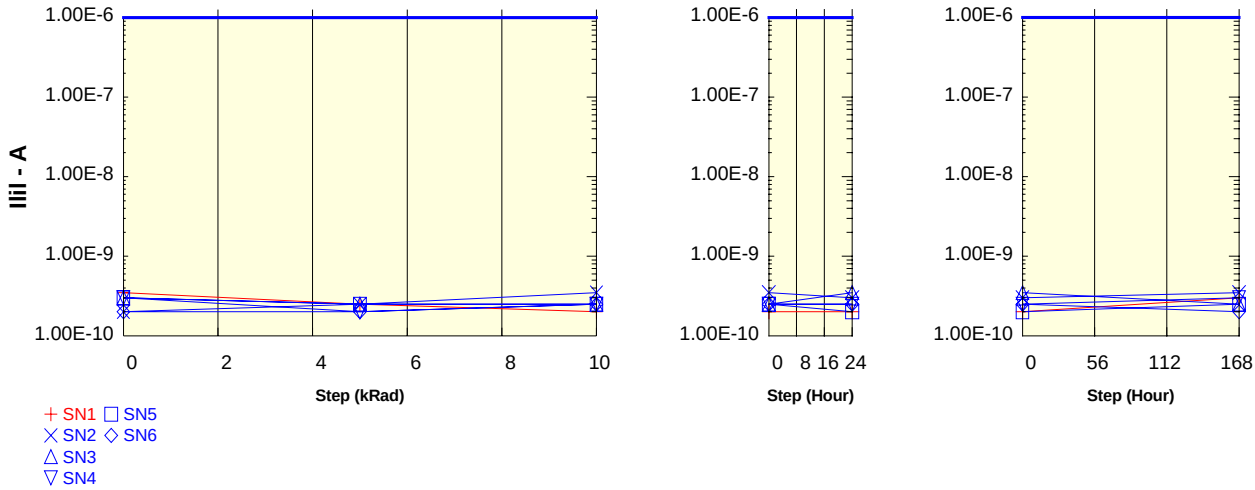
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.50E-10	3.50E-10
SN2	3.50E-10	3.00E-10
SN3	3.00E-10	3.50E-10
SN4	3.00E-10	3.50E-10
SN5	2.50E-10	3.00E-10
SN6	2.50E-10	3.50E-10
Statistics		
Min	2.50E-10	3.00E-10
Max	3.50E-10	3.50E-10
Mean	2.90E-10	3.30E-10
Sigma	4.18E-11	2.74E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.50E-10	4.50E-10
SN2	3.00E-10	3.00E-10
SN3	3.50E-10	3.00E-10
SN4	3.50E-10	3.50E-10
SN5	3.00E-10	3.50E-10
SN6	3.50E-10	3.50E-10
Statistics		
Min	3.00E-10	3.00E-10
Max	3.50E-10	3.50E-10
Mean	3.30E-10	3.30E-10
Sigma	2.74E-11	2.74E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA17
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.50E-10	2.50E-10	2.00E-10
SN2	2.00E-10	2.50E-10	3.50E-10
SN3	3.00E-10	2.50E-10	2.50E-10
SN4	3.00E-10	2.00E-10	2.50E-10
SN5	3.00E-10	2.50E-10	2.50E-10
SN6	2.00E-10	2.00E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	2.50E-10
Max	3.00E-10	2.50E-10	3.50E-10
Mean	2.60E-10	2.30E-10	2.70E-10
Sigma	5.48E-11	2.74E-11	4.47E-11

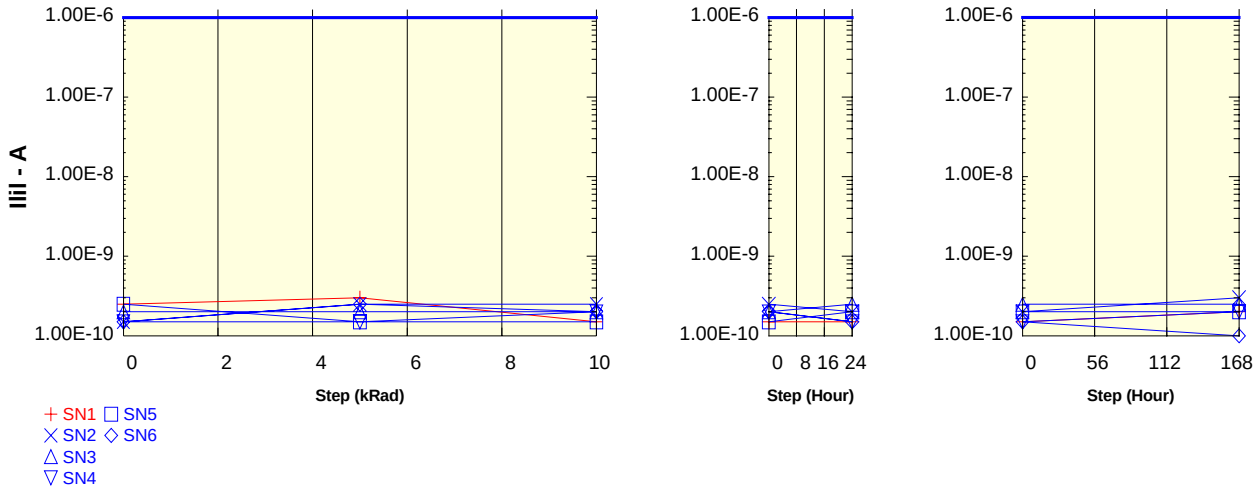
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	2.00E-10
SN2	3.50E-10	3.00E-10
SN3	2.50E-10	3.50E-10
SN4	2.50E-10	2.50E-10
SN5	2.50E-10	2.00E-10
SN6	2.50E-10	2.50E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.50E-10	3.50E-10
Mean	2.70E-10	2.70E-10
Sigma	4.47E-11	5.70E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	3.00E-10
SN2	3.00E-10	3.50E-10
SN3	3.50E-10	2.50E-10
SN4	2.50E-10	3.00E-10
SN5	2.00E-10	2.50E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.50E-10	3.50E-10
Mean	2.70E-10	2.70E-10
Sigma	5.70E-11	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA16
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	3.00E-10	1.50E-10
SN2	1.50E-10	2.50E-10	2.50E-10
SN3	2.00E-10	2.00E-10	2.00E-10
SN4	1.50E-10	1.50E-10	2.00E-10
SN5	2.50E-10	1.50E-10	1.50E-10
SN6	1.50E-10	2.50E-10	2.00E-10
Statistics			
Min	1.50E-10	1.50E-10	1.50E-10
Max	2.50E-10	2.50E-10	2.50E-10
Mean	1.80E-10	2.00E-10	2.00E-10
Sigma	4.47E-11	5.00E-11	3.54E-11

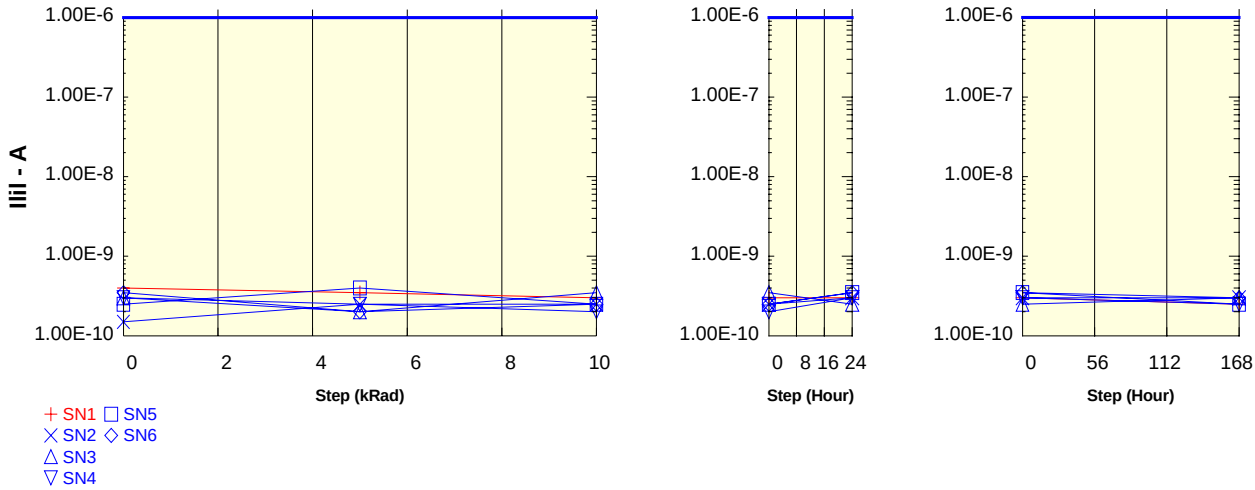
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	1.50E-10
SN2	2.50E-10	2.00E-10
SN3	2.00E-10	2.50E-10
SN4	2.00E-10	1.50E-10
SN5	1.50E-10	2.00E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	2.50E-10	2.50E-10
Mean	2.00E-10	1.90E-10
Sigma	3.54E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.50E-10	2.00E-10
SN2	2.00E-10	3.00E-10
SN3	2.50E-10	2.50E-10
SN4	1.50E-10	2.00E-10
SN5	2.00E-10	2.00E-10
SN6	1.50E-10	1.00E-10
Statistics		
Min	1.50E-10	1.00E-10
Max	2.50E-10	3.00E-10
Mean	1.90E-10	2.10E-10
Sigma	4.18E-11	7.42E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA15
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	3.50E-10	3.00E-10
SN2	1.50E-10	2.50E-10	2.50E-10
SN3	3.00E-10	2.00E-10	3.50E-10
SN4	3.00E-10	2.50E-10	2.00E-10
SN5	2.50E-10	4.00E-10	2.50E-10
SN6	3.50E-10	2.00E-10	2.50E-10
Statistics			
Min	1.50E-10	2.00E-10	2.00E-10
Max	3.50E-10	4.00E-10	3.50E-10
Mean	2.70E-10	2.60E-10	2.60E-10
Sigma	7.58E-11	8.22E-11	5.48E-11

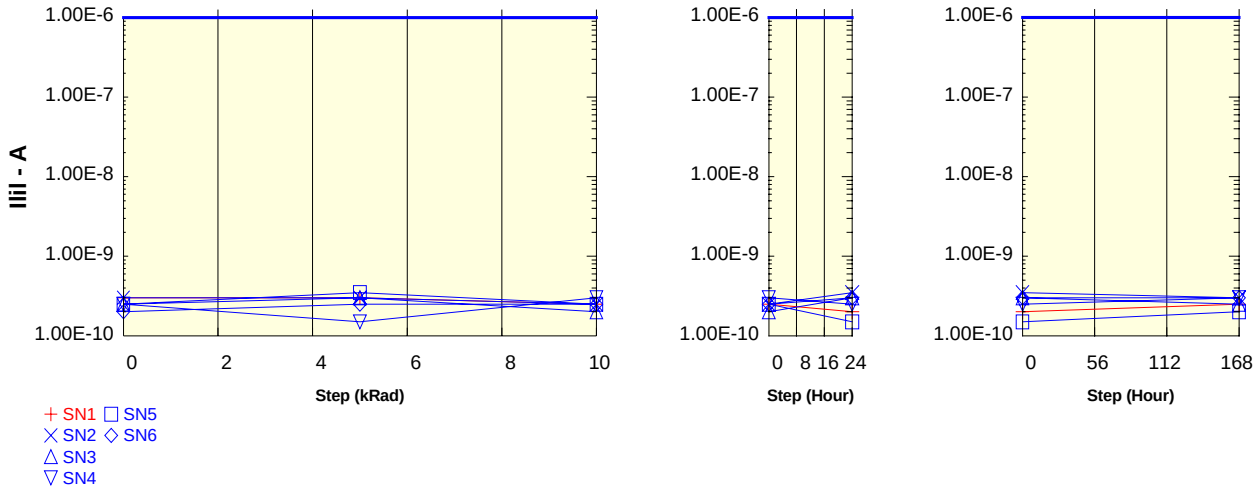
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	3.00E-10
SN2	2.50E-10	3.00E-10
SN3	3.50E-10	2.50E-10
SN4	2.00E-10	3.00E-10
SN5	2.50E-10	3.50E-10
SN6	2.50E-10	3.50E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.50E-10	3.50E-10
Mean	2.60E-10	3.10E-10
Sigma	5.48E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	2.50E-10
SN2	3.00E-10	3.00E-10
SN3	2.50E-10	3.00E-10
SN4	3.00E-10	2.50E-10
SN5	3.50E-10	2.50E-10
SN6	3.50E-10	3.00E-10
Statistics		
Min	2.50E-10	2.50E-10
Max	3.50E-10	3.00E-10
Mean	3.10E-10	2.80E-10
Sigma	4.18E-11	2.74E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA14
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.00E-10	2.50E-10
SN2	3.00E-10	3.00E-10	2.50E-10
SN3	2.50E-10	3.00E-10	2.00E-10
SN4	2.50E-10	1.50E-10	3.00E-10
SN5	2.50E-10	3.50E-10	2.50E-10
SN6	2.00E-10	2.50E-10	2.50E-10
Statistics			
Min	2.00E-10	1.50E-10	2.00E-10
Max	3.00E-10	3.50E-10	3.00E-10
Mean	2.50E-10	2.70E-10	2.50E-10
Sigma	3.54E-11	7.58E-11	3.54E-11

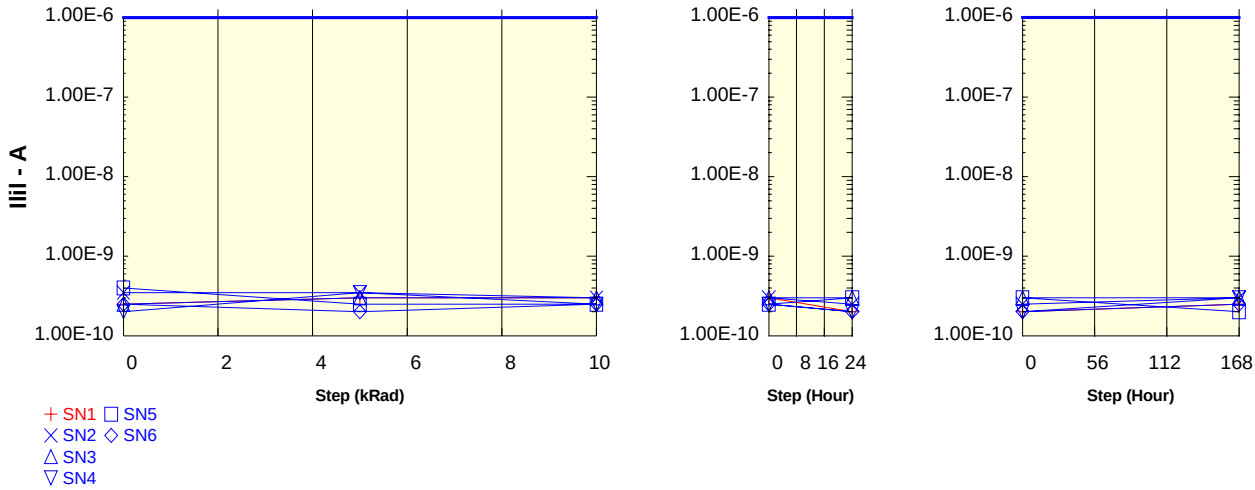
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.00E-10
SN2	2.50E-10	3.50E-10
SN3	2.00E-10	3.00E-10
SN4	3.00E-10	2.50E-10
SN5	2.50E-10	1.50E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	3.00E-10	3.50E-10
Mean	2.50E-10	2.70E-10
Sigma	3.54E-11	7.58E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.50E-10
SN2	3.50E-10	3.00E-10
SN3	3.00E-10	2.50E-10
SN4	2.50E-10	3.00E-10
SN5	1.50E-10	2.00E-10
SN6	3.00E-10	3.00E-10
Statistics		
Min	1.50E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	2.70E-10	2.70E-10
Sigma	7.58E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA13
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	3.00E-10	3.00E-10
SN2	3.50E-10	3.50E-10	3.00E-10
SN3	2.50E-10	3.00E-10	3.00E-10
SN4	2.00E-10	3.50E-10	2.50E-10
SN5	4.00E-10	2.50E-10	2.50E-10
SN6	2.50E-10	2.00E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	2.50E-10
Max	4.00E-10	3.50E-10	3.00E-10
Mean	2.90E-10	2.90E-10	2.70E-10
Sigma	8.22E-11	6.52E-11	2.74E-11

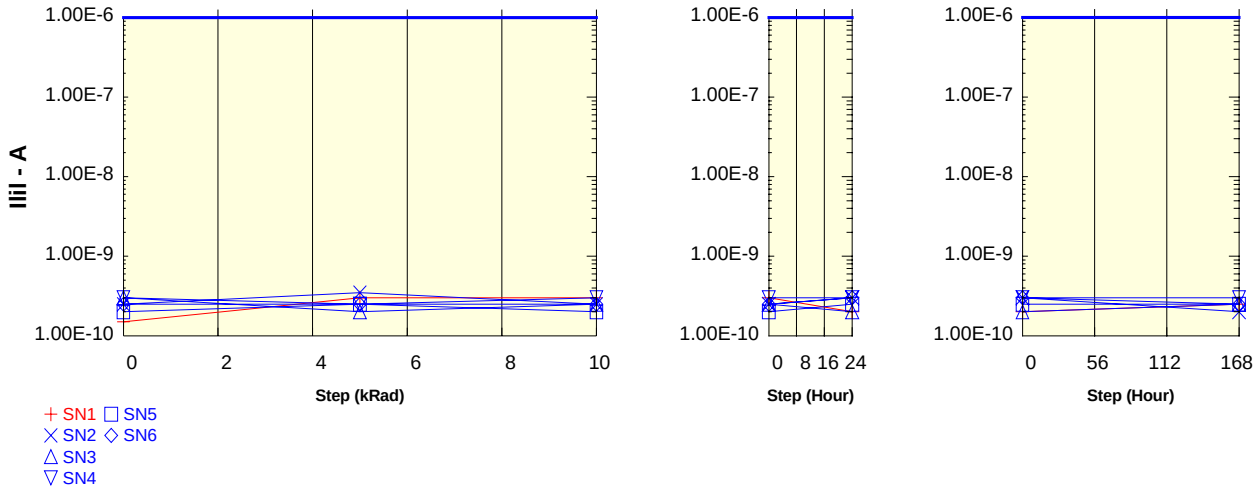
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	2.00E-10
SN2	3.00E-10	2.50E-10
SN3	3.00E-10	3.00E-10
SN4	2.50E-10	2.00E-10
SN5	2.50E-10	3.00E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.70E-10	2.50E-10
Sigma	2.74E-11	5.00E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.50E-10
SN2	2.50E-10	3.00E-10
SN3	3.00E-10	3.00E-10
SN4	2.00E-10	3.00E-10
SN5	3.00E-10	2.00E-10
SN6	2.00E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.50E-10	2.70E-10
Sigma	5.00E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA12
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	3.00E-10	3.00E-10
SN2	2.50E-10	3.50E-10	2.50E-10
SN3	3.00E-10	2.00E-10	2.50E-10
SN4	3.00E-10	2.50E-10	3.00E-10
SN5	2.00E-10	2.50E-10	2.00E-10
SN6	2.50E-10	2.50E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	2.00E-10
Max	3.00E-10	3.50E-10	3.00E-10
Mean	2.60E-10	2.60E-10	2.50E-10
Sigma	4.18E-11	5.48E-11	3.54E-11

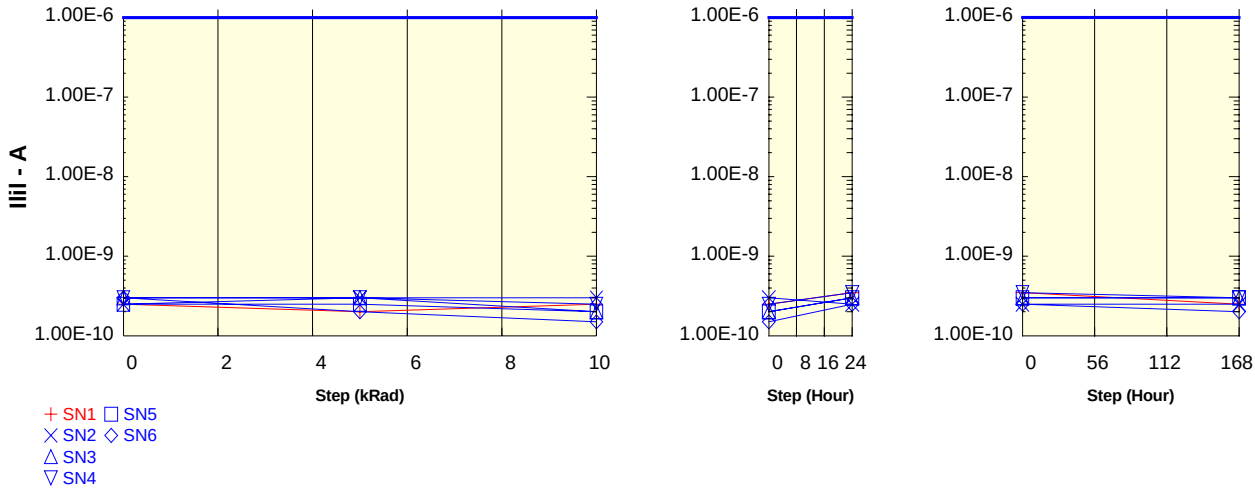
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	2.00E-10
SN2	2.50E-10	3.00E-10
SN3	2.50E-10	2.00E-10
SN4	3.00E-10	3.00E-10
SN5	2.00E-10	2.50E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.50E-10	2.70E-10
Sigma	3.54E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.50E-10
SN2	3.00E-10	2.00E-10
SN3	2.00E-10	2.50E-10
SN4	3.00E-10	3.00E-10
SN5	2.50E-10	2.50E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.70E-10	2.50E-10
Sigma	4.47E-11	3.54E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA11
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	2.00E-10	2.50E-10
SN2	2.50E-10	3.00E-10	3.00E-10
SN3	3.00E-10	3.00E-10	2.00E-10
SN4	3.00E-10	3.00E-10	2.50E-10
SN5	2.50E-10	2.50E-10	2.00E-10
SN6	3.00E-10	2.00E-10	1.50E-10
Statistics			
Min	2.50E-10	2.00E-10	1.50E-10
Max	3.00E-10	3.00E-10	3.00E-10
Mean	2.80E-10	2.70E-10	2.20E-10
Sigma	2.74E-11	4.47E-11	5.70E-11

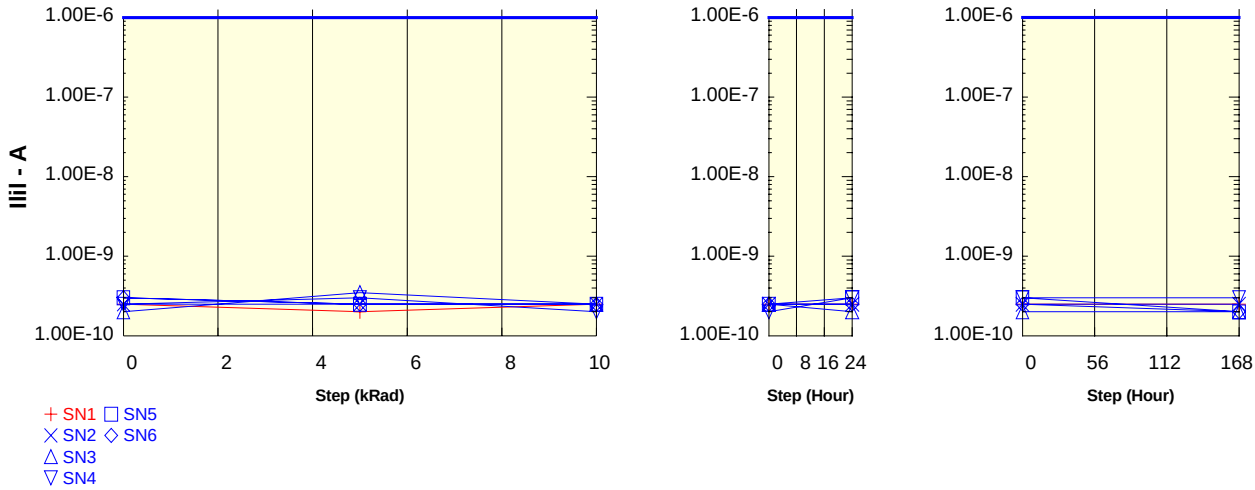
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	3.50E-10
SN2	3.00E-10	2.50E-10
SN3	2.00E-10	3.00E-10
SN4	2.50E-10	3.50E-10
SN5	2.00E-10	3.00E-10
SN6	1.50E-10	2.50E-10
Statistics		
Min	1.50E-10	2.50E-10
Max	3.00E-10	3.50E-10
Mean	2.20E-10	2.90E-10
Sigma	5.70E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.50E-10	2.50E-10
SN2	2.50E-10	2.50E-10
SN3	3.00E-10	3.00E-10
SN4	3.50E-10	3.00E-10
SN5	3.00E-10	3.00E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	2.90E-10	2.70E-10
Sigma	4.18E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA10
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	2.00E-10	2.50E-10
SN2	2.50E-10	2.50E-10	2.50E-10
SN3	2.00E-10	3.50E-10	2.50E-10
SN4	2.50E-10	3.00E-10	2.00E-10
SN5	3.00E-10	2.50E-10	2.50E-10
SN6	3.00E-10	2.50E-10	2.50E-10
Statistics			
Min	2.00E-10	2.50E-10	2.00E-10
Max	3.00E-10	3.50E-10	2.50E-10
Mean	2.60E-10	2.80E-10	2.40E-10
Sigma	4.18E-11	4.47E-11	2.24E-11

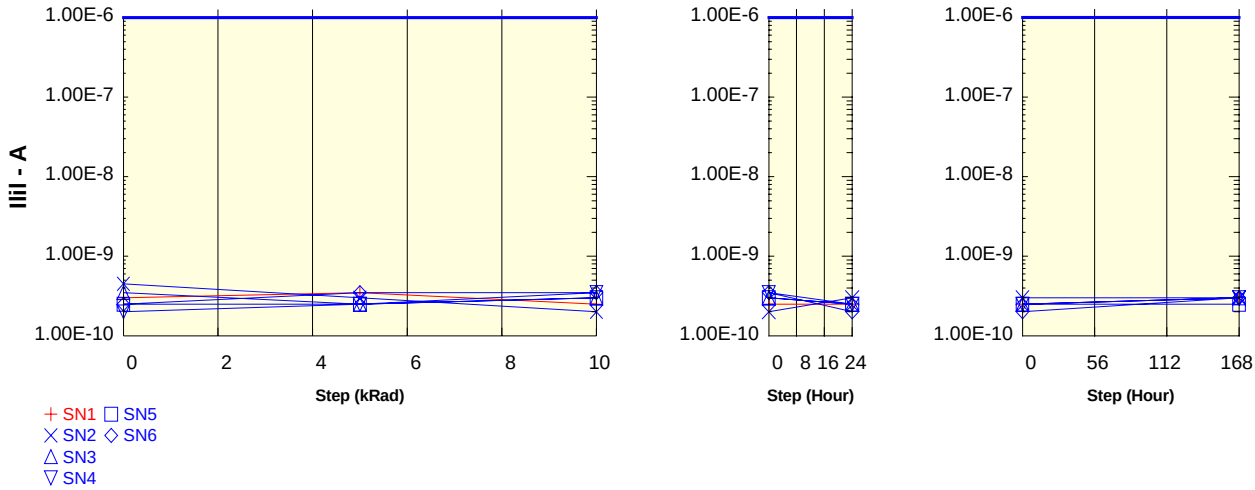
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.50E-10
SN2	2.50E-10	2.50E-10
SN3	2.50E-10	2.00E-10
SN4	2.00E-10	3.00E-10
SN5	2.50E-10	3.00E-10
SN6	2.50E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	2.50E-10	3.00E-10
Mean	2.40E-10	2.60E-10
Sigma	2.24E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	2.50E-10
SN2	2.50E-10	2.50E-10
SN3	2.00E-10	2.00E-10
SN4	3.00E-10	3.00E-10
SN5	3.00E-10	2.00E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.60E-10	2.30E-10
Sigma	4.18E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA9
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.50E-10	2.50E-10
SN2	4.50E-10	3.00E-10	2.00E-10
SN3	3.50E-10	2.50E-10	3.00E-10
SN4	2.00E-10	2.50E-10	3.50E-10
SN5	2.50E-10	2.50E-10	3.00E-10
SN6	2.50E-10	3.50E-10	3.50E-10
Statistics			
Min	2.00E-10	2.50E-10	2.00E-10
Max	4.50E-10	3.50E-10	3.50E-10
Mean	3.00E-10	2.80E-10	3.00E-10
Sigma	1.00E-10	4.47E-11	6.12E-11

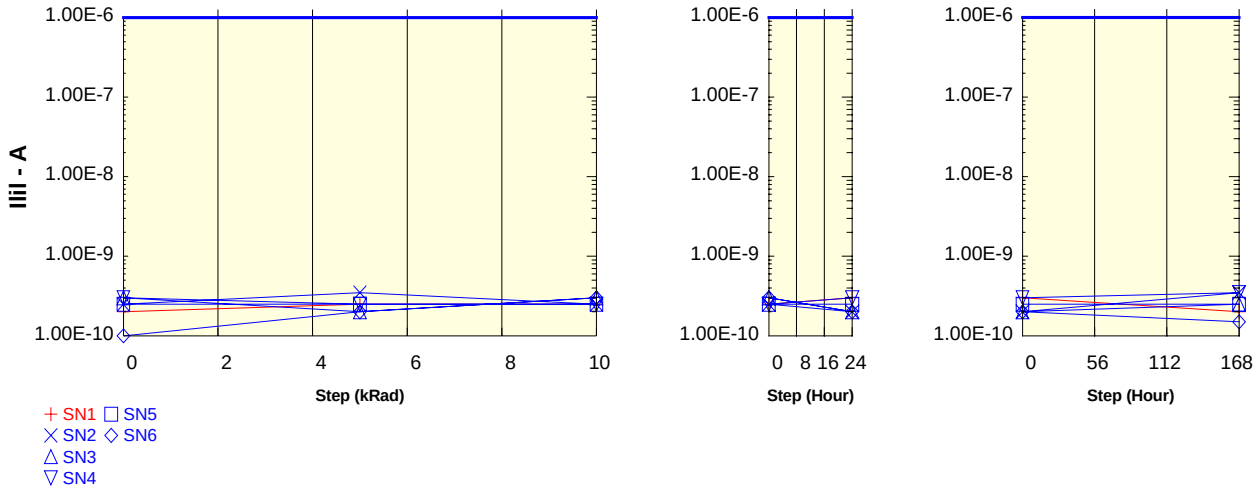
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.50E-10
SN2	2.00E-10	3.00E-10
SN3	3.00E-10	2.50E-10
SN4	3.50E-10	2.50E-10
SN5	3.00E-10	2.50E-10
SN6	3.50E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	3.00E-10	2.50E-10
Sigma	6.12E-11	3.54E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	3.00E-10
SN2	3.00E-10	3.00E-10
SN3	2.50E-10	3.00E-10
SN4	2.50E-10	3.00E-10
SN5	2.50E-10	2.50E-10
SN6	2.00E-10	3.00E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.00E-10	3.00E-10
Mean	2.50E-10	2.90E-10
Sigma	3.54E-11	2.24E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA8
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	2.50E-10	2.50E-10
SN2	2.50E-10	3.50E-10	2.50E-10
SN3	3.00E-10	2.00E-10	3.00E-10
SN4	3.00E-10	2.50E-10	2.50E-10
SN5	2.50E-10	2.50E-10	2.50E-10
SN6	1.00E-10	2.00E-10	3.00E-10
Statistics			
Min	1.00E-10	2.00E-10	2.50E-10
Max	3.00E-10	3.50E-10	3.00E-10
Mean	2.40E-10	2.50E-10	2.70E-10
Sigma	8.22E-11	6.12E-11	2.74E-11

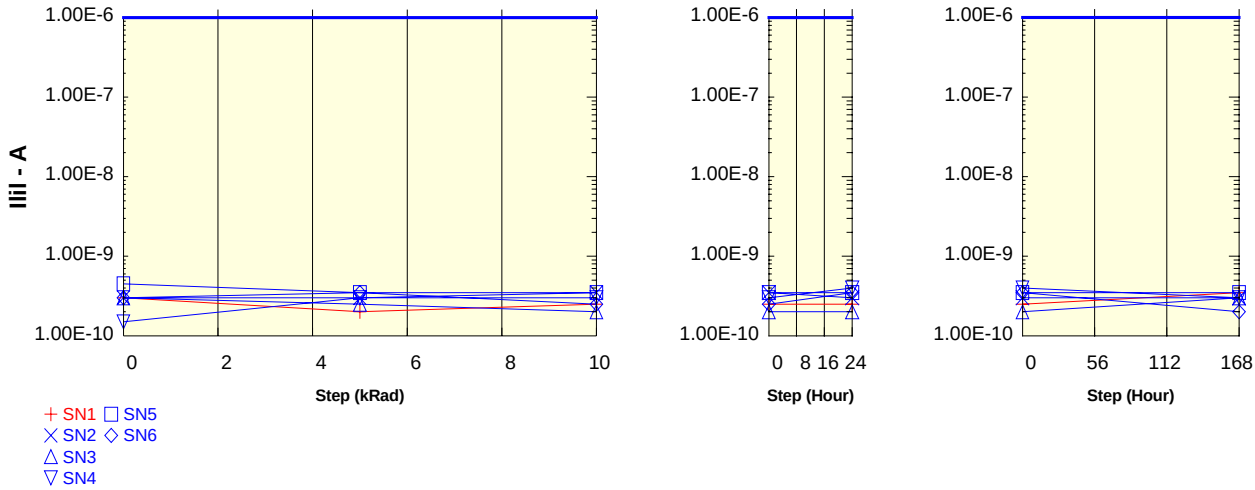
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	3.00E-10
SN2	2.50E-10	2.00E-10
SN3	3.00E-10	2.00E-10
SN4	2.50E-10	3.00E-10
SN5	2.50E-10	2.50E-10
SN6	3.00E-10	2.00E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.70E-10	2.30E-10
Sigma	2.74E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	2.00E-10
SN2	2.00E-10	3.50E-10
SN3	2.00E-10	2.50E-10
SN4	3.00E-10	3.50E-10
SN5	2.50E-10	2.50E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	3.00E-10	3.50E-10
Mean	2.30E-10	2.70E-10
Sigma	4.47E-11	8.37E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA7
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	2.00E-10	2.50E-10
SN2	3.00E-10	3.00E-10	3.50E-10
SN3	3.00E-10	2.50E-10	2.00E-10
SN4	1.50E-10	3.00E-10	3.00E-10
SN5	4.50E-10	3.50E-10	3.50E-10
SN6	3.00E-10	3.50E-10	2.50E-10
Statistics			
Min	1.50E-10	2.50E-10	2.00E-10
Max	4.50E-10	3.50E-10	3.50E-10
Mean	3.00E-10	3.10E-10	2.90E-10
Sigma	1.06E-10	4.18E-11	6.52E-11

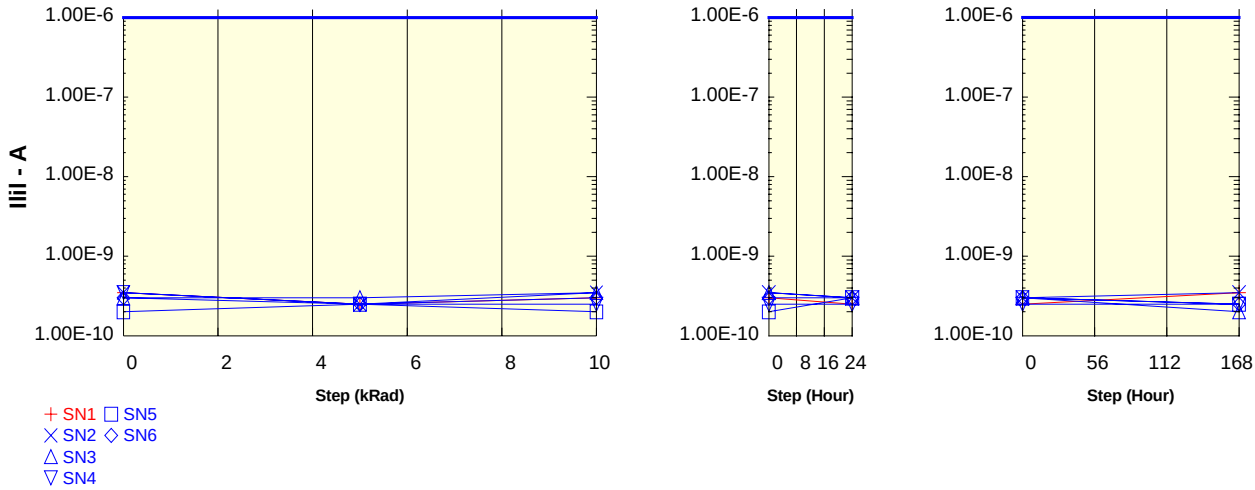
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.50E-10
SN2	3.50E-10	3.00E-10
SN3	2.00E-10	2.00E-10
SN4	3.00E-10	4.00E-10
SN5	3.50E-10	3.50E-10
SN6	2.50E-10	3.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.50E-10	4.00E-10
Mean	2.90E-10	3.20E-10
Sigma	6.52E-11	7.58E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	3.50E-10
SN2	3.00E-10	3.00E-10
SN3	2.00E-10	3.00E-10
SN4	4.00E-10	3.00E-10
SN5	3.50E-10	3.50E-10
SN6	3.50E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	4.00E-10	3.50E-10
Mean	3.20E-10	2.90E-10
Sigma	7.58E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA6
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.50E-10	2.50E-10	3.00E-10
SN2	3.50E-10	2.50E-10	3.50E-10
SN3	3.00E-10	3.00E-10	3.50E-10
SN4	3.50E-10	2.50E-10	2.50E-10
SN5	2.00E-10	2.50E-10	2.00E-10
SN6	3.00E-10	2.50E-10	3.00E-10
Statistics			
Min	2.00E-10	2.50E-10	2.00E-10
Max	3.50E-10	3.00E-10	3.50E-10
Mean	3.00E-10	2.60E-10	2.90E-10
Sigma	6.12E-11	2.24E-11	6.52E-11

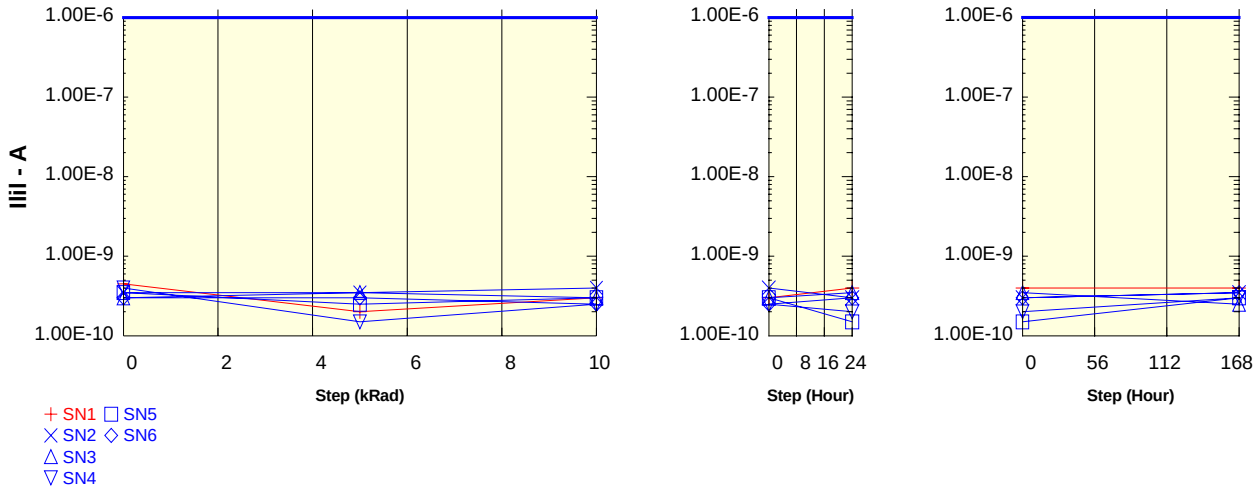
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	2.50E-10
SN2	3.50E-10	3.00E-10
SN3	3.50E-10	3.00E-10
SN4	2.50E-10	2.50E-10
SN5	2.00E-10	3.00E-10
SN6	3.00E-10	3.00E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.50E-10	3.00E-10
Mean	2.90E-10	2.90E-10
Sigma	6.52E-11	2.24E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	3.50E-10
SN2	3.00E-10	3.50E-10
SN3	3.00E-10	2.00E-10
SN4	2.50E-10	2.50E-10
SN5	3.00E-10	2.50E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.00E-10	3.50E-10
Mean	2.90E-10	2.60E-10
Sigma	2.24E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA5
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.50E-10	2.00E-10	3.00E-10
SN2	3.50E-10	3.50E-10	4.00E-10
SN3	3.00E-10	3.50E-10	3.00E-10
SN4	4.00E-10	1.50E-10	2.50E-10
SN5	3.50E-10	2.50E-10	3.00E-10
SN6	3.00E-10	3.00E-10	2.50E-10
Statistics			
Min	3.00E-10	1.50E-10	2.50E-10
Max	4.00E-10	3.50E-10	4.00E-10
Mean	3.40E-10	2.80E-10	3.00E-10
Sigma	4.18E-11	8.37E-11	6.12E-11

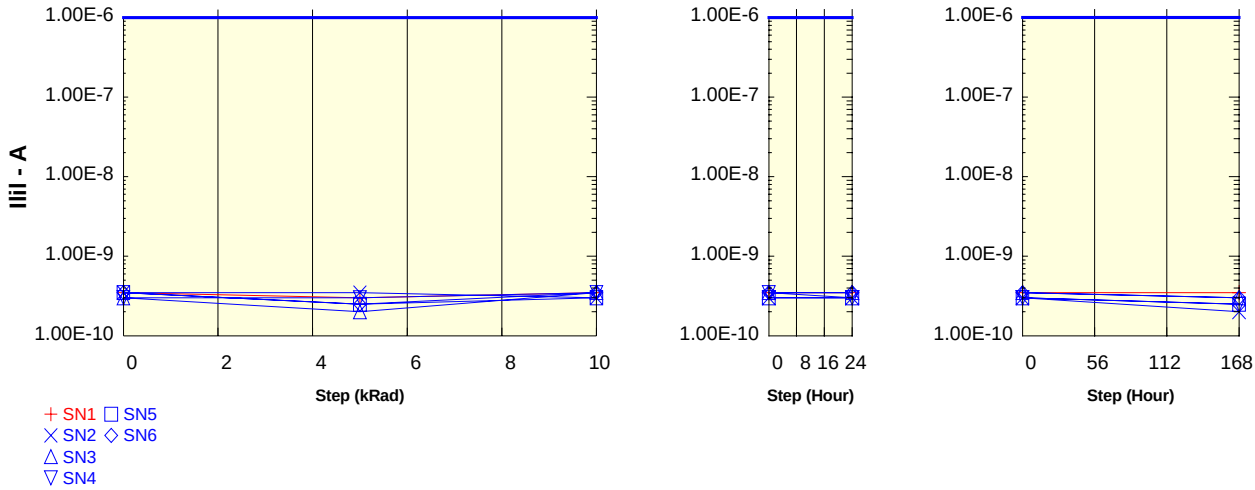
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	4.00E-10
SN2	4.00E-10	3.00E-10
SN3	3.00E-10	3.50E-10
SN4	2.50E-10	2.00E-10
SN5	3.00E-10	1.50E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.50E-10	1.50E-10
Max	4.00E-10	3.50E-10
Mean	3.00E-10	2.60E-10
Sigma	6.12E-11	8.22E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.00E-10	4.00E-10
SN2	3.00E-10	3.50E-10
SN3	3.50E-10	2.50E-10
SN4	2.00E-10	3.00E-10
SN5	1.50E-10	3.00E-10
SN6	3.00E-10	3.50E-10
Statistics		
Min	1.50E-10	2.50E-10
Max	3.50E-10	3.50E-10
Mean	2.60E-10	3.10E-10
Sigma	8.22E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA4
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.50E-10	3.00E-10	3.50E-10
SN2	3.50E-10	3.50E-10	3.00E-10
SN3	3.00E-10	2.00E-10	3.50E-10
SN4	3.00E-10	3.00E-10	3.50E-10
SN5	3.50E-10	2.50E-10	3.00E-10
SN6	3.50E-10	2.50E-10	3.50E-10
Statistics			
Min	3.00E-10	2.00E-10	3.00E-10
Max	3.50E-10	3.50E-10	3.50E-10
Mean	3.30E-10	2.70E-10	3.30E-10
Sigma	2.74E-11	5.70E-11	2.74E-11

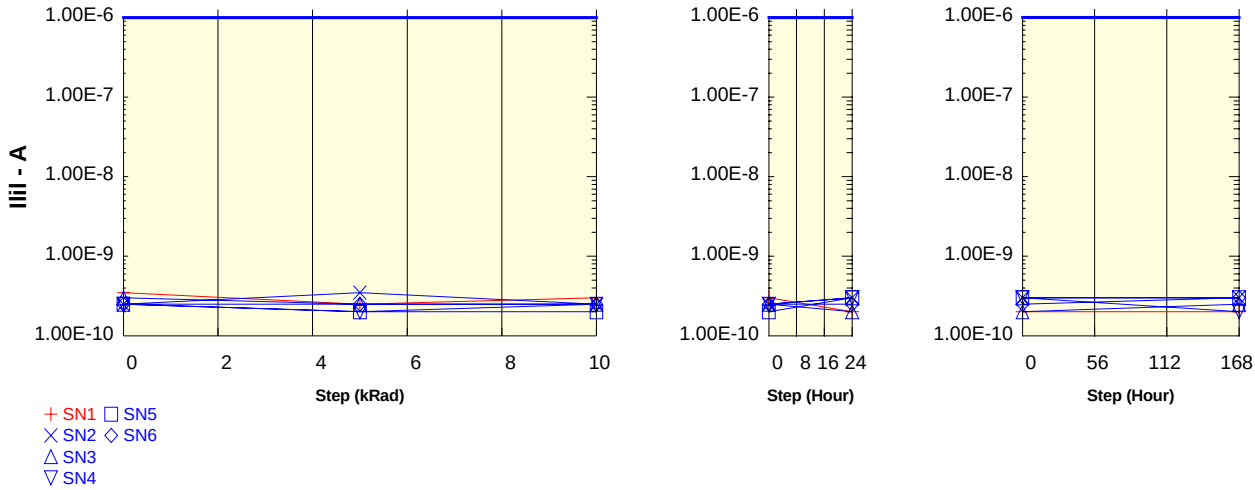
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.50E-10	3.50E-10
SN2	3.00E-10	3.00E-10
SN3	3.50E-10	3.50E-10
SN4	3.50E-10	3.00E-10
SN5	3.00E-10	3.00E-10
SN6	3.50E-10	3.50E-10
Statistics		
Min	3.00E-10	3.00E-10
Max	3.50E-10	3.50E-10
Mean	3.30E-10	3.20E-10
Sigma	2.74E-11	2.74E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.50E-10	3.50E-10
SN2	3.00E-10	2.00E-10
SN3	3.50E-10	3.00E-10
SN4	3.00E-10	2.50E-10
SN5	3.00E-10	2.50E-10
SN6	3.50E-10	3.00E-10
Statistics		
Min	3.00E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	3.20E-10	2.60E-10
Sigma	2.74E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA3
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.50E-10	2.50E-10	3.00E-10
SN2	2.50E-10	3.50E-10	2.50E-10
SN3	3.00E-10	2.50E-10	2.50E-10
SN4	2.50E-10	2.00E-10	2.50E-10
SN5	2.50E-10	2.00E-10	2.00E-10
SN6	2.50E-10	2.50E-10	2.50E-10
Statistics			
Min	2.50E-10	2.00E-10	2.00E-10
Max	3.00E-10	3.50E-10	2.50E-10
Mean	2.60E-10	2.50E-10	2.40E-10
Sigma	2.24E-11	6.12E-11	2.24E-11

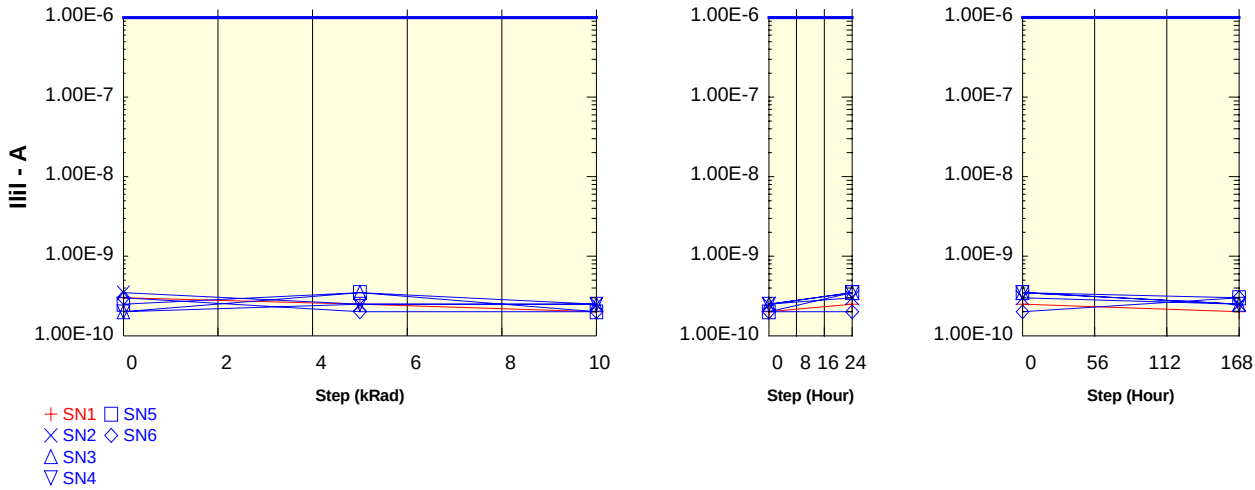
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	2.00E-10
SN2	2.50E-10	3.00E-10
SN3	2.50E-10	2.00E-10
SN4	2.50E-10	3.00E-10
SN5	2.00E-10	3.00E-10
SN6	2.50E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	2.50E-10	3.00E-10
Mean	2.40E-10	2.70E-10
Sigma	2.24E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.00E-10
SN2	3.00E-10	3.00E-10
SN3	2.00E-10	2.50E-10
SN4	3.00E-10	2.00E-10
SN5	3.00E-10	3.00E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.70E-10	2.70E-10
Sigma	4.47E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA2
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	2.50E-10	2.00E-10
SN2	3.50E-10	2.50E-10	2.50E-10
SN3	2.00E-10	3.50E-10	2.50E-10
SN4	2.00E-10	2.50E-10	2.50E-10
SN5	2.50E-10	3.50E-10	2.00E-10
SN6	3.00E-10	2.00E-10	2.00E-10
Statistics			
Min	2.00E-10	2.00E-10	2.00E-10
Max	3.50E-10	3.50E-10	2.50E-10
Mean	2.60E-10	2.80E-10	2.30E-10
Sigma	6.52E-11	6.71E-11	2.74E-11

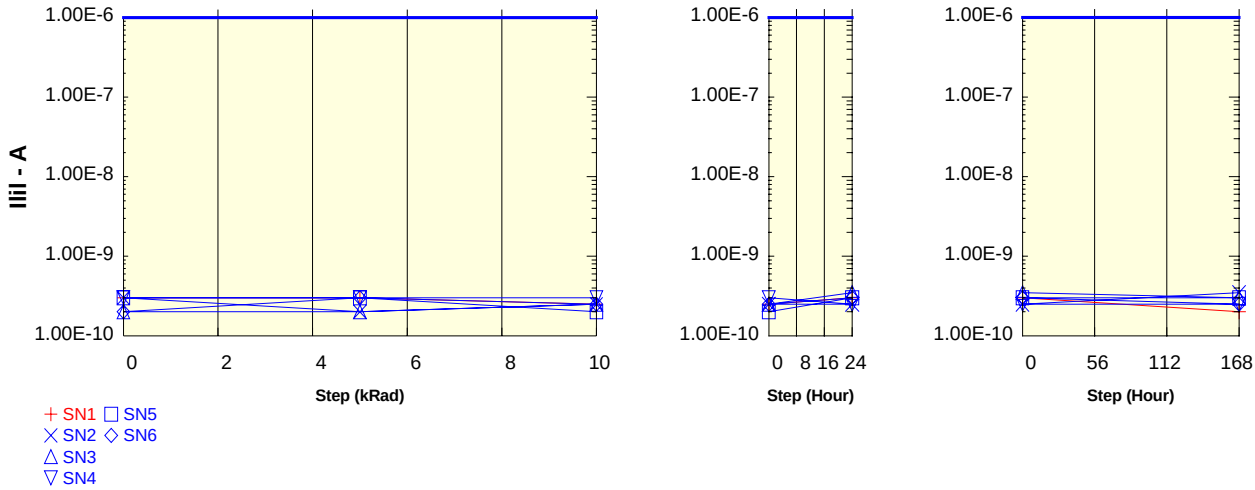
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	2.50E-10
SN2	2.50E-10	3.00E-10
SN3	2.50E-10	3.50E-10
SN4	2.50E-10	3.50E-10
SN5	2.00E-10	3.50E-10
SN6	2.00E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	2.50E-10	3.50E-10
Mean	2.30E-10	3.10E-10
Sigma	2.74E-11	6.52E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	2.00E-10
SN2	3.00E-10	2.50E-10
SN3	3.50E-10	2.50E-10
SN4	3.50E-10	2.50E-10
SN5	3.50E-10	3.00E-10
SN6	2.00E-10	3.00E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.50E-10	3.00E-10
Mean	3.10E-10	2.70E-10
Sigma	6.52E-11	2.74E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA1
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.00E-10	2.50E-10
SN2	3.00E-10	2.00E-10	2.50E-10
SN3	2.00E-10	2.00E-10	2.50E-10
SN4	3.00E-10	3.00E-10	3.00E-10
SN5	3.00E-10	3.00E-10	2.00E-10
SN6	2.00E-10	3.00E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10	3.00E-10
Mean	2.60E-10	2.60E-10	2.50E-10
Sigma	5.48E-11	5.48E-11	3.54E-11

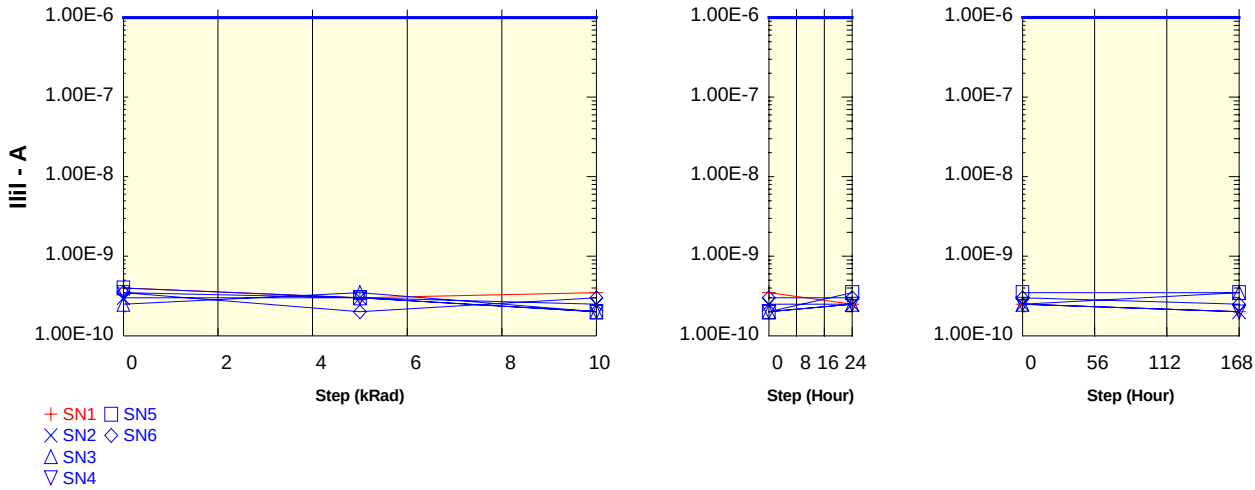
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	3.00E-10
SN2	2.50E-10	2.50E-10
SN3	2.50E-10	3.50E-10
SN4	3.00E-10	2.50E-10
SN5	2.00E-10	3.00E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.00E-10	3.50E-10
Mean	2.50E-10	2.90E-10
Sigma	3.54E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	2.00E-10
SN2	2.50E-10	3.50E-10
SN3	3.50E-10	3.00E-10
SN4	2.50E-10	2.50E-10
SN5	3.00E-10	3.00E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.50E-10	2.50E-10
Max	3.50E-10	3.50E-10
Mean	2.90E-10	2.90E-10
Sigma	4.18E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current Low : IIilA0
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	3.00E-10	3.50E-10
SN2	3.00E-10	3.00E-10	2.50E-10
SN3	2.50E-10	3.50E-10	2.00E-10
SN4	3.50E-10	3.00E-10	2.00E-10
SN5	4.00E-10	3.00E-10	2.00E-10
SN6	3.50E-10	2.00E-10	3.00E-10
Statistics			
Min	2.50E-10	2.00E-10	2.00E-10
Max	4.00E-10	3.50E-10	3.00E-10
Mean	3.30E-10	2.90E-10	2.30E-10
Sigma	5.70E-11	5.48E-11	4.47E-11

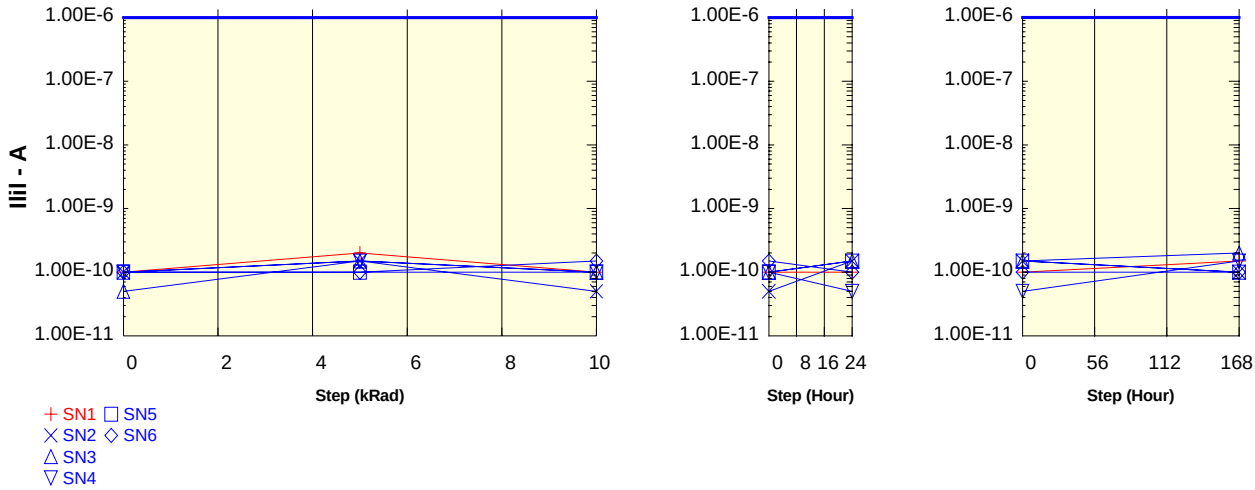
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.50E-10	2.50E-10
SN2	2.50E-10	2.50E-10
SN3	2.00E-10	2.50E-10
SN4	2.00E-10	2.50E-10
SN5	2.00E-10	3.50E-10
SN6	3.00E-10	3.00E-10
Statistics		
Min	2.00E-10	2.50E-10
Max	3.00E-10	3.50E-10
Mean	2.30E-10	2.80E-10
Sigma	4.47E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	2.00E-10
SN2	2.50E-10	2.00E-10
SN3	2.50E-10	3.50E-10
SN4	2.50E-10	2.00E-10
SN5	3.50E-10	3.50E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.50E-10	3.50E-10
Mean	2.80E-10	2.70E-10
Sigma	4.47E-11	7.58E-11

Test conditions : TID
Parameter : Input Leakage Current Low : Iili/RST
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.00E-10	2.00E-10	1.00E-10
SN2	1.00E-10	1.50E-10	5.00E-11
SN3	5.00E-11	1.50E-10	1.00E-10
SN4	1.00E-10	1.50E-10	1.00E-10
SN5	1.00E-10	1.00E-10	1.00E-10
SN6	1.00E-10	1.00E-10	1.50E-10
Statistics			
Min	5.00E-11	1.00E-10	5.00E-11
Max	1.00E-10	1.50E-10	1.50E-10
Mean	9.00E-11	1.30E-10	1.00E-10
Sigma	2.24E-11	2.74E-11	3.54E-11

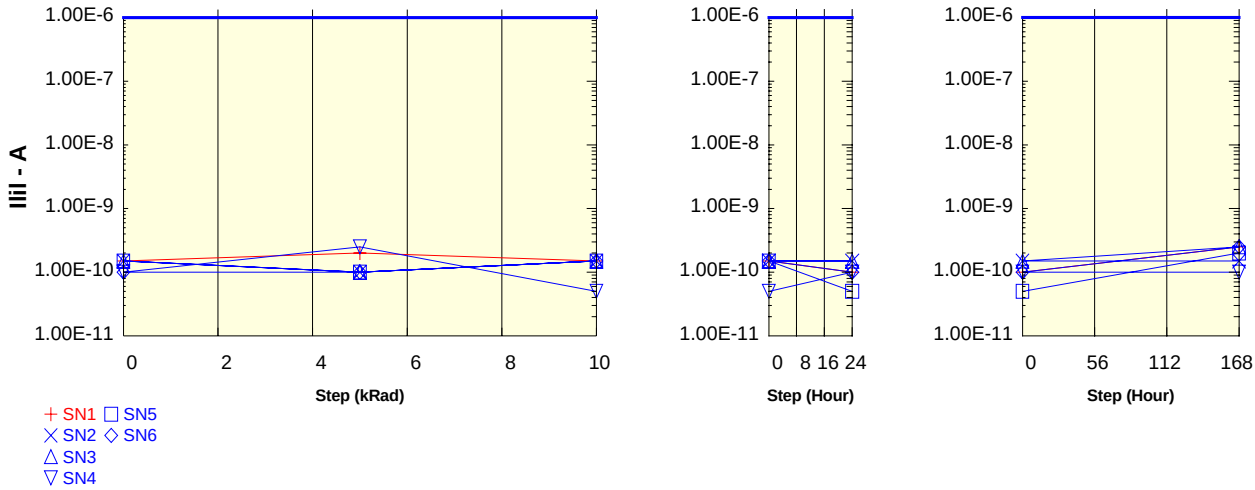
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.00E-10	1.00E-10
SN2	5.00E-11	1.50E-10
SN3	1.00E-10	1.50E-10
SN4	1.00E-10	5.00E-11
SN5	1.00E-10	1.50E-10
SN6	1.50E-10	1.00E-10
Statistics		
Min	5.00E-11	5.00E-11
Max	1.50E-10	1.50E-10
Mean	1.00E-10	1.20E-10
Sigma	3.54E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.00E-10	1.50E-10
SN2	1.50E-10	1.00E-10
SN3	1.50E-10	2.00E-10
SN4	5.00E-11	1.50E-10
SN5	1.50E-10	1.00E-10
SN6	1.00E-10	1.00E-10
Statistics		
Min	5.00E-11	1.00E-10
Max	1.50E-10	2.00E-10
Mean	1.20E-10	1.30E-10
Sigma	4.47E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current Low : Iili/CE
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	2.00E-10	1.50E-10
SN2	1.50E-10	1.00E-10	1.50E-10
SN3	1.50E-10	1.00E-10	1.50E-10
SN4	1.00E-10	2.50E-10	5.00E-11
SN5	1.50E-10	1.00E-10	1.50E-10
SN6	1.00E-10	1.00E-10	1.50E-10
Statistics			
Min	1.00E-10	1.00E-10	5.00E-11
Max	1.50E-10	2.50E-10	1.50E-10
Mean	1.30E-10	1.30E-10	1.30E-10
Sigma	2.74E-11	6.71E-11	4.47E-11

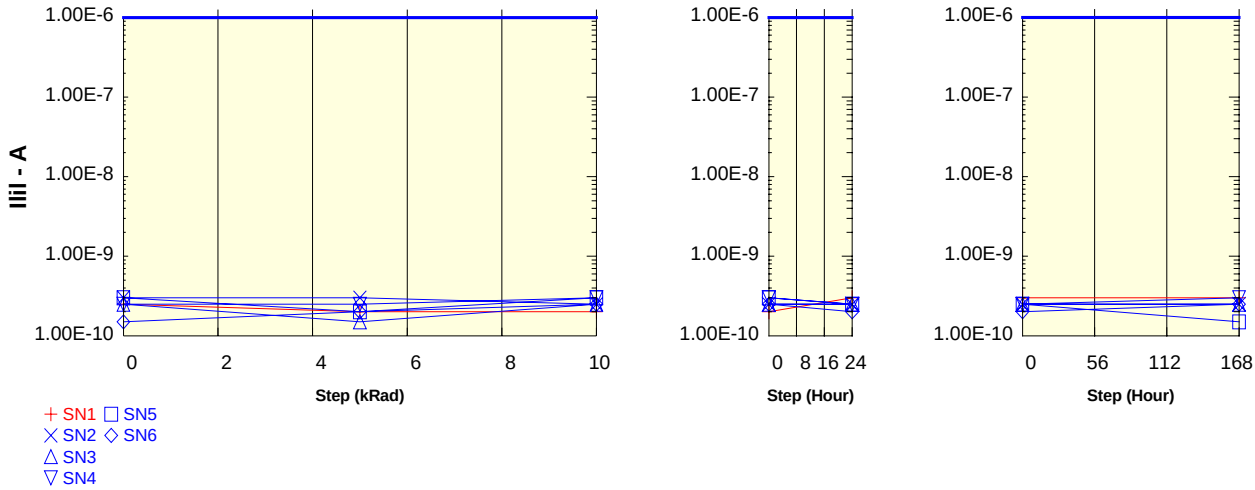
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	1.00E-10
SN2	1.50E-10	1.50E-10
SN3	1.50E-10	1.50E-10
SN4	5.00E-11	1.00E-10
SN5	1.50E-10	5.00E-11
SN6	1.50E-10	1.00E-10
Statistics		
Min	5.00E-11	5.00E-11
Max	1.50E-10	1.50E-10
Mean	1.30E-10	1.10E-10
Sigma	4.47E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.00E-10	2.50E-10
SN2	1.50E-10	1.50E-10
SN3	1.50E-10	2.50E-10
SN4	1.00E-10	1.00E-10
SN5	5.00E-11	2.00E-10
SN6	1.00E-10	2.50E-10
Statistics		
Min	5.00E-11	1.00E-10
Max	1.50E-10	2.50E-10
Mean	1.10E-10	1.90E-10
Sigma	4.18E-11	6.52E-11

Test conditions : TID
Parameter : Input Leakage Current Low : Iili/OE
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	2.00E-10	2.00E-10
SN2	3.00E-10	3.00E-10	2.50E-10
SN3	2.50E-10	1.50E-10	2.50E-10
SN4	2.50E-10	2.50E-10	3.00E-10
SN5	3.00E-10	2.00E-10	3.00E-10
SN6	1.50E-10	2.00E-10	2.50E-10
Statistics			
Min	1.50E-10	1.50E-10	2.50E-10
Max	3.00E-10	3.00E-10	3.00E-10
Mean	2.50E-10	2.20E-10	2.70E-10
Sigma	6.12E-11	5.70E-11	2.74E-11

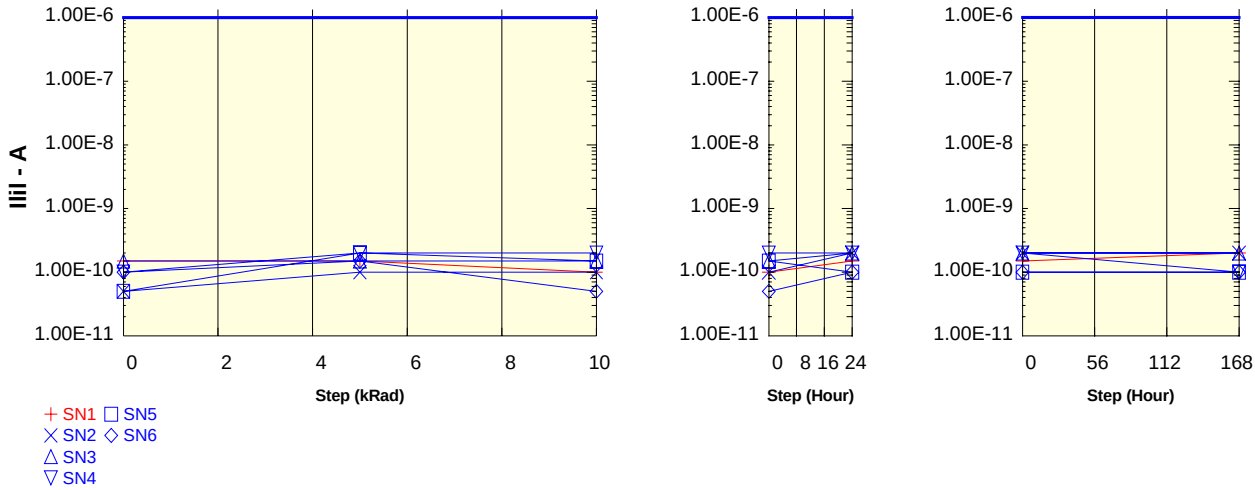
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	3.00E-10
SN2	2.50E-10	2.50E-10
SN3	2.50E-10	2.50E-10
SN4	3.00E-10	2.50E-10
SN5	3.00E-10	2.50E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.00E-10	2.50E-10
Mean	2.70E-10	2.40E-10
Sigma	2.74E-11	2.24E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	3.00E-10
SN2	2.50E-10	2.50E-10
SN3	2.50E-10	2.50E-10
SN4	2.50E-10	3.00E-10
SN5	2.50E-10	1.50E-10
SN6	2.00E-10	2.50E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	2.50E-10	3.00E-10
Mean	2.40E-10	2.40E-10
Sigma	2.24E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current Low : Iili/WE
Vin = Gnd. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	1.50E-10	1.00E-10
SN2	5.00E-11	1.00E-10	1.00E-10
SN3	1.50E-10	1.50E-10	1.50E-10
SN4	1.00E-10	2.00E-10	2.00E-10
SN5	5.00E-11	2.00E-10	1.50E-10
SN6	1.00E-10	1.50E-10	5.00E-11
Statistics			
Min	5.00E-11	1.00E-10	5.00E-11
Max	1.50E-10	2.00E-10	2.00E-10
Mean	9.00E-11	1.60E-10	1.30E-10
Sigma	4.18E-11	4.18E-11	5.70E-11

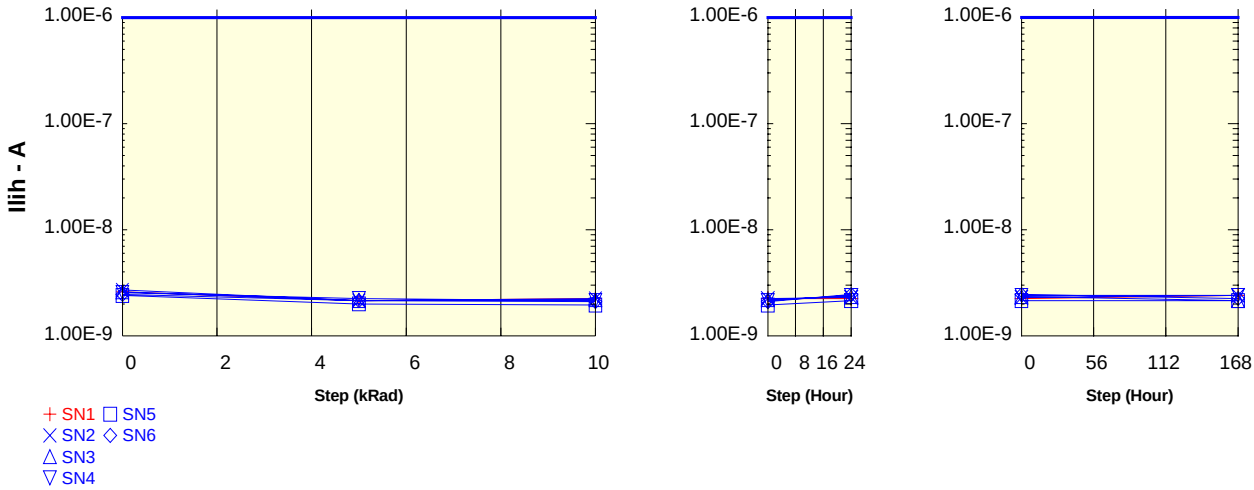
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.00E-10	1.50E-10
SN2	1.00E-10	2.00E-10
SN3	1.50E-10	2.00E-10
SN4	2.00E-10	2.00E-10
SN5	1.50E-10	1.00E-10
SN6	5.00E-11	1.00E-10
Statistics		
Min	5.00E-11	1.00E-10
Max	2.00E-10	2.00E-10
Mean	1.30E-10	1.60E-10
Sigma	5.70E-11	5.48E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.50E-10	2.00E-10
SN2	2.00E-10	2.00E-10
SN3	2.00E-10	2.00E-10
SN4	2.00E-10	1.00E-10
SN5	1.00E-10	1.00E-10
SN6	1.00E-10	1.00E-10
Statistics		
Min	1.00E-10	1.00E-10
Max	2.00E-10	2.00E-10
Mean	1.60E-10	1.40E-10
Sigma	5.48E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current High : IlihA20
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.60E-9	2.15E-9	2.25E-9
SN2	2.70E-9	2.15E-9	2.25E-9
SN3	2.60E-9	2.15E-9	2.20E-9
SN4	2.55E-9	2.25E-9	2.15E-9
SN5	2.40E-9	2.00E-9	1.95E-9
SN6	2.45E-9	2.15E-9	2.10E-9
Statistics			
Min	2.40E-9	2.00E-9	1.95E-9
Max	2.70E-9	2.25E-9	2.25E-9
Mean	2.54E-9	2.14E-9	2.13E-9
Sigma	1.19E-10	8.94E-11	1.15E-10

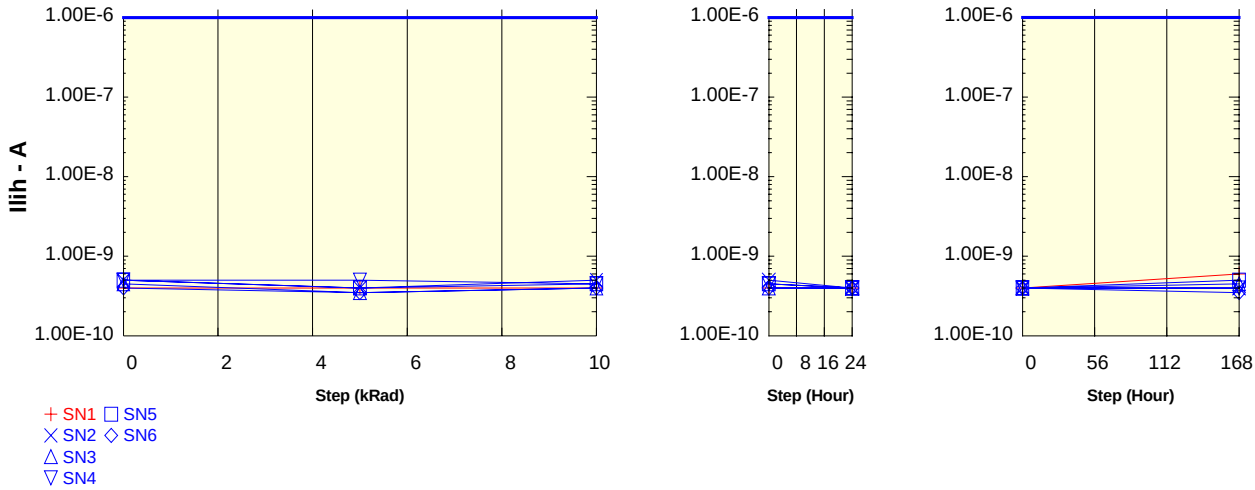
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.25E-9	2.25E-9
SN2	2.25E-9	2.30E-9
SN3	2.20E-9	2.35E-9
SN4	2.15E-9	2.40E-9
SN5	1.95E-9	2.15E-9
SN6	2.10E-9	2.45E-9
Statistics		
Min	1.95E-9	2.15E-9
Max	2.25E-9	2.45E-9
Mean	2.13E-9	2.33E-9
Sigma	1.15E-10	1.15E-10

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.25E-9	2.40E-9
SN2	2.30E-9	2.40E-9
SN3	2.35E-9	2.15E-9
SN4	2.40E-9	2.40E-9
SN5	2.15E-9	2.15E-9
SN6	2.45E-9	2.25E-9
Statistics		
Min	2.15E-9	2.15E-9
Max	2.45E-9	2.40E-9
Mean	2.33E-9	2.27E-9
Sigma	1.15E-10	1.25E-10

Test conditions : TID
Parameter : Input Leakage Current High : IihA19
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	4.00E-10	4.00E-10
SN2	5.00E-10	4.00E-10	5.00E-10
SN3	4.50E-10	3.50E-10	4.00E-10
SN4	5.00E-10	5.00E-10	4.50E-10
SN5	5.00E-10	4.00E-10	4.50E-10
SN6	4.00E-10	3.50E-10	4.00E-10
Statistics			
Min	4.00E-10	3.50E-10	4.00E-10
Max	5.00E-10	5.00E-10	5.00E-10
Mean	4.70E-10	4.00E-10	4.40E-10
Sigma	4.47E-11	6.12E-11	4.18E-11

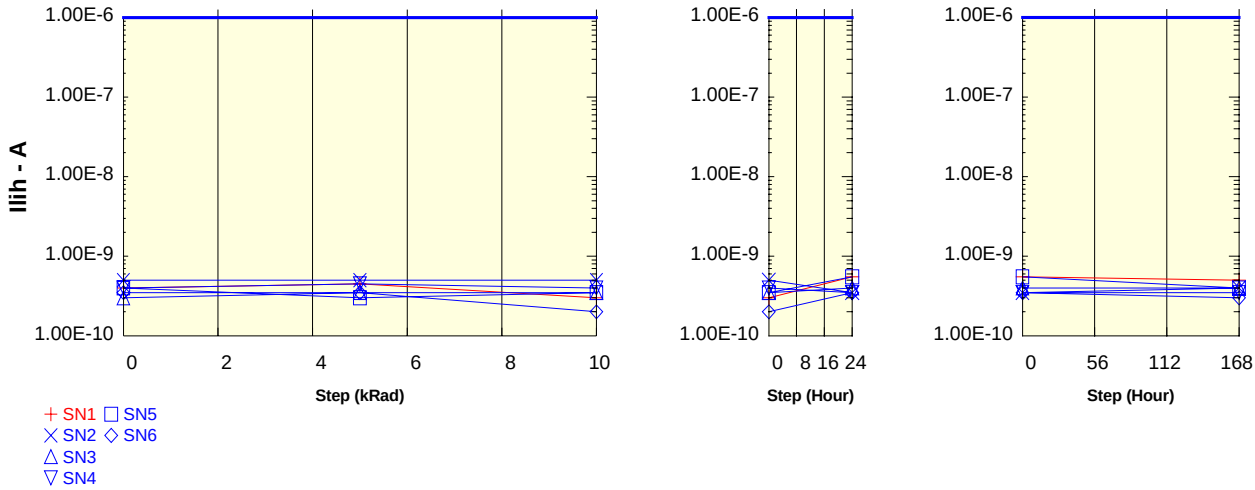
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.00E-10	4.00E-10
SN2	5.00E-10	4.00E-10
SN3	4.00E-10	4.00E-10
SN4	4.50E-10	4.00E-10
SN5	4.50E-10	4.00E-10
SN6	4.00E-10	4.00E-10
Statistics		
Min	4.00E-10	4.00E-10
Max	5.00E-10	4.00E-10
Mean	4.40E-10	4.00E-10
Sigma	4.18E-11	0.00E+0

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.00E-10	6.00E-10
SN2	4.00E-10	4.00E-10
SN3	4.00E-10	4.50E-10
SN4	4.00E-10	4.00E-10
SN5	4.00E-10	5.00E-10
SN6	4.00E-10	3.50E-10
Statistics		
Min	4.00E-10	3.50E-10
Max	4.00E-10	5.00E-10
Mean	4.00E-10	4.20E-10
Sigma	0.00E+0	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA18
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	4.50E-10	3.00E-10
SN2	5.00E-10	5.00E-10	5.00E-10
SN3	3.00E-10	3.50E-10	3.50E-10
SN4	4.00E-10	4.50E-10	4.00E-10
SN5	4.00E-10	3.00E-10	3.50E-10
SN6	3.50E-10	3.50E-10	2.00E-10
Statistics			
Min	3.00E-10	3.00E-10	2.00E-10
Max	5.00E-10	5.00E-10	5.00E-10
Mean	3.90E-10	3.90E-10	3.60E-10
Sigma	7.42E-11	8.22E-11	1.08E-10

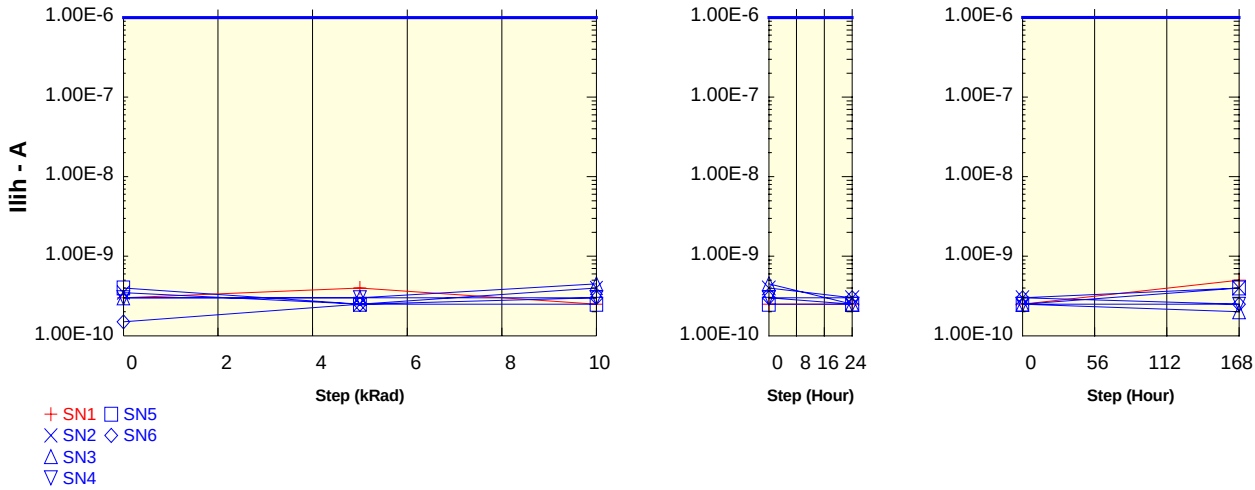
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	5.50E-10
SN2	5.00E-10	3.50E-10
SN3	3.50E-10	4.00E-10
SN4	4.00E-10	3.50E-10
SN5	3.50E-10	5.50E-10
SN6	2.00E-10	3.50E-10
Statistics		
Min	2.00E-10	3.50E-10
Max	5.00E-10	5.50E-10
Mean	3.60E-10	4.00E-10
Sigma	1.08E-10	8.66E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	5.50E-10	5.00E-10
SN2	3.50E-10	4.00E-10
SN3	4.00E-10	4.00E-10
SN4	3.50E-10	3.50E-10
SN5	5.50E-10	4.00E-10
SN6	3.50E-10	3.00E-10
Statistics		
Min	3.50E-10	3.00E-10
Max	5.50E-10	4.00E-10
Mean	4.00E-10	3.70E-10
Sigma	8.66E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA17
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	4.00E-10	2.50E-10
SN2	3.50E-10	2.50E-10	4.00E-10
SN3	3.00E-10	3.00E-10	4.50E-10
SN4	3.00E-10	3.00E-10	3.00E-10
SN5	4.00E-10	2.50E-10	2.50E-10
SN6	1.50E-10	2.50E-10	3.00E-10
Statistics			
Min	1.50E-10	2.50E-10	2.50E-10
Max	4.00E-10	3.00E-10	4.50E-10
Mean	3.00E-10	2.70E-10	3.40E-10
Sigma	9.35E-11	2.74E-11	8.22E-11

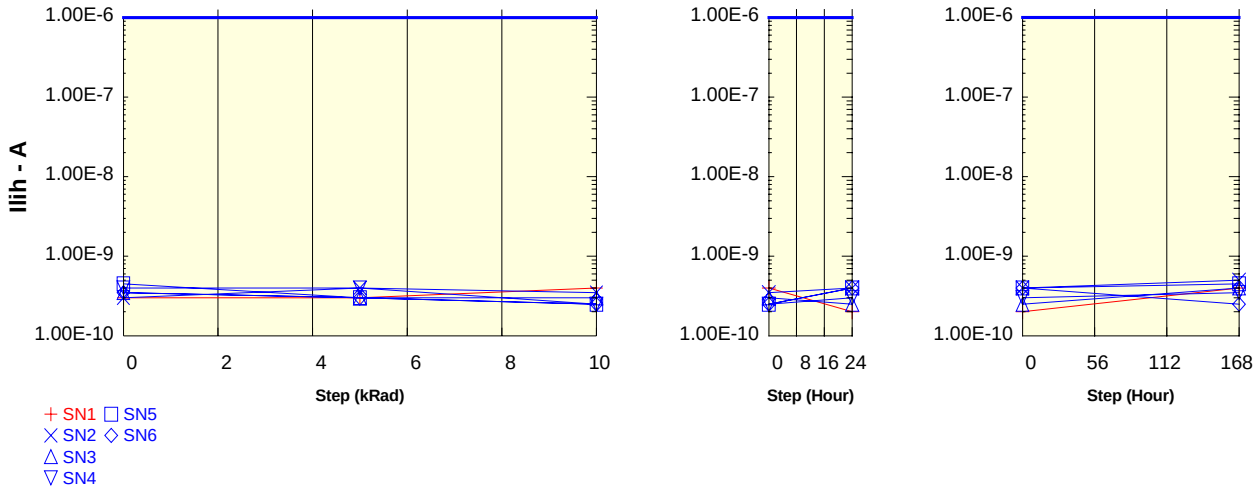
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.50E-10
SN2	4.00E-10	3.00E-10
SN3	4.50E-10	2.50E-10
SN4	3.00E-10	2.50E-10
SN5	2.50E-10	2.50E-10
SN6	3.00E-10	3.00E-10
Statistics		
Min	2.50E-10	2.50E-10
Max	4.50E-10	3.00E-10
Mean	3.40E-10	2.70E-10
Sigma	8.22E-11	2.74E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	5.00E-10
SN2	3.00E-10	4.00E-10
SN3	2.50E-10	2.00E-10
SN4	2.50E-10	2.50E-10
SN5	2.50E-10	4.00E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.50E-10	2.00E-10
Max	3.00E-10	4.00E-10
Mean	2.70E-10	3.00E-10
Sigma	2.74E-11	9.35E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA16
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.00E-10	4.00E-10
SN2	3.00E-10	4.00E-10	3.50E-10
SN3	3.50E-10	3.00E-10	3.00E-10
SN4	4.00E-10	4.00E-10	2.50E-10
SN5	4.50E-10	3.00E-10	2.50E-10
SN6	3.50E-10	3.00E-10	2.50E-10
Statistics			
Min	3.00E-10	3.00E-10	2.50E-10
Max	4.50E-10	4.00E-10	3.50E-10
Mean	3.70E-10	3.40E-10	2.80E-10
Sigma	5.70E-11	5.48E-11	4.47E-11

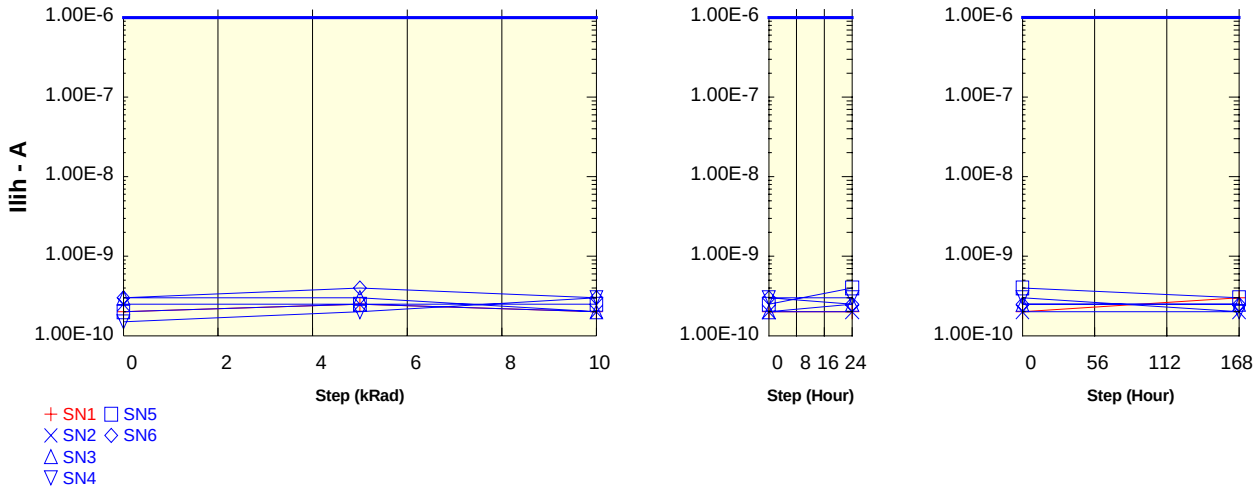
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.00E-10	2.00E-10
SN2	3.50E-10	4.00E-10
SN3	3.00E-10	2.50E-10
SN4	2.50E-10	3.00E-10
SN5	2.50E-10	4.00E-10
SN6	2.50E-10	4.00E-10
Statistics		
Min	2.50E-10	2.50E-10
Max	3.50E-10	4.00E-10
Mean	2.80E-10	3.50E-10
Sigma	4.47E-11	7.07E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	4.00E-10
SN2	4.00E-10	5.00E-10
SN3	2.50E-10	4.00E-10
SN4	3.00E-10	3.50E-10
SN5	4.00E-10	4.50E-10
SN6	4.00E-10	2.50E-10
Statistics		
Min	2.50E-10	2.50E-10
Max	4.00E-10	5.00E-10
Mean	3.50E-10	3.90E-10
Sigma	7.07E-11	9.62E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA15
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	2.50E-10	2.00E-10
SN2	2.50E-10	2.50E-10	2.00E-10
SN3	3.00E-10	3.00E-10	2.00E-10
SN4	1.50E-10	2.00E-10	3.00E-10
SN5	2.00E-10	2.50E-10	2.50E-10
SN6	3.00E-10	4.00E-10	3.00E-10
Statistics			
Min	1.50E-10	2.00E-10	2.00E-10
Max	3.00E-10	4.00E-10	3.00E-10
Mean	2.40E-10	2.80E-10	2.50E-10
Sigma	6.52E-11	7.58E-11	5.00E-11

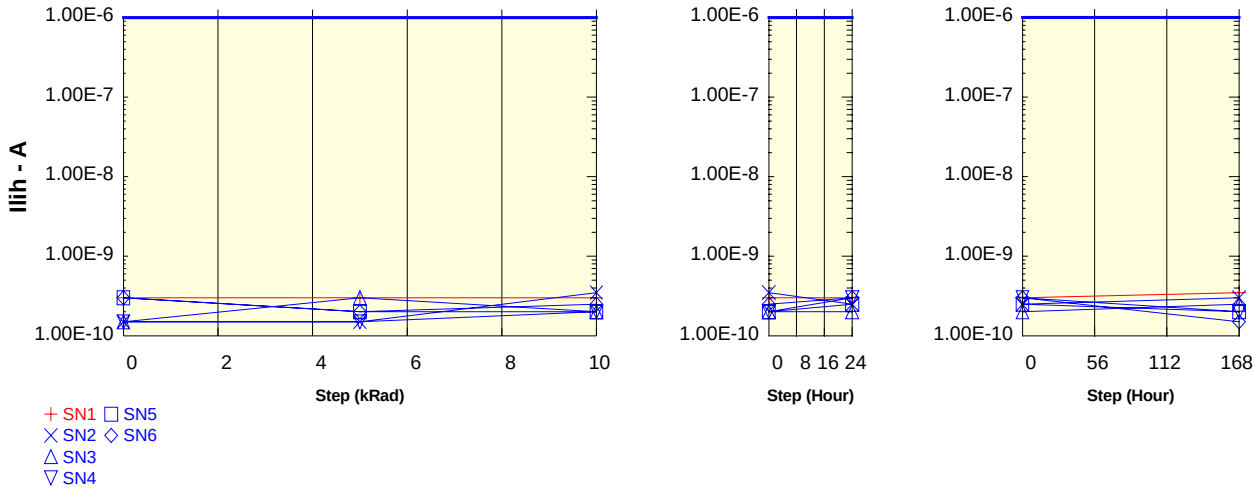
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	2.00E-10
SN2	2.00E-10	2.00E-10
SN3	2.00E-10	2.50E-10
SN4	3.00E-10	3.00E-10
SN5	2.50E-10	4.00E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	4.00E-10
Mean	2.50E-10	2.80E-10
Sigma	5.00E-11	7.58E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	3.00E-10
SN2	2.00E-10	2.00E-10
SN3	2.50E-10	2.50E-10
SN4	3.00E-10	2.00E-10
SN5	4.00E-10	3.00E-10
SN6	2.50E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	4.00E-10	3.00E-10
Mean	2.80E-10	2.40E-10
Sigma	7.58E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA14
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.00E-10	3.00E-10
SN2	1.50E-10	1.50E-10	3.50E-10
SN3	1.50E-10	3.00E-10	2.00E-10
SN4	1.50E-10	1.50E-10	2.00E-10
SN5	3.00E-10	2.00E-10	2.00E-10
SN6	3.00E-10	2.00E-10	2.50E-10
Statistics			
Min	1.50E-10	1.50E-10	2.00E-10
Max	3.00E-10	3.00E-10	3.50E-10
Mean	2.10E-10	2.00E-10	2.40E-10
Sigma	8.22E-11	6.12E-11	6.52E-11

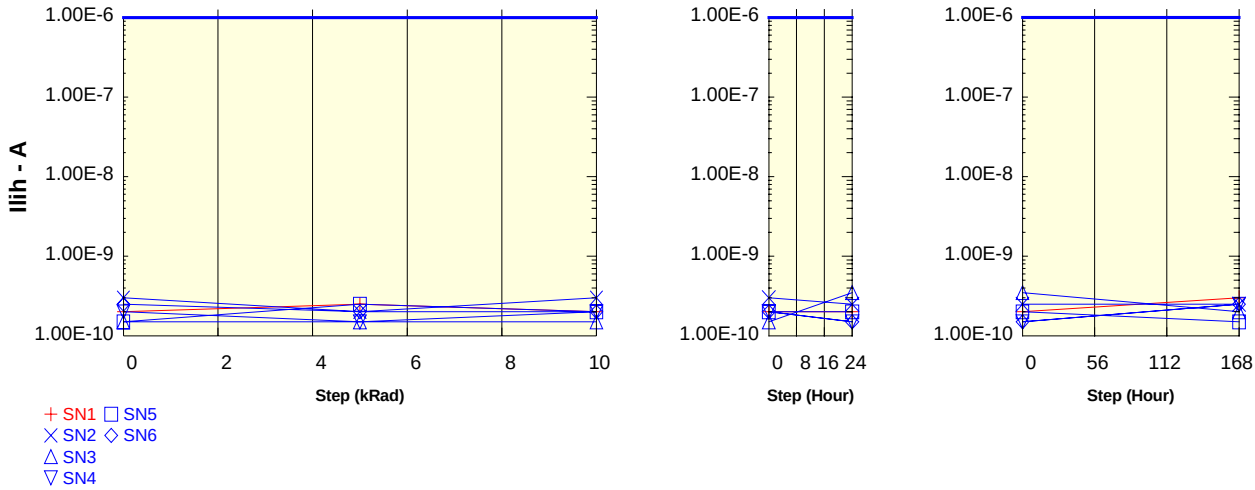
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	3.00E-10
SN2	3.50E-10	2.50E-10
SN3	2.00E-10	2.00E-10
SN4	2.00E-10	3.00E-10
SN5	2.00E-10	2.50E-10
SN6	2.50E-10	3.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	2.40E-10	2.60E-10
Sigma	6.52E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	3.50E-10
SN2	2.50E-10	3.00E-10
SN3	2.00E-10	2.50E-10
SN4	3.00E-10	2.00E-10
SN5	2.50E-10	2.00E-10
SN6	3.00E-10	1.50E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	3.00E-10	3.00E-10
Mean	2.60E-10	2.20E-10
Sigma	4.18E-11	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA13
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	2.50E-10	2.00E-10
SN2	3.00E-10	2.00E-10	3.00E-10
SN3	1.50E-10	1.50E-10	1.50E-10
SN4	2.00E-10	1.50E-10	2.00E-10
SN5	1.50E-10	2.50E-10	2.00E-10
SN6	2.50E-10	2.00E-10	2.00E-10
Statistics			
Min	1.50E-10	1.50E-10	1.50E-10
Max	3.00E-10	2.50E-10	3.00E-10
Mean	2.10E-10	1.90E-10	2.10E-10
Sigma	6.52E-11	4.18E-11	5.48E-11

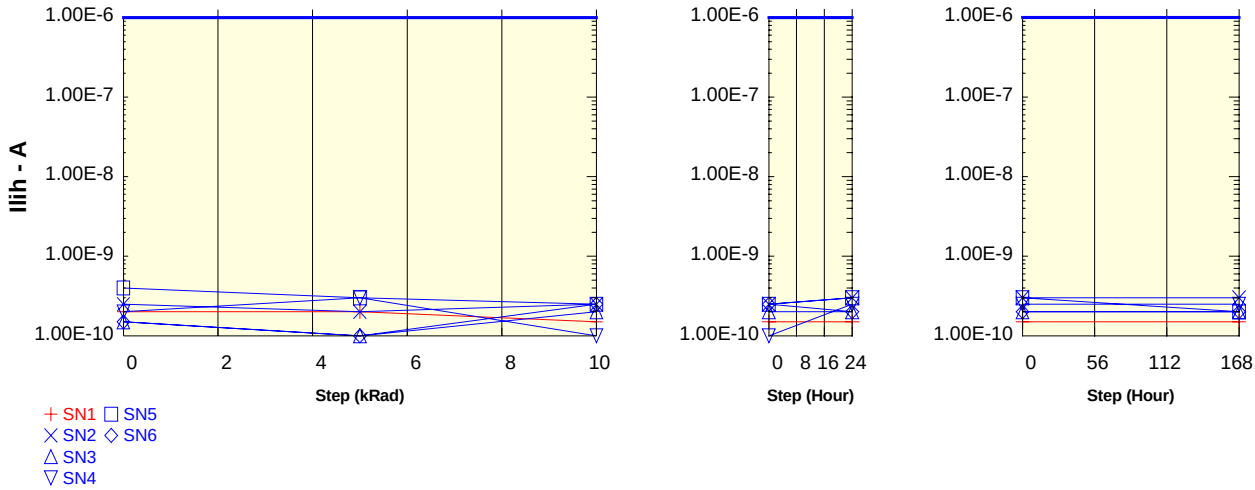
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	2.00E-10
SN2	3.00E-10	2.50E-10
SN3	1.50E-10	3.50E-10
SN4	2.00E-10	1.50E-10
SN5	2.00E-10	2.00E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.00E-10	3.50E-10
Mean	2.10E-10	2.20E-10
Sigma	5.48E-11	8.37E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	3.00E-10
SN2	2.50E-10	2.50E-10
SN3	3.50E-10	2.00E-10
SN4	1.50E-10	2.50E-10
SN5	2.00E-10	1.50E-10
SN6	1.50E-10	2.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.50E-10	2.50E-10
Mean	2.20E-10	2.20E-10
Sigma	8.37E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA12
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	2.00E-10	1.50E-10
SN2	2.50E-10	2.00E-10	2.50E-10
SN3	1.50E-10	1.00E-10	2.00E-10
SN4	2.00E-10	3.00E-10	1.00E-10
SN5	4.00E-10	3.00E-10	2.50E-10
SN6	1.50E-10	1.00E-10	2.50E-10
Statistics			
Min	1.50E-10	1.00E-10	1.00E-10
Max	4.00E-10	3.00E-10	2.50E-10
Mean	2.30E-10	2.00E-10	2.10E-10
Sigma	1.04E-10	1.00E-10	6.52E-11

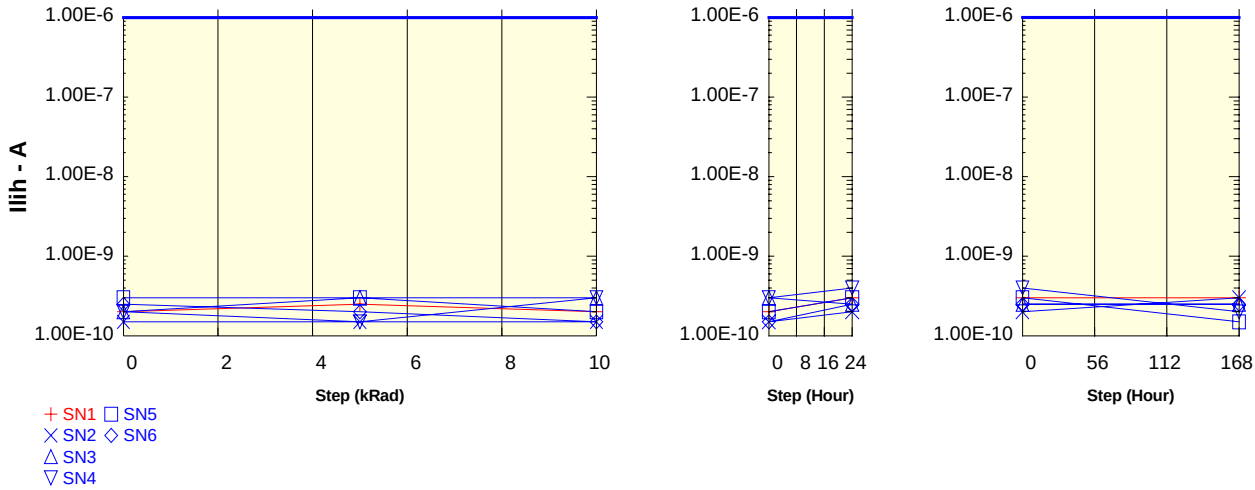
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	1.50E-10
SN2	2.50E-10	3.00E-10
SN3	2.00E-10	2.00E-10
SN4	1.00E-10	2.50E-10
SN5	2.50E-10	3.00E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	1.00E-10	2.00E-10
Max	2.50E-10	3.00E-10
Mean	2.10E-10	2.50E-10
Sigma	6.52E-11	5.00E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.50E-10	1.50E-10
SN2	3.00E-10	3.00E-10
SN3	2.00E-10	2.00E-10
SN4	2.50E-10	2.50E-10
SN5	3.00E-10	2.00E-10
SN6	2.00E-10	2.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.00E-10
Mean	2.50E-10	2.30E-10
Sigma	5.00E-11	4.47E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA11
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	2.50E-10	2.00E-10
SN2	1.50E-10	1.50E-10	1.50E-10
SN3	2.00E-10	3.00E-10	3.00E-10
SN4	2.00E-10	1.50E-10	3.00E-10
SN5	3.00E-10	3.00E-10	2.00E-10
SN6	2.50E-10	2.00E-10	1.50E-10
Statistics			
Min	1.50E-10	1.50E-10	1.50E-10
Max	3.00E-10	3.00E-10	3.00E-10
Mean	2.20E-10	2.20E-10	2.20E-10
Sigma	5.70E-11	7.58E-11	7.58E-11

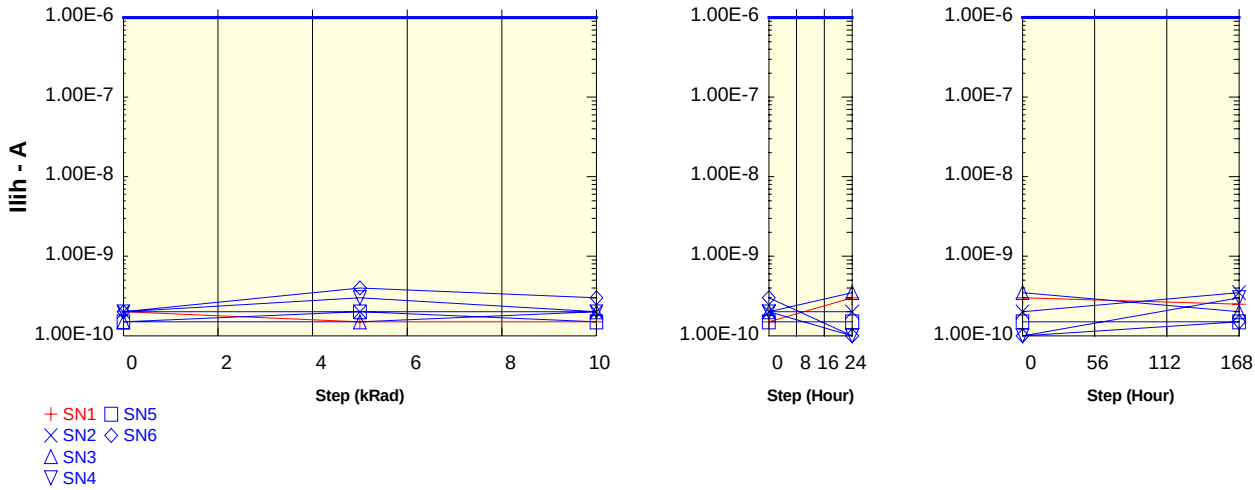
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	3.00E-10
SN2	1.50E-10	2.00E-10
SN3	3.00E-10	2.50E-10
SN4	3.00E-10	4.00E-10
SN5	2.00E-10	3.00E-10
SN6	1.50E-10	2.50E-10
Statistics		
Min	1.50E-10	2.00E-10
Max	3.00E-10	4.00E-10
Mean	2.20E-10	2.80E-10
Sigma	7.58E-11	7.58E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	3.00E-10
SN2	2.00E-10	3.00E-10
SN3	2.50E-10	2.50E-10
SN4	4.00E-10	2.00E-10
SN5	3.00E-10	1.50E-10
SN6	2.50E-10	2.50E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	4.00E-10	3.00E-10
Mean	2.80E-10	2.30E-10
Sigma	7.58E-11	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA10
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	1.50E-10	1.50E-10
SN2	2.00E-10	2.00E-10	2.00E-10
SN3	1.50E-10	1.50E-10	2.00E-10
SN4	2.00E-10	3.00E-10	2.00E-10
SN5	1.50E-10	2.00E-10	1.50E-10
SN6	2.00E-10	4.00E-10	3.00E-10
Statistics			
Min	1.50E-10	1.50E-10	1.50E-10
Max	2.00E-10	4.00E-10	3.00E-10
Mean	1.80E-10	2.50E-10	2.10E-10
Sigma	2.74E-11	1.00E-10	5.48E-11

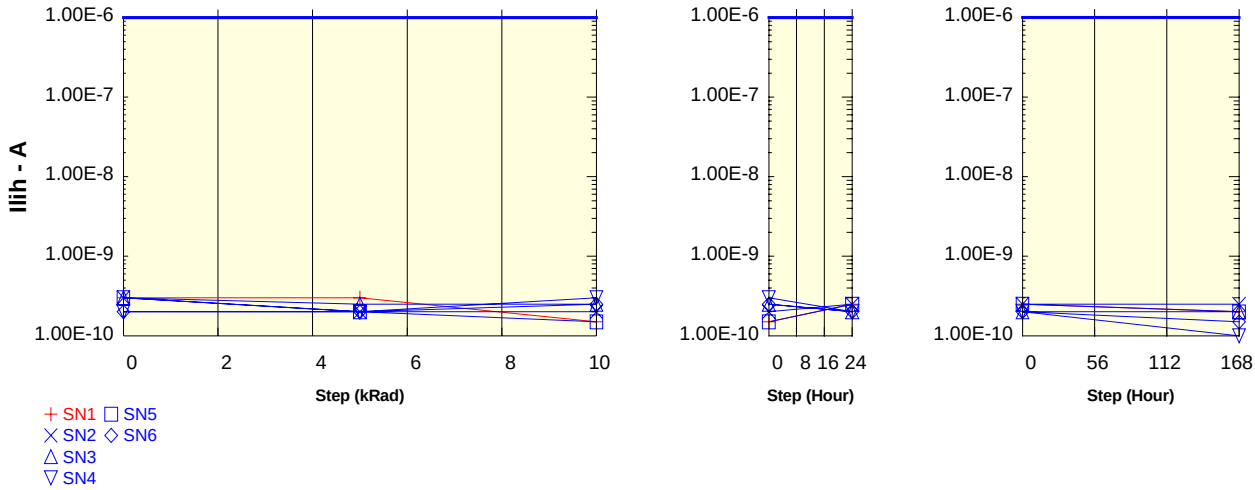
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	3.00E-10
SN2	2.00E-10	2.00E-10
SN3	2.00E-10	3.50E-10
SN4	2.00E-10	1.00E-10
SN5	1.50E-10	1.50E-10
SN6	3.00E-10	1.00E-10
Statistics		
Min	1.50E-10	1.00E-10
Max	3.00E-10	3.50E-10
Mean	2.10E-10	1.80E-10
Sigma	5.48E-11	1.04E-10

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	2.50E-10
SN2	2.00E-10	3.50E-10
SN3	3.50E-10	2.00E-10
SN4	1.00E-10	3.00E-10
SN5	1.50E-10	1.50E-10
SN6	1.00E-10	1.50E-10
Statistics		
Min	1.00E-10	1.50E-10
Max	3.50E-10	3.50E-10
Mean	1.80E-10	2.30E-10
Sigma	1.04E-10	9.08E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA9
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.00E-10	3.00E-10	1.50E-10
SN2	3.00E-10	2.00E-10	2.00E-10
SN3	3.00E-10	2.50E-10	2.50E-10
SN4	2.00E-10	2.00E-10	3.00E-10
SN5	3.00E-10	2.00E-10	1.50E-10
SN6	2.00E-10	2.00E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	1.50E-10
Max	3.00E-10	2.50E-10	3.00E-10
Mean	2.60E-10	2.10E-10	2.30E-10
Sigma	5.48E-11	2.24E-11	5.70E-11

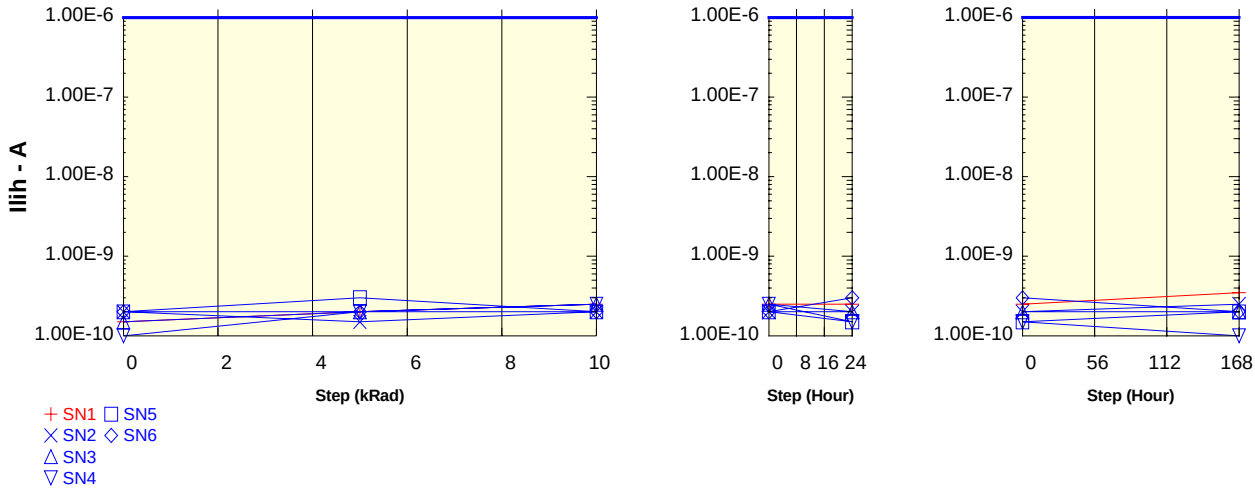
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	2.50E-10
SN2	2.00E-10	2.50E-10
SN3	2.50E-10	2.00E-10
SN4	3.00E-10	2.00E-10
SN5	1.50E-10	2.50E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	1.50E-10	2.00E-10
Max	3.00E-10	2.50E-10
Mean	2.30E-10	2.20E-10
Sigma	5.70E-11	2.74E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	2.00E-10
SN2	2.50E-10	2.50E-10
SN3	2.00E-10	2.00E-10
SN4	2.00E-10	1.00E-10
SN5	2.50E-10	2.00E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	2.00E-10	1.00E-10
Max	2.50E-10	2.50E-10
Mean	2.20E-10	1.80E-10
Sigma	2.74E-11	5.70E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA8
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	2.00E-10	2.50E-10
SN2	2.00E-10	1.50E-10	2.00E-10
SN3	1.50E-10	2.00E-10	2.50E-10
SN4	1.00E-10	2.00E-10	2.50E-10
SN5	2.00E-10	3.00E-10	2.00E-10
SN6	2.00E-10	2.00E-10	2.00E-10
Statistics			
Min	1.00E-10	1.50E-10	2.00E-10
Max	2.00E-10	3.00E-10	2.50E-10
Mean	1.70E-10	2.10E-10	2.20E-10
Sigma	4.47E-11	5.48E-11	2.74E-11

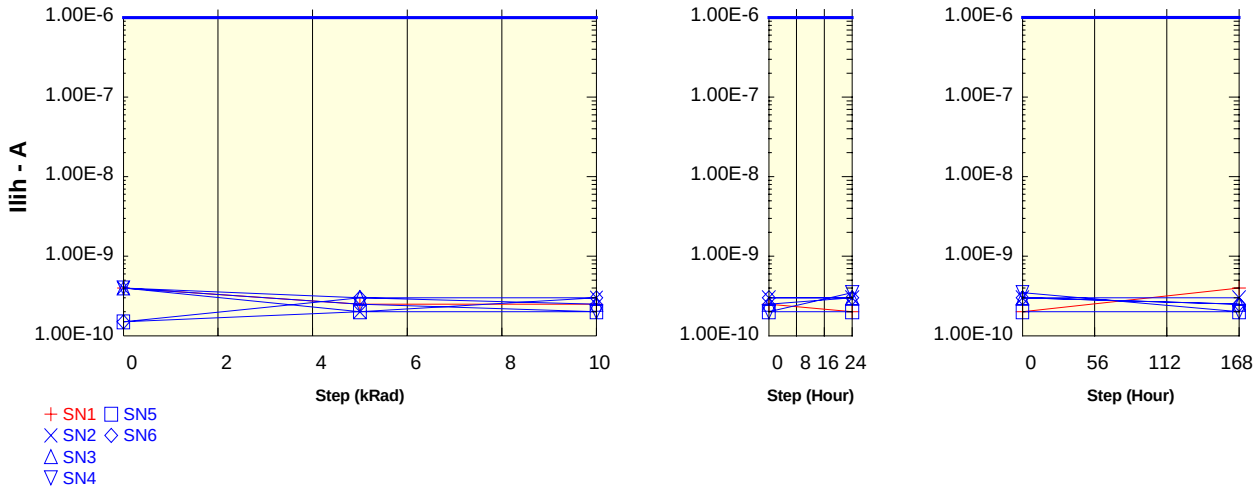
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.50E-10
SN2	2.00E-10	2.00E-10
SN3	2.50E-10	2.00E-10
SN4	2.50E-10	1.50E-10
SN5	2.00E-10	1.50E-10
SN6	2.00E-10	3.00E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	2.50E-10	3.00E-10
Mean	2.20E-10	2.00E-10
Sigma	2.74E-11	6.12E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.50E-10	3.50E-10
SN2	2.00E-10	2.50E-10
SN3	2.00E-10	2.00E-10
SN4	1.50E-10	1.00E-10
SN5	1.50E-10	2.00E-10
SN6	3.00E-10	2.00E-10
Statistics		
Min	1.50E-10	1.00E-10
Max	3.00E-10	2.50E-10
Mean	2.00E-10	1.90E-10
Sigma	6.12E-11	5.48E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA7
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	2.50E-10	2.50E-10
SN2	4.00E-10	2.00E-10	3.00E-10
SN3	4.00E-10	3.00E-10	2.50E-10
SN4	4.00E-10	2.50E-10	2.00E-10
SN5	1.50E-10	2.00E-10	2.00E-10
SN6	1.50E-10	3.00E-10	3.00E-10
Statistics			
Min	1.50E-10	2.00E-10	2.00E-10
Max	4.00E-10	3.00E-10	3.00E-10
Mean	3.00E-10	2.50E-10	2.50E-10
Sigma	1.37E-10	5.00E-11	5.00E-11

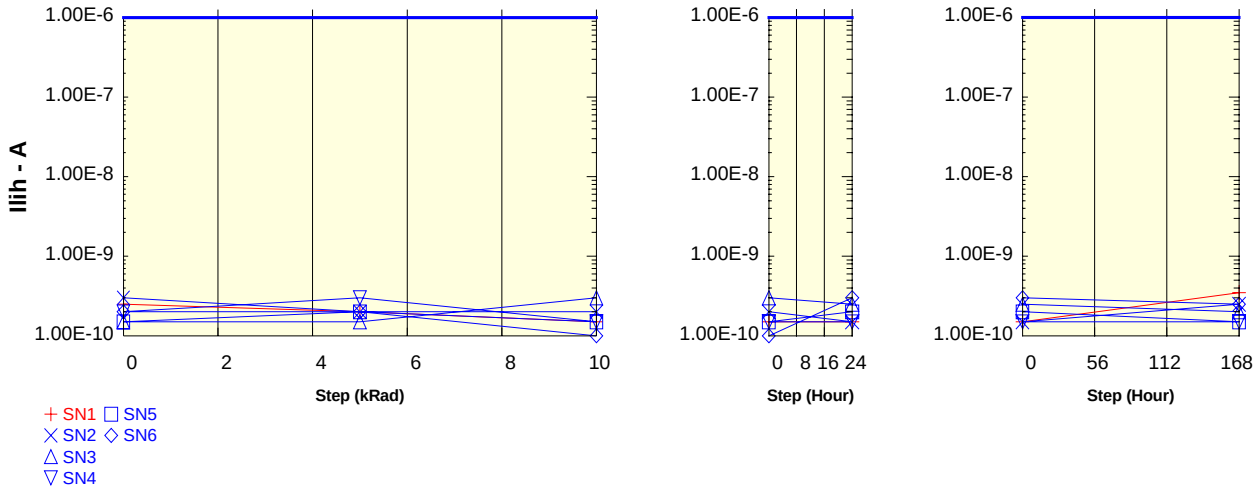
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.00E-10
SN2	3.00E-10	3.00E-10
SN3	2.50E-10	3.00E-10
SN4	2.00E-10	3.50E-10
SN5	2.00E-10	2.00E-10
SN6	3.00E-10	3.00E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.00E-10	3.50E-10
Mean	2.50E-10	2.90E-10
Sigma	5.00E-11	5.48E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	4.00E-10
SN2	3.00E-10	3.00E-10
SN3	3.00E-10	2.50E-10
SN4	3.50E-10	2.00E-10
SN5	2.00E-10	2.00E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	2.00E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	2.90E-10	2.40E-10
Sigma	5.48E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA6
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	2.00E-10	1.50E-10
SN2	3.00E-10	2.00E-10	2.00E-10
SN3	1.50E-10	1.50E-10	3.00E-10
SN4	2.00E-10	3.00E-10	1.50E-10
SN5	1.50E-10	2.00E-10	1.50E-10
SN6	2.00E-10	2.00E-10	1.00E-10
Statistics			
Min	1.50E-10	1.50E-10	1.00E-10
Max	3.00E-10	3.00E-10	3.00E-10
Mean	2.00E-10	2.10E-10	1.80E-10
Sigma	6.12E-11	5.48E-11	7.58E-11

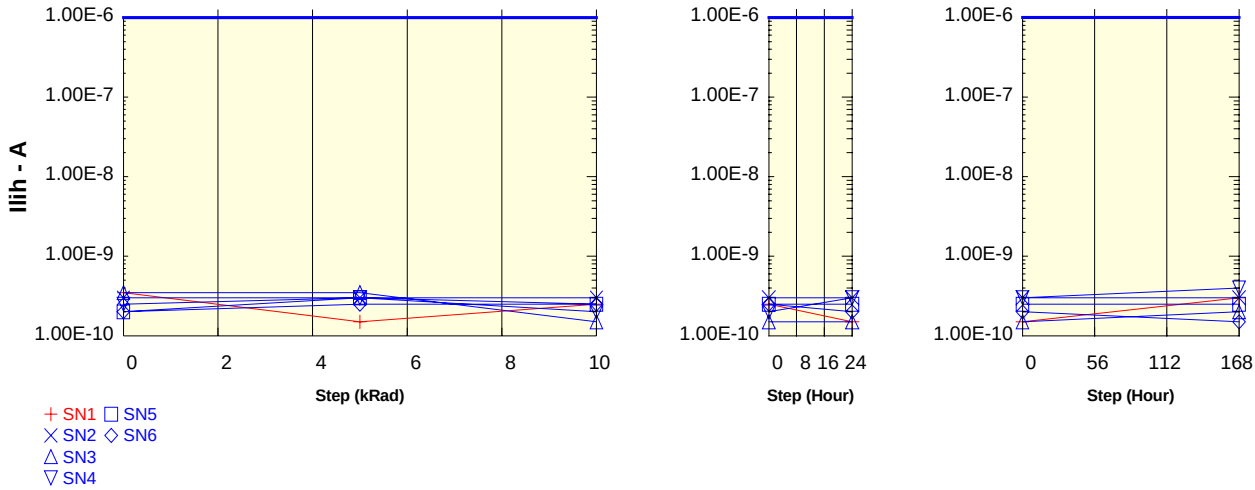
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	1.50E-10
SN2	2.00E-10	1.50E-10
SN3	3.00E-10	2.50E-10
SN4	1.50E-10	1.50E-10
SN5	1.50E-10	2.00E-10
SN6	1.00E-10	3.00E-10
Statistics		
Min	1.00E-10	1.50E-10
Max	3.00E-10	3.00E-10
Mean	1.80E-10	2.10E-10
Sigma	7.58E-11	6.52E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.50E-10	3.50E-10
SN2	1.50E-10	2.50E-10
SN3	2.50E-10	2.00E-10
SN4	1.50E-10	1.50E-10
SN5	2.00E-10	1.50E-10
SN6	3.00E-10	2.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.00E-10	2.50E-10
Mean	2.10E-10	2.00E-10
Sigma	6.52E-11	5.00E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA5
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.50E-10	1.50E-10	2.50E-10
SN2	3.00E-10	3.00E-10	3.00E-10
SN3	3.50E-10	3.50E-10	1.50E-10
SN4	2.50E-10	3.00E-10	2.00E-10
SN5	2.00E-10	3.00E-10	2.50E-10
SN6	2.00E-10	2.50E-10	2.50E-10
Statistics			
Min	2.00E-10	2.50E-10	1.50E-10
Max	3.50E-10	3.50E-10	3.00E-10
Mean	2.60E-10	3.00E-10	2.30E-10
Sigma	6.52E-11	3.54E-11	5.70E-11

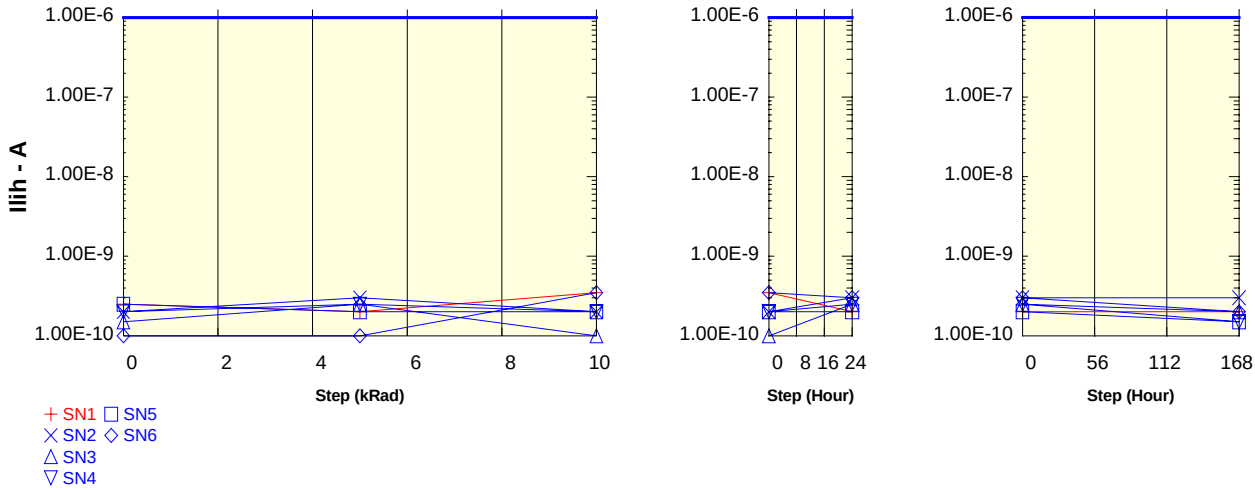
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	1.50E-10
SN2	3.00E-10	3.00E-10
SN3	1.50E-10	1.50E-10
SN4	2.00E-10	3.00E-10
SN5	2.50E-10	2.50E-10
SN6	2.50E-10	2.00E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.00E-10	3.00E-10
Mean	2.30E-10	2.40E-10
Sigma	5.70E-11	6.52E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.50E-10	3.00E-10
SN2	3.00E-10	3.00E-10
SN3	1.50E-10	2.00E-10
SN4	3.00E-10	4.00E-10
SN5	2.50E-10	2.50E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.00E-10	4.00E-10
Mean	2.40E-10	2.60E-10
Sigma	6.52E-11	9.62E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA4
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	2.00E-10	3.50E-10
SN2	2.00E-10	3.00E-10	2.00E-10
SN3	1.50E-10	2.50E-10	1.00E-10
SN4	2.00E-10	2.50E-10	2.00E-10
SN5	2.50E-10	2.00E-10	2.00E-10
SN6	1.00E-10	1.00E-10	3.50E-10
Statistics			
Min	1.00E-10	1.00E-10	1.00E-10
Max	2.50E-10	3.00E-10	3.50E-10
Mean	1.80E-10	2.20E-10	2.10E-10
Sigma	5.70E-11	7.58E-11	8.94E-11

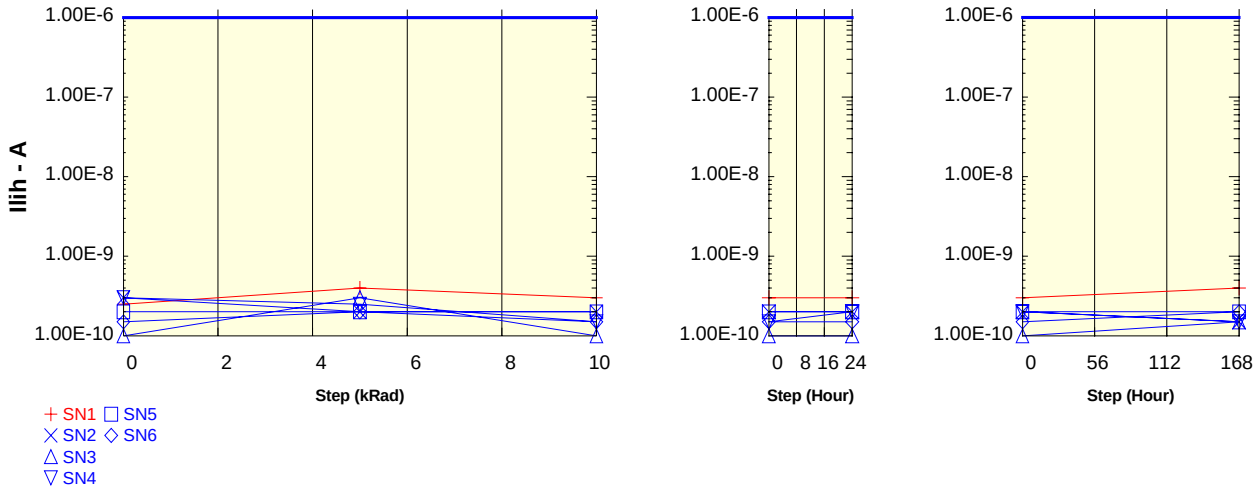
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.50E-10	2.00E-10
SN2	2.00E-10	3.00E-10
SN3	1.00E-10	2.50E-10
SN4	2.00E-10	2.50E-10
SN5	2.00E-10	2.00E-10
SN6	3.50E-10	3.00E-10
Statistics		
Min	1.00E-10	2.00E-10
Max	3.50E-10	3.00E-10
Mean	2.10E-10	2.60E-10
Sigma	8.94E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.00E-10
SN2	3.00E-10	3.00E-10
SN3	2.50E-10	2.00E-10
SN4	2.50E-10	1.50E-10
SN5	2.00E-10	1.50E-10
SN6	3.00E-10	2.00E-10
Statistics		
Min	2.00E-10	1.50E-10
Max	3.00E-10	3.00E-10
Mean	2.60E-10	2.00E-10
Sigma	4.18E-11	6.12E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA3
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	4.00E-10	3.00E-10
SN2	3.00E-10	2.00E-10	2.00E-10
SN3	1.00E-10	3.00E-10	1.00E-10
SN4	3.00E-10	2.50E-10	1.50E-10
SN5	2.00E-10	2.00E-10	2.00E-10
SN6	1.50E-10	2.00E-10	1.50E-10
Statistics			
Min	1.00E-10	2.00E-10	1.00E-10
Max	3.00E-10	3.00E-10	2.00E-10
Mean	2.10E-10	2.30E-10	1.60E-10
Sigma	8.94E-11	4.47E-11	4.18E-11

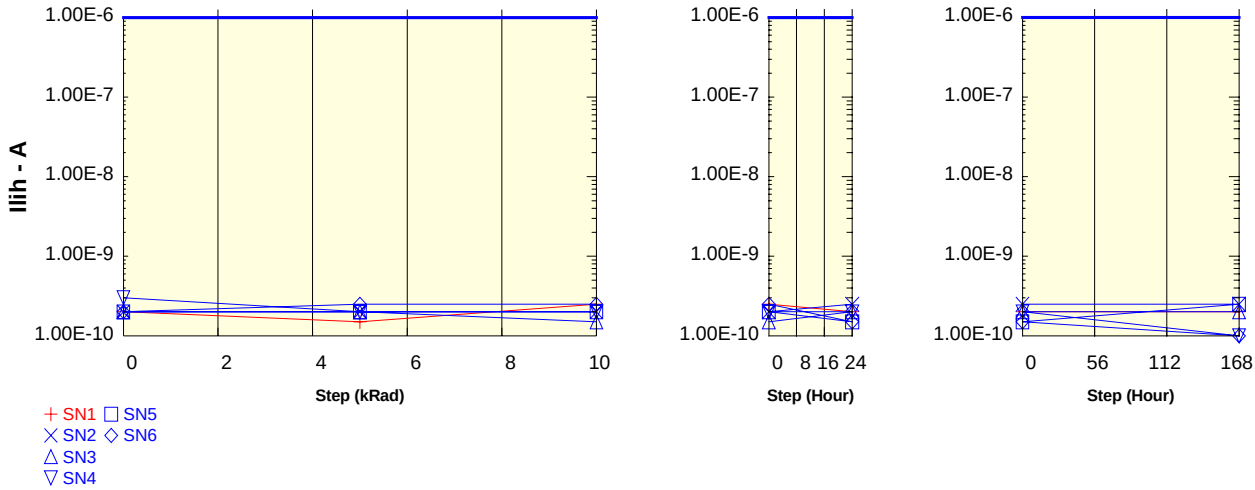
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.00E-10	3.00E-10
SN2	2.00E-10	2.00E-10
SN3	1.00E-10	1.00E-10
SN4	1.50E-10	2.00E-10
SN5	2.00E-10	2.00E-10
SN6	1.50E-10	1.50E-10
Statistics		
Min	1.00E-10	1.00E-10
Max	2.00E-10	2.00E-10
Mean	1.60E-10	1.70E-10
Sigma	4.18E-11	4.47E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.00E-10	4.00E-10
SN2	2.00E-10	1.50E-10
SN3	1.00E-10	1.50E-10
SN4	2.00E-10	1.50E-10
SN5	2.00E-10	2.00E-10
SN6	1.50E-10	2.00E-10
Statistics		
Min	1.00E-10	1.50E-10
Max	2.00E-10	2.00E-10
Mean	1.70E-10	1.70E-10
Sigma	4.47E-11	2.74E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA2
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.00E-10	1.50E-10	2.50E-10
SN2	2.00E-10	2.00E-10	2.00E-10
SN3	2.00E-10	2.00E-10	1.50E-10
SN4	3.00E-10	2.00E-10	2.00E-10
SN5	2.00E-10	2.00E-10	2.00E-10
SN6	2.00E-10	2.50E-10	2.50E-10
Statistics			
Min	2.00E-10	2.00E-10	1.50E-10
Max	3.00E-10	2.50E-10	2.50E-10
Mean	2.20E-10	2.10E-10	2.00E-10
Sigma	4.47E-11	2.24E-11	3.54E-11

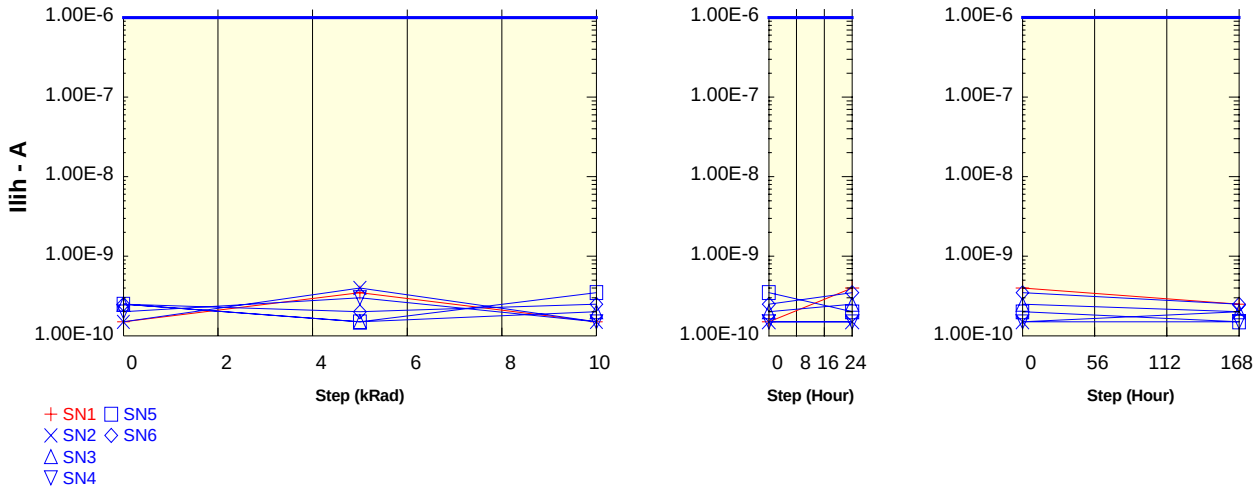
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.50E-10	2.00E-10
SN2	2.00E-10	2.50E-10
SN3	1.50E-10	2.00E-10
SN4	2.00E-10	2.00E-10
SN5	2.00E-10	1.50E-10
SN6	2.50E-10	1.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	2.50E-10	2.50E-10
Mean	2.00E-10	1.90E-10
Sigma	3.54E-11	4.18E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.00E-10
SN2	2.50E-10	2.50E-10
SN3	2.00E-10	2.00E-10
SN4	2.00E-10	1.00E-10
SN5	1.50E-10	2.50E-10
SN6	1.50E-10	1.00E-10
Statistics		
Min	1.50E-10	1.00E-10
Max	2.50E-10	2.50E-10
Mean	1.90E-10	1.80E-10
Sigma	4.18E-11	7.58E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA1
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	3.50E-10	1.50E-10
SN2	1.50E-10	4.00E-10	1.50E-10
SN3	2.50E-10	1.50E-10	2.00E-10
SN4	2.00E-10	3.00E-10	1.50E-10
SN5	2.50E-10	1.50E-10	3.50E-10
SN6	2.50E-10	2.00E-10	2.50E-10
Statistics			
Min	1.50E-10	1.50E-10	1.50E-10
Max	2.50E-10	4.00E-10	3.50E-10
Mean	2.20E-10	2.40E-10	2.20E-10
Sigma	4.47E-11	1.08E-10	8.37E-11

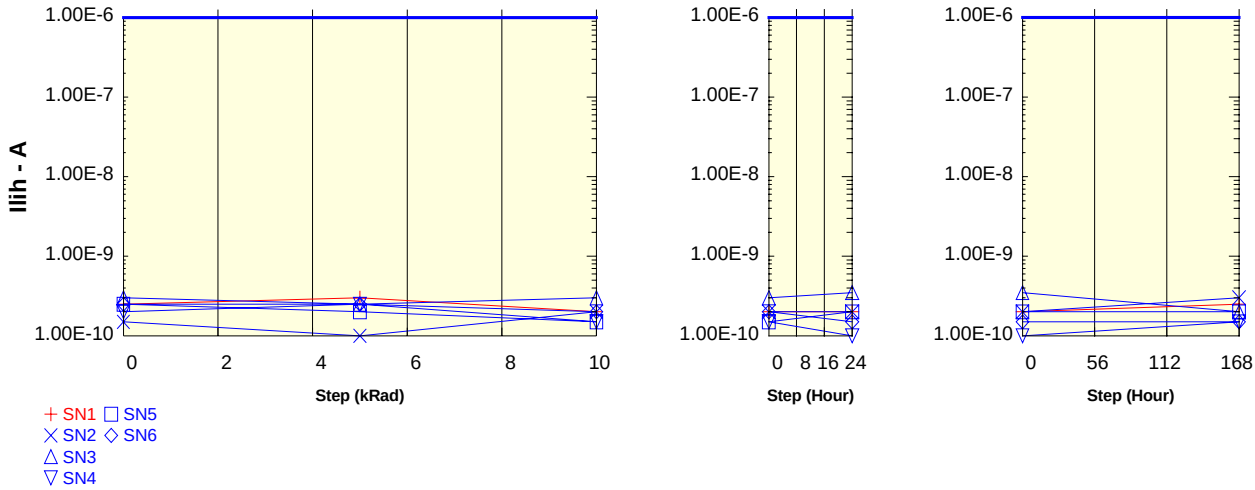
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.50E-10	4.00E-10
SN2	1.50E-10	1.50E-10
SN3	2.00E-10	2.50E-10
SN4	1.50E-10	1.50E-10
SN5	3.50E-10	2.00E-10
SN6	2.50E-10	3.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.50E-10	3.50E-10
Mean	2.20E-10	2.20E-10
Sigma	8.37E-11	8.37E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.00E-10	2.50E-10
SN2	1.50E-10	2.00E-10
SN3	2.50E-10	2.00E-10
SN4	1.50E-10	1.50E-10
SN5	2.00E-10	1.50E-10
SN6	3.50E-10	2.50E-10
Statistics		
Min	1.50E-10	1.50E-10
Max	3.50E-10	2.50E-10
Mean	2.20E-10	1.90E-10
Sigma	8.37E-11	4.18E-11

Test conditions : TID
Parameter : Input Leakage Current High : IihA0
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.50E-10	3.00E-10	2.00E-10
SN2	1.50E-10	1.00E-10	2.00E-10
SN3	3.00E-10	2.50E-10	3.00E-10
SN4	2.00E-10	2.50E-10	1.50E-10
SN5	2.50E-10	2.00E-10	1.50E-10
SN6	2.50E-10	2.50E-10	2.00E-10
Statistics			
Min	1.50E-10	1.00E-10	1.50E-10
Max	3.00E-10	2.50E-10	3.00E-10
Mean	2.30E-10	2.10E-10	2.00E-10
Sigma	5.70E-11	6.52E-11	6.12E-11

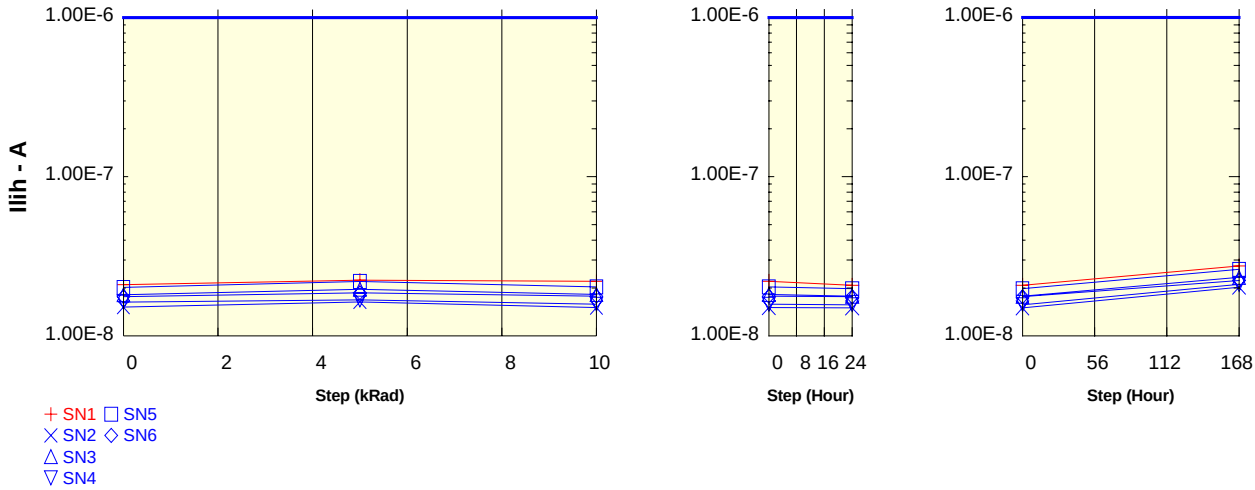
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.00E-10	2.00E-10
SN2	2.00E-10	2.00E-10
SN3	3.00E-10	3.50E-10
SN4	1.50E-10	1.00E-10
SN5	1.50E-10	2.00E-10
SN6	2.00E-10	1.50E-10
Statistics		
Min	1.50E-10	1.00E-10
Max	3.00E-10	3.50E-10
Mean	2.00E-10	2.00E-10
Sigma	6.12E-11	9.35E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.00E-10	2.50E-10
SN2	2.00E-10	3.00E-10
SN3	3.50E-10	2.00E-10
SN4	1.00E-10	1.50E-10
SN5	2.00E-10	2.00E-10
SN6	1.50E-10	1.50E-10
Statistics		
Min	1.00E-10	1.50E-10
Max	3.50E-10	3.00E-10
Mean	2.00E-10	2.00E-10
Sigma	9.35E-11	6.12E-11

Test conditions : TID
Parameter : Input Leakage Current High : Iih/RST
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	2.10E-8	2.24E-8	2.20E-8
SN2	1.52E-8	1.64E-8	1.51E-8
SN3	1.82E-8	1.96E-8	1.82E-8
SN4	1.63E-8	1.68E-8	1.58E-8
SN5	2.02E-8	2.20E-8	2.03E-8
SN6	1.76E-8	1.87E-8	1.77E-8
Statistics			
Min	1.52E-8	1.64E-8	1.51E-8
Max	2.02E-8	2.20E-8	2.03E-8
Mean	1.75E-8	1.87E-8	1.74E-8
Sigma	1.90E-9	2.26E-9	2.07E-9

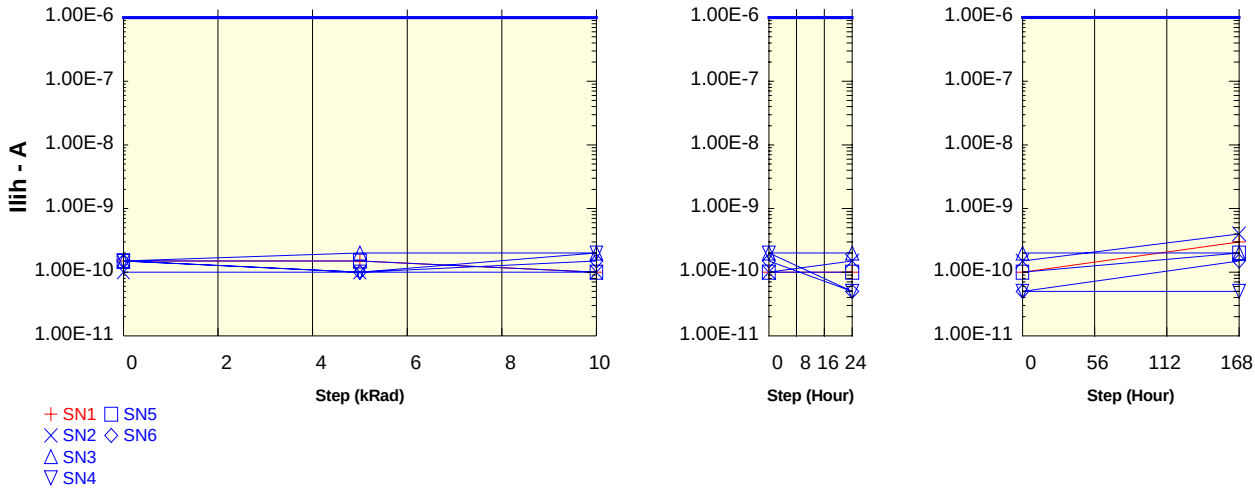
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.20E-8	2.08E-8
SN2	1.51E-8	1.50E-8
SN3	1.82E-8	1.78E-8
SN4	1.58E-8	1.57E-8
SN5	2.03E-8	1.98E-8
SN6	1.77E-8	1.76E-8
Statistics		
Min	1.51E-8	1.50E-8
Max	2.03E-8	1.98E-8
Mean	1.74E-8	1.72E-8
Sigma	2.07E-9	1.89E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.08E-8	2.75E-8
SN2	1.50E-8	2.02E-8
SN3	1.78E-8	2.33E-8
SN4	1.57E-8	2.11E-8
SN5	1.98E-8	2.62E-8
SN6	1.76E-8	2.23E-8
Statistics		
Min	1.50E-8	2.02E-8
Max	1.98E-8	2.62E-8
Mean	1.72E-8	2.26E-8
Sigma	1.89E-9	2.31E-9

Test conditions : TID
Parameter : Input Leakage Current High : Iih/CE
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.50E-10	1.50E-10	1.00E-10
SN2	1.00E-10	1.00E-10	1.00E-10
SN3	1.50E-10	2.00E-10	2.00E-10
SN4	1.50E-10	1.00E-10	2.00E-10
SN5	1.50E-10	1.50E-10	1.00E-10
SN6	1.50E-10	1.00E-10	1.50E-10
Statistics			
Min	1.00E-10	1.00E-10	1.00E-10
Max	1.50E-10	2.00E-10	2.00E-10
Mean	1.40E-10	1.30E-10	1.50E-10
Sigma	2.24E-11	4.47E-11	5.00E-11

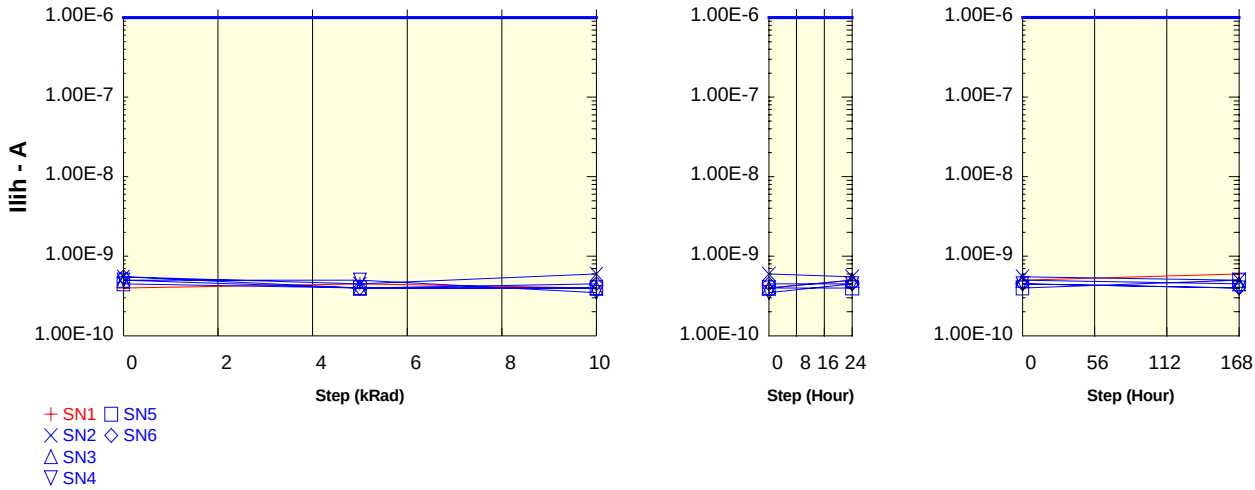
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.00E-10	1.00E-10
SN2	1.00E-10	1.50E-10
SN3	2.00E-10	2.00E-10
SN4	2.00E-10	5.00E-11
SN5	1.00E-10	1.00E-10
SN6	1.50E-10	5.00E-11
Statistics		
Min	1.00E-10	5.00E-11
Max	2.00E-10	2.00E-10
Mean	1.50E-10	1.10E-10
Sigma	5.00E-11	6.52E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.00E-10	3.00E-10
SN2	1.50E-10	4.00E-10
SN3	2.00E-10	2.00E-10
SN4	5.00E-11	5.00E-11
SN5	1.00E-10	2.00E-10
SN6	5.00E-11	1.50E-10
Statistics		
Min	5.00E-11	5.00E-11
Max	2.00E-10	4.00E-10
Mean	1.10E-10	2.00E-10
Sigma	6.52E-11	1.27E-10

Test conditions : TID
Parameter : Input Leakage Current High : Iih/OE
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.00E-10	4.50E-10	4.00E-10
SN2	5.50E-10	4.50E-10	6.00E-10
SN3	5.00E-10	4.00E-10	4.00E-10
SN4	5.00E-10	5.00E-10	3.50E-10
SN5	4.50E-10	4.00E-10	4.00E-10
SN6	5.50E-10	4.00E-10	4.50E-10
Statistics			
Min	4.50E-10	4.00E-10	3.50E-10
Max	5.50E-10	5.00E-10	6.00E-10
Mean	5.10E-10	4.30E-10	4.40E-10
Sigma	4.18E-11	4.47E-11	9.62E-11

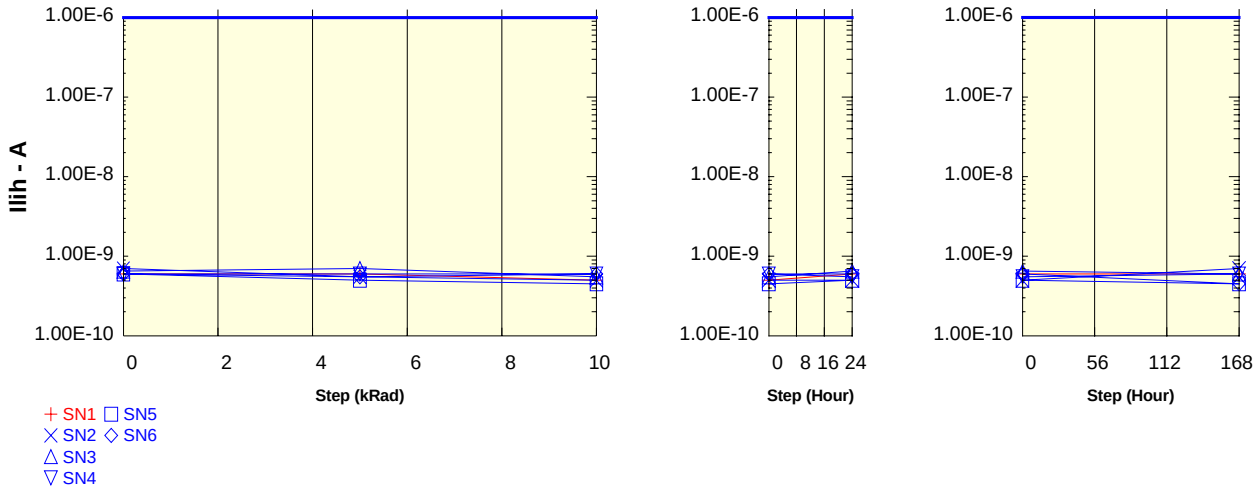
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.00E-10	5.00E-10
SN2	6.00E-10	5.50E-10
SN3	4.00E-10	5.00E-10
SN4	3.50E-10	4.50E-10
SN5	4.00E-10	4.00E-10
SN6	4.50E-10	4.50E-10
Statistics		
Min	3.50E-10	4.00E-10
Max	6.00E-10	5.50E-10
Mean	4.40E-10	4.70E-10
Sigma	9.62E-11	5.70E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	5.00E-10	6.00E-10
SN2	5.50E-10	5.00E-10
SN3	5.00E-10	4.50E-10
SN4	4.50E-10	4.00E-10
SN5	4.00E-10	5.00E-10
SN6	4.50E-10	4.00E-10
Statistics		
Min	4.00E-10	4.00E-10
Max	5.50E-10	5.00E-10
Mean	4.70E-10	4.50E-10
Sigma	5.70E-11	5.00E-11

Test conditions : TID
Parameter : Input Leakage Current High : Iih/WE
Vin = Vcc. Vcc = VccMax
Unit : A
Spec Limit Max : 1.00E-6
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	6.00E-10	6.00E-10	5.00E-10
SN2	7.00E-10	5.50E-10	5.00E-10
SN3	6.50E-10	7.00E-10	5.50E-10
SN4	6.00E-10	6.00E-10	6.00E-10
SN5	6.00E-10	5.00E-10	4.50E-10
SN6	6.00E-10	5.50E-10	6.00E-10
Statistics			
Min	6.00E-10	5.00E-10	4.50E-10
Max	7.00E-10	7.00E-10	6.00E-10
Mean	6.30E-10	5.80E-10	5.40E-10
Sigma	4.47E-11	7.58E-11	6.52E-11

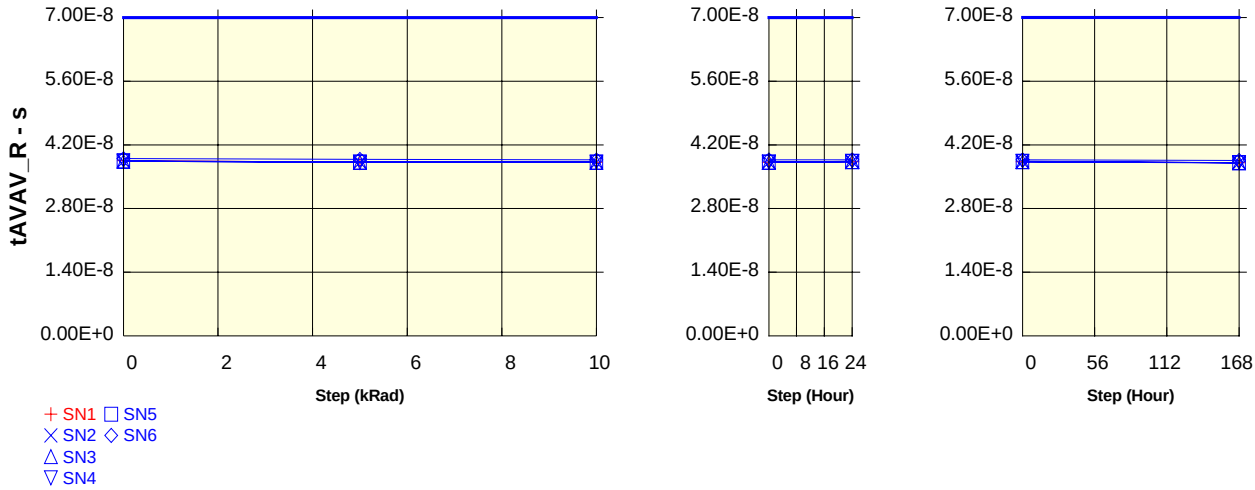
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	5.00E-10	6.00E-10
SN2	5.00E-10	5.00E-10
SN3	5.50E-10	6.50E-10
SN4	6.00E-10	5.50E-10
SN5	4.50E-10	5.00E-10
SN6	6.00E-10	6.00E-10
Statistics		
Min	4.50E-10	5.00E-10
Max	6.00E-10	6.50E-10
Mean	5.40E-10	5.60E-10
Sigma	6.52E-11	6.52E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	6.00E-10	6.00E-10
SN2	5.00E-10	7.00E-10
SN3	6.50E-10	6.00E-10
SN4	5.50E-10	6.00E-10
SN5	5.00E-10	4.50E-10
SN6	6.00E-10	4.50E-10
Statistics		
Min	5.00E-10	4.50E-10
Max	6.50E-10	7.00E-10
Mean	5.60E-10	5.60E-10
Sigma	6.52E-11	1.08E-10

Test conditions : TID
Parameter : Read Cycle Time : tAVAV_R
-
Unit : s
Spec Limit Max : 7.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	3.85E-8	3.82E-8	3.82E-8
SN2	3.84E-8	3.82E-8	3.82E-8
SN3	3.84E-8	3.82E-8	3.82E-8
SN4	3.85E-8	3.82E-8	3.82E-8
SN5	3.84E-8	3.82E-8	3.82E-8
SN6	3.90E-8	3.88E-8	3.87E-8
Statistics			
Min	3.84E-8	3.82E-8	3.82E-8
Max	3.90E-8	3.88E-8	3.87E-8
Mean	3.85E-8	3.83E-8	3.83E-8
Sigma	2.61E-10	2.68E-10	2.24E-10

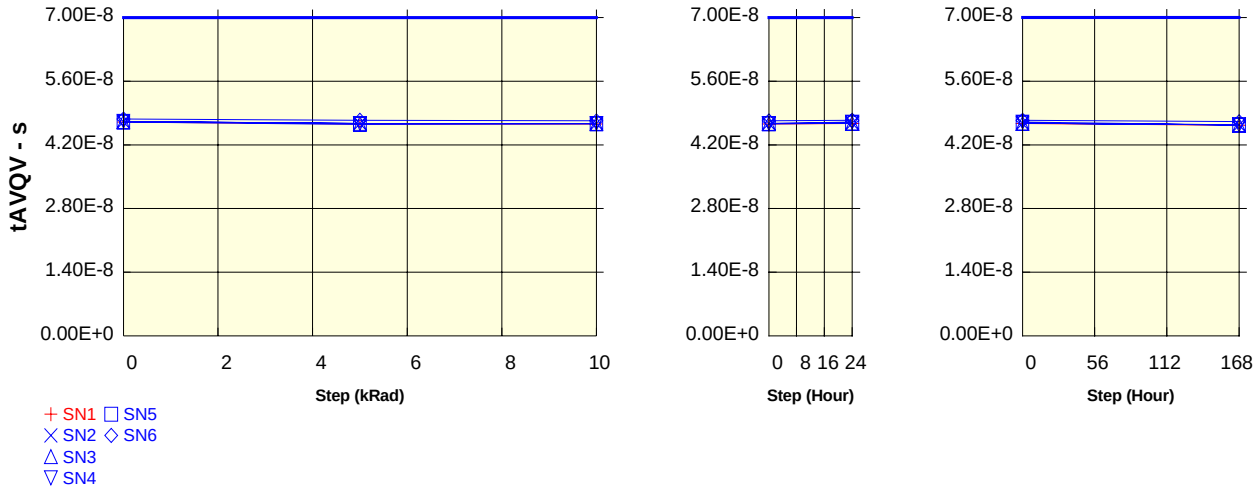
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	3.82E-8	3.83E-8
SN2	3.82E-8	3.83E-8
SN3	3.82E-8	3.83E-8
SN4	3.82E-8	3.84E-8
SN5	3.82E-8	3.83E-8
SN6	3.87E-8	3.87E-8
Statistics		
Min	3.82E-8	3.83E-8
Max	3.87E-8	3.87E-8
Mean	3.83E-8	3.84E-8
Sigma	2.24E-10	1.73E-10

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	3.83E-8	3.81E-8
SN2	3.83E-8	3.81E-8
SN3	3.83E-8	3.80E-8
SN4	3.84E-8	3.81E-8
SN5	3.83E-8	3.81E-8
SN6	3.87E-8	3.86E-8
Statistics		
Min	3.83E-8	3.80E-8
Max	3.87E-8	3.86E-8
Mean	3.84E-8	3.82E-8
Sigma	1.73E-10	2.39E-10

Test conditions : TID
Parameter : Address to Output Delay : tAVQV
CE* = VIL. OE* = VIL
Unit : s
Spec Limit Max : 7.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.70E-8	4.66E-8	4.66E-8
SN2	4.71E-8	4.67E-8	4.67E-8
SN3	4.71E-8	4.67E-8	4.67E-8
SN4	4.72E-8	4.67E-8	4.67E-8
SN5	4.70E-8	4.65E-8	4.66E-8
SN6	4.77E-8	4.74E-8	4.73E-8
Statistics			
Min	4.70E-8	4.65E-8	4.66E-8
Max	4.77E-8	4.74E-8	4.73E-8
Mean	4.72E-8	4.68E-8	4.68E-8
Sigma	2.77E-10	3.46E-10	2.83E-10

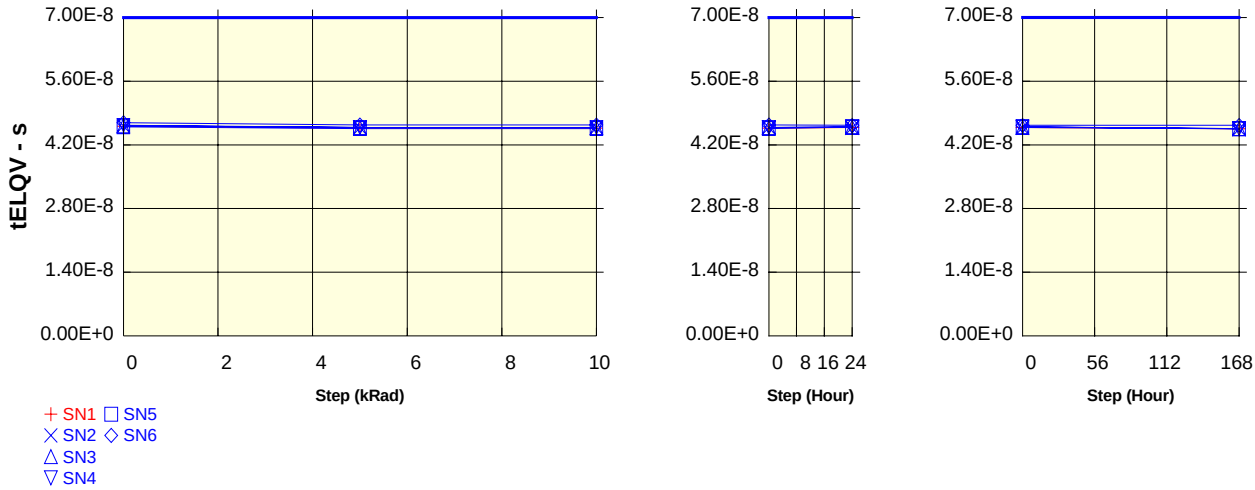
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.66E-8	4.67E-8
SN2	4.67E-8	4.68E-8
SN3	4.67E-8	4.68E-8
SN4	4.67E-8	4.70E-8
SN5	4.66E-8	4.68E-8
SN6	4.73E-8	4.74E-8
Statistics		
Min	4.66E-8	4.68E-8
Max	4.73E-8	4.74E-8
Mean	4.68E-8	4.70E-8
Sigma	2.83E-10	2.61E-10

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.67E-8	4.63E-8
SN2	4.68E-8	4.64E-8
SN3	4.68E-8	4.64E-8
SN4	4.70E-8	4.64E-8
SN5	4.68E-8	4.64E-8
SN6	4.74E-8	4.71E-8
Statistics		
Min	4.68E-8	4.64E-8
Max	4.74E-8	4.71E-8
Mean	4.70E-8	4.65E-8
Sigma	2.61E-10	3.13E-10

Test conditions : TID
Parameter : Chip Enable to Output Delay : tELQV
OE* = VIL
Unit : s
Spec Limit Max : 7.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	4.61E-8	4.57E-8	4.57E-8
SN2	4.62E-8	4.58E-8	4.58E-8
SN3	4.62E-8	4.58E-8	4.58E-8
SN4	4.63E-8	4.58E-8	4.58E-8
SN5	4.60E-8	4.56E-8	4.56E-8
SN6	4.69E-8	4.64E-8	4.64E-8
Statistics			
Min	4.60E-8	4.56E-8	4.56E-8
Max	4.69E-8	4.64E-8	4.64E-8
Mean	4.63E-8	4.59E-8	4.59E-8
Sigma	3.42E-10	3.03E-10	3.03E-10

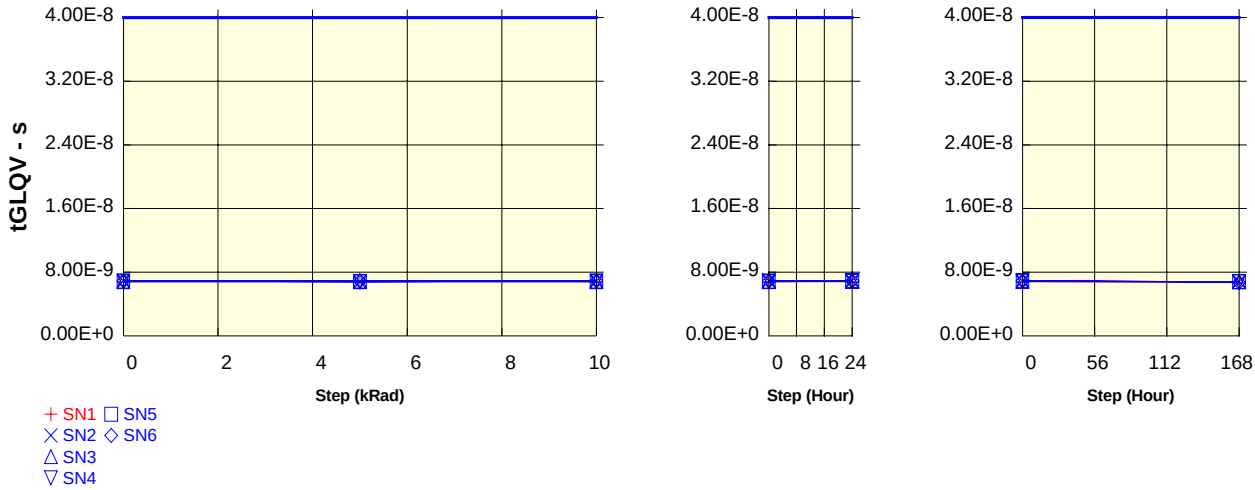
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	4.57E-8	4.58E-8
SN2	4.58E-8	4.58E-8
SN3	4.58E-8	4.59E-8
SN4	4.58E-8	4.60E-8
SN5	4.56E-8	4.59E-8
SN6	4.64E-8	4.63E-8
Statistics		
Min	4.56E-8	4.58E-8
Max	4.64E-8	4.63E-8
Mean	4.59E-8	4.60E-8
Sigma	3.03E-10	1.92E-10

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	4.58E-8	4.55E-8
SN2	4.58E-8	4.55E-8
SN3	4.59E-8	4.56E-8
SN4	4.60E-8	4.56E-8
SN5	4.59E-8	4.55E-8
SN6	4.63E-8	4.63E-8
Statistics		
Min	4.58E-8	4.55E-8
Max	4.63E-8	4.63E-8
Mean	4.60E-8	4.57E-8
Sigma	1.92E-10	3.39E-10

Test conditions : TID
Parameter : Output Enable to Output Delay : tGLQV
-
Unit : s
Spec Limit Max : 4.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	6.80E-9	6.80E-9	6.80E-9
SN2	6.90E-9	6.80E-9	6.90E-9
SN3	6.90E-9	6.90E-9	6.90E-9
SN4	6.90E-9	6.80E-9	6.90E-9
SN5	6.80E-9	6.80E-9	6.80E-9
SN6	6.90E-9	6.90E-9	6.90E-9
Statistics			
Min	6.80E-9	6.80E-9	6.80E-9
Max	6.90E-9	6.90E-9	6.90E-9
Mean	6.88E-9	6.84E-9	6.88E-9
Sigma	4.47E-11	5.48E-11	4.47E-11

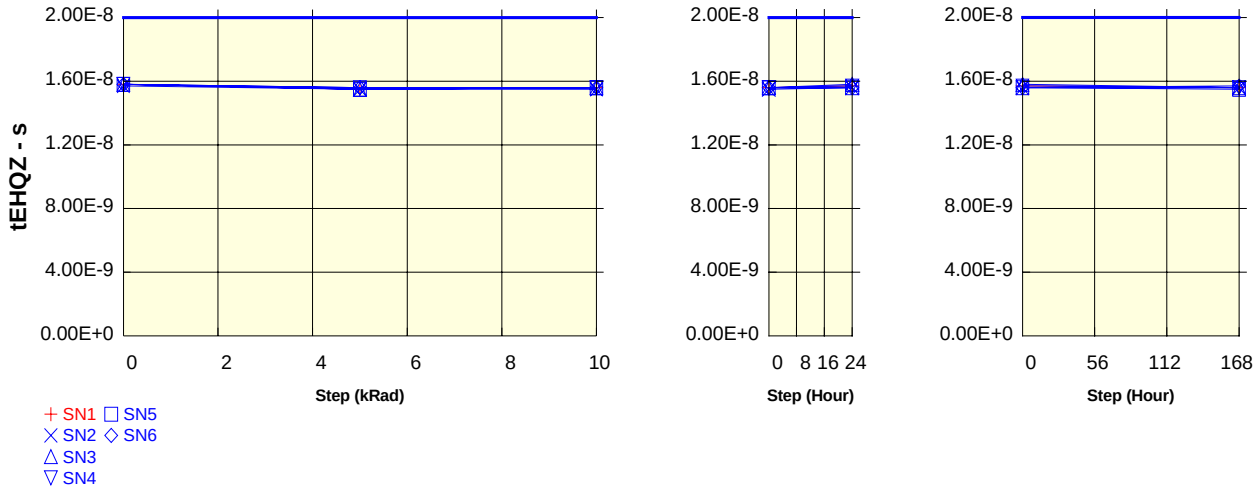
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	6.80E-9	6.80E-9
SN2	6.90E-9	6.90E-9
SN3	6.90E-9	6.90E-9
SN4	6.90E-9	6.90E-9
SN5	6.80E-9	6.90E-9
SN6	6.90E-9	6.90E-9
Statistics		
Min	6.80E-9	6.90E-9
Max	6.90E-9	6.90E-9
Mean	6.88E-9	6.90E-9
Sigma	4.47E-11	0.00E+0

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	6.80E-9	6.70E-9
SN2	6.90E-9	6.80E-9
SN3	6.90E-9	6.80E-9
SN4	6.90E-9	6.80E-9
SN5	6.90E-9	6.80E-9
SN6	6.90E-9	6.70E-9
Statistics		
Min	6.90E-9	6.70E-9
Max	6.90E-9	6.80E-9
Mean	6.90E-9	6.78E-9
Sigma	0.00E+0	4.47E-11

Test conditions : TID
Parameter : Chip Enable to Output HiZ : tEHQZ
-
Unit : s
Spec Limit Max : 2.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.58E-8	1.55E-8	1.56E-8
SN2	1.57E-8	1.55E-8	1.55E-8
SN3	1.58E-8	1.55E-8	1.56E-8
SN4	1.58E-8	1.56E-8	1.56E-8
SN5	1.58E-8	1.55E-8	1.56E-8
SN6	1.58E-8	1.56E-8	1.56E-8
Statistics			
Min	1.57E-8	1.55E-8	1.55E-8
Max	1.58E-8	1.56E-8	1.56E-8
Mean	1.58E-8	1.55E-8	1.56E-8
Sigma	4.47E-11	5.48E-11	4.47E-11

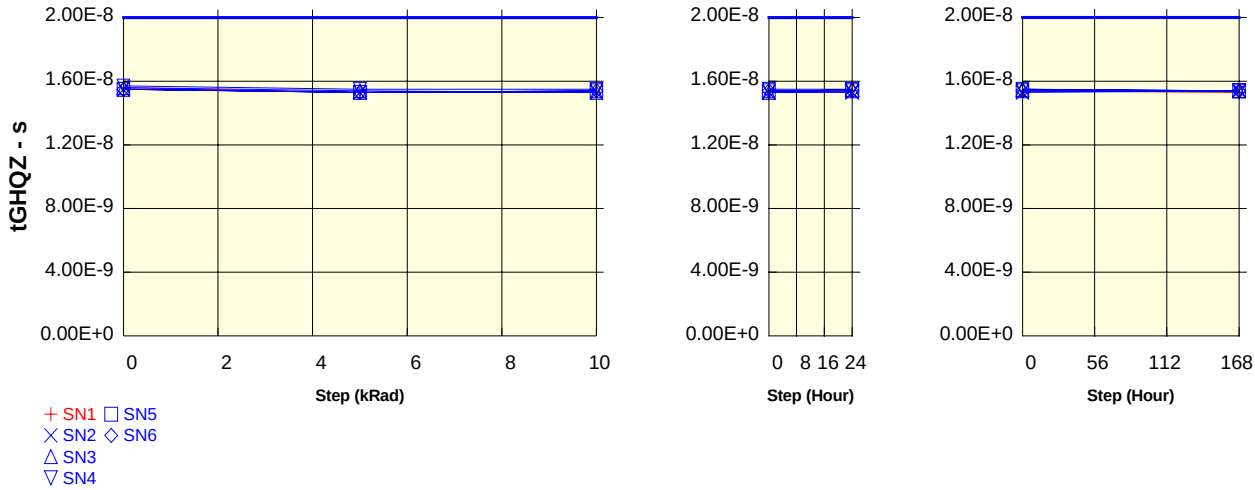
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.56E-8	1.57E-8
SN2	1.55E-8	1.56E-8
SN3	1.56E-8	1.58E-8
SN4	1.56E-8	1.57E-8
SN5	1.56E-8	1.56E-8
SN6	1.56E-8	1.56E-8
Statistics		
Min	1.55E-8	1.56E-8
Max	1.56E-8	1.58E-8
Mean	1.56E-8	1.57E-8
Sigma	4.47E-11	8.94E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.57E-8	1.56E-8
SN2	1.56E-8	1.56E-8
SN3	1.58E-8	1.56E-8
SN4	1.57E-8	1.56E-8
SN5	1.56E-8	1.55E-8
SN6	1.56E-8	1.57E-8
Statistics		
Min	1.56E-8	1.55E-8
Max	1.58E-8	1.57E-8
Mean	1.57E-8	1.56E-8
Sigma	8.94E-11	7.07E-11

Test conditions : TID
Parameter : Output Enable to Output HiZ : tGHQZ
-
Unit : s
Spec Limit Max : 2.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.56E-8	1.53E-8	1.53E-8
SN2	1.55E-8	1.53E-8	1.53E-8
SN3	1.56E-8	1.54E-8	1.53E-8
SN4	1.57E-8	1.55E-8	1.55E-8
SN5	1.55E-8	1.53E-8	1.54E-8
SN6	1.55E-8	1.53E-8	1.54E-8
Statistics			
Min	1.55E-8	1.53E-8	1.53E-8
Max	1.57E-8	1.55E-8	1.55E-8
Mean	1.56E-8	1.54E-8	1.54E-8
Sigma	8.94E-11	8.94E-11	8.37E-11

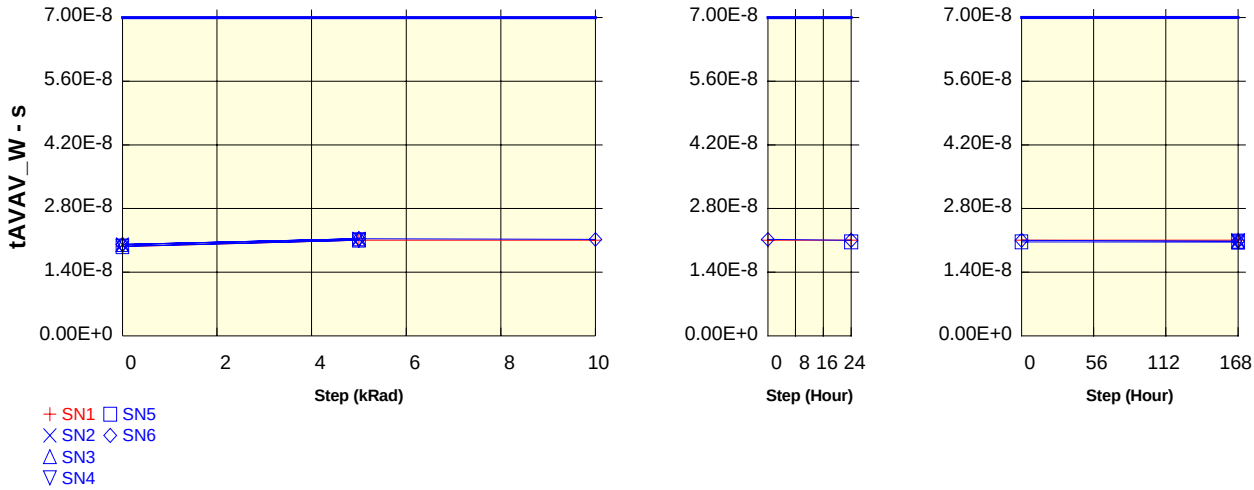
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.53E-8	1.54E-8
SN2	1.53E-8	1.53E-8
SN3	1.53E-8	1.55E-8
SN4	1.55E-8	1.55E-8
SN5	1.54E-8	1.54E-8
SN6	1.54E-8	1.54E-8
Statistics		
Min	1.53E-8	1.53E-8
Max	1.55E-8	1.55E-8
Mean	1.54E-8	1.54E-8
Sigma	8.37E-11	8.37E-11

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.54E-8	1.53E-8
SN2	1.53E-8	1.54E-8
SN3	1.55E-8	1.54E-8
SN4	1.55E-8	1.54E-8
SN5	1.54E-8	1.54E-8
SN6	1.54E-8	1.54E-8
Statistics		
Min	1.53E-8	1.54E-8
Max	1.55E-8	1.54E-8
Mean	1.54E-8	1.54E-8
Sigma	8.37E-11	0.00E+0

Test conditions : TID
Parameter : Write Cycle Time : tAVAV_W
-
Unit : s
Spec Limit Max : 7.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.97E-8	2.10E-8	2.10E-8
SN2	2.01E-8	2.13E-8	
SN3	2.01E-8	2.13E-8	
SN4	1.97E-8	2.10E-8	
SN5	1.97E-8	2.10E-8	
SN6	2.01E-8	2.13E-8	2.12E-8
Statistics			
Min	1.97E-8	2.10E-8	0.00E+0
Max	2.01E-8	2.13E-8	2.12E-8
Mean	1.99E-8	2.12E-8	4.24E-9
Sigma	2.30E-10	1.53E-10	9.48E-9

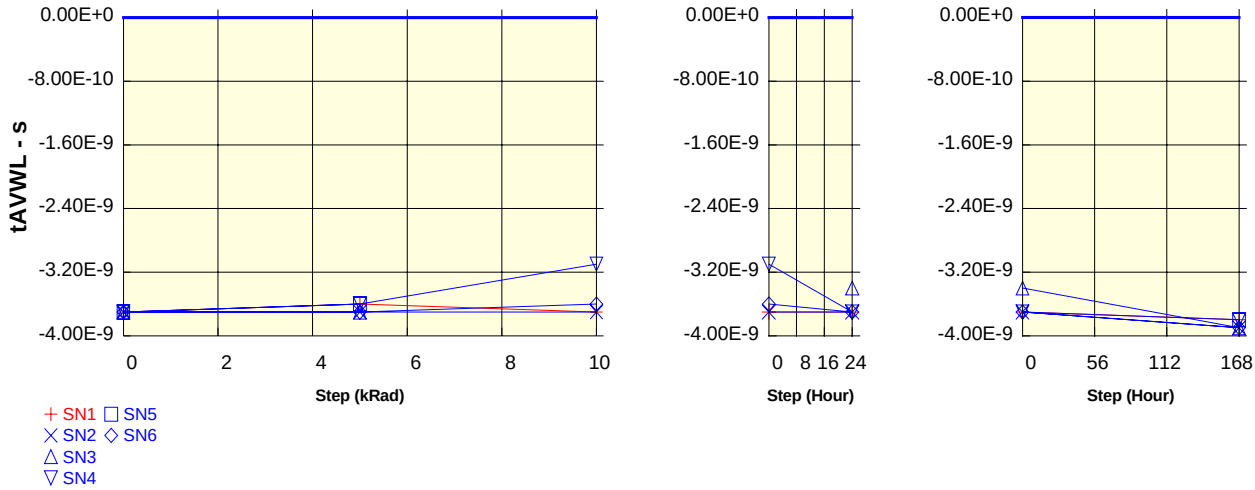
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	2.10E-8	2.10E-8
SN2		
SN3		
SN4		
SN5		2.07E-8
SN6	2.12E-8	2.10E-8
Statistics		
Min		0.00E+0
Max		2.10E-8
Mean		8.33E-9
Sigma		1.14E-8

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	2.10E-8	2.10E-8
SN2		2.09E-8
SN3		2.09E-8
SN4		2.09E-8
SN5	2.07E-8	2.06E-8
SN6	2.10E-8	2.09E-8
Statistics		
Min	2.07E-8	2.06E-8
Max	2.10E-8	2.09E-8
Mean	2.08E-8	2.08E-8
Sigma	2.33E-10	1.28E-10

Test conditions : TID
Parameter : Address Setup Time : tAVWL
-
Unit : s
Spec Limit Max : 0.00E+0
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	-3.70E-9	-3.60E-9	-3.70E-9
SN2	-3.70E-9	-3.70E-9	-3.70E-9
SN3	-3.70E-9	-3.70E-9	
SN4	-3.70E-9	-3.60E-9	-3.10E-9
SN5	-3.70E-9	-3.60E-9	
SN6	-3.70E-9	-3.70E-9	-3.60E-9
Statistics			
Min	-3.70E-9	-3.70E-9	-3.70E-9
Max	-3.70E-9	-3.60E-9	0.00E+0
Mean	-3.70E-9	-3.66E-9	-2.08E-9
Sigma	0.00E+0	5.48E-11	1.91E-9

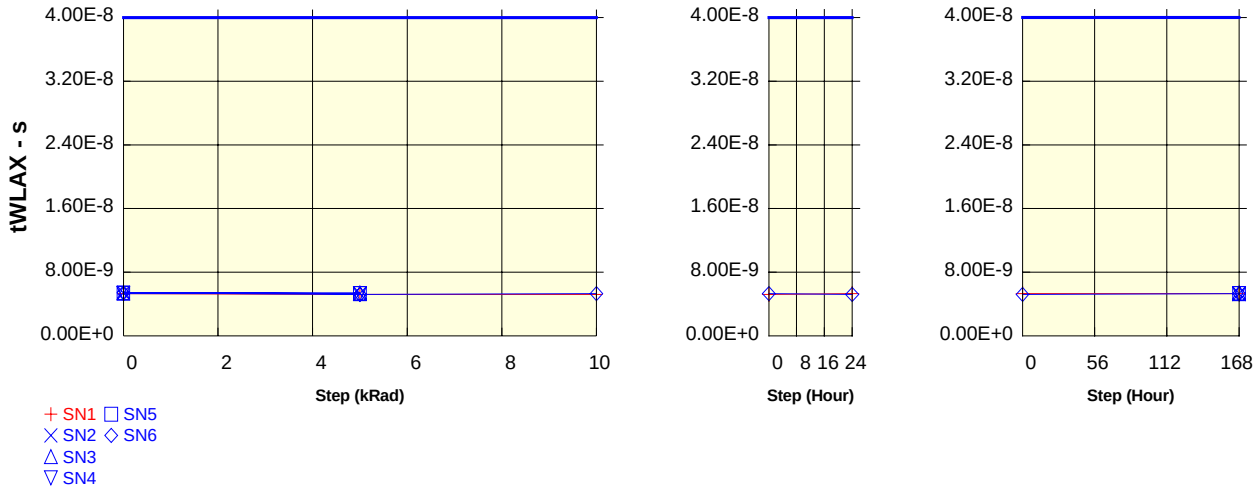
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	-3.70E-9	-3.70E-9
SN2	-3.70E-9	-3.70E-9
SN3		-3.40E-9
SN4	-3.10E-9	-3.70E-9
SN5		
SN6	-3.60E-9	-3.70E-9
Statistics		
Min	-3.70E-9	-3.70E-9
Max	-3.10E-9	0.00E+0
Mean	-3.47E-9	-2.90E-9
Sigma	3.21E-10	1.63E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	-3.70E-9	-3.80E-9
SN2	-3.70E-9	-3.90E-9
SN3	-3.40E-9	-3.90E-9
SN4	-3.70E-9	-3.80E-9
SN5		-3.80E-9
SN6	-3.70E-9	-3.90E-9
Statistics		
Min	-3.70E-9	-3.90E-9
Max	-3.40E-9	-3.80E-9
Mean	-3.63E-9	-3.86E-9
Sigma	1.50E-10	5.48E-11

Test conditions : TID
Parameter : Address Hold Time : tWLAX
-
Unit : s
Spec Limit Max : 4.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	5.30E-9	5.20E-9	5.20E-9
SN2	5.40E-9	5.30E-9	
SN3	5.40E-9	5.40E-9	
SN4	5.30E-9	5.30E-9	
SN5	5.40E-9	5.30E-9	
SN6	5.40E-9	5.20E-9	5.30E-9
Statistics			
Min	5.30E-9	5.20E-9	0.00E+0
Max	5.40E-9	5.40E-9	5.30E-9
Mean	5.38E-9	5.30E-9	1.06E-9
Sigma	4.47E-11	7.07E-11	2.37E-9

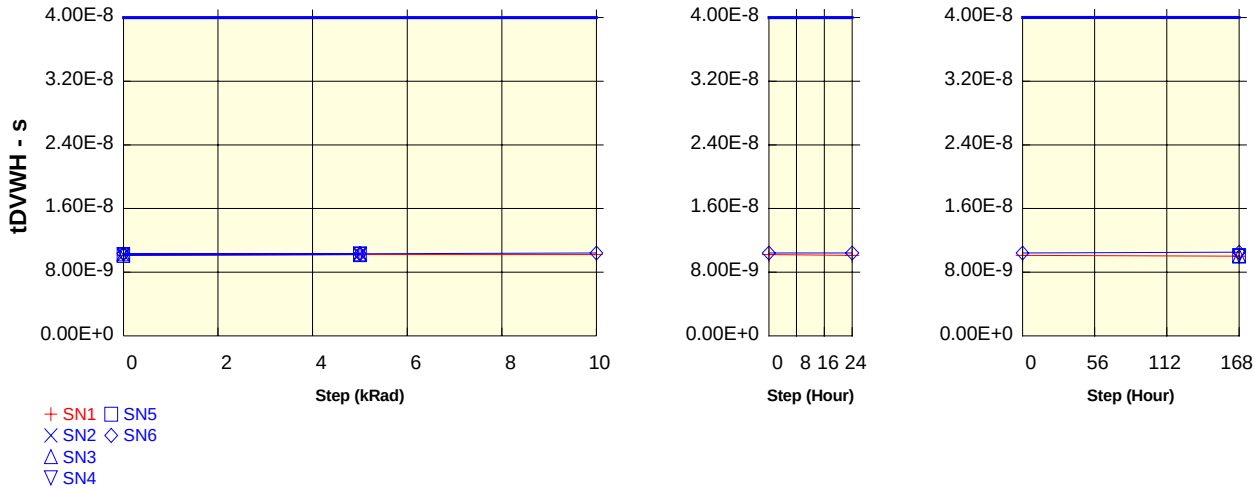
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	5.20E-9	5.30E-9
SN2		
SN3		
SN4		
SN5		
SN6	5.30E-9	5.20E-9
Statistics		
Min		0.00E+0
Max		5.20E-9
Mean		1.04E-9
Sigma		2.33E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	5.30E-9	5.30E-9
SN2		5.30E-9
SN3		5.40E-9
SN4		5.30E-9
SN5		5.30E-9
SN6	5.20E-9	5.30E-9
Statistics		
Min		5.30E-9
Max		5.40E-9
Mean		5.32E-9
Sigma		4.47E-11

Test conditions : TID
Parameter : Data Setup Time : tDVWH
-
Unit : s
Spec Limit Max : 4.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.01E-8	1.02E-8	1.02E-8
SN2	1.02E-8	1.03E-8	
SN3	1.03E-8	1.03E-8	
SN4	1.02E-8	1.03E-8	
SN5	1.01E-8	1.02E-8	
SN6	1.03E-8	1.03E-8	1.04E-8
Statistics			
Min	1.01E-8	1.02E-8	0.00E+0
Max	1.03E-8	1.03E-8	1.04E-8
Mean	1.02E-8	1.03E-8	2.08E-9
Sigma	8.37E-11	4.47E-11	4.65E-9

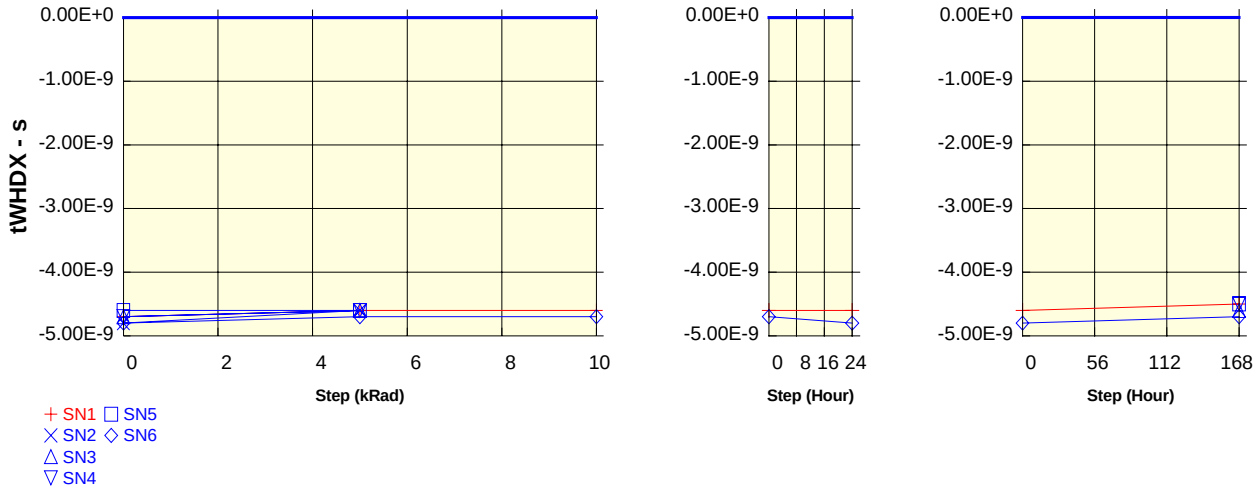
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.02E-8	1.01E-8
SN2		
SN3		
SN4		
SN5		
SN6	1.04E-8	1.04E-8
Statistics		
Min		0.00E+0
Max		1.04E-8
Mean		2.08E-9
Sigma		4.65E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.01E-8	1.00E-8
SN2		
SN3		1.01E-8
SN4		1.01E-8
SN5		1.00E-8
SN6	1.04E-8	1.05E-8
Statistics		
Min		0.00E+0
Max		1.05E-8
Mean		8.14E-9
Sigma		4.55E-9

Test conditions : TID
Parameter : Data Hold Time : tWHDX
-
Unit : s
Spec Limit Max : 0.00E+0
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	-4.70E-9	-4.60E-9	-4.60E-9
SN2	-4.80E-9	-4.60E-9	
SN3	-4.70E-9	-4.60E-9	
SN4	-4.70E-9	-4.60E-9	
SN5	-4.60E-9	-4.60E-9	
SN6	-4.80E-9	-4.70E-9	-4.70E-9
Statistics			
Min	-4.80E-9	-4.70E-9	-4.70E-9
Max	-4.60E-9	-4.60E-9	0.00E+0
Mean	-4.72E-9	-4.62E-9	-9.40E-10
Sigma	8.37E-11	4.47E-11	2.10E-9

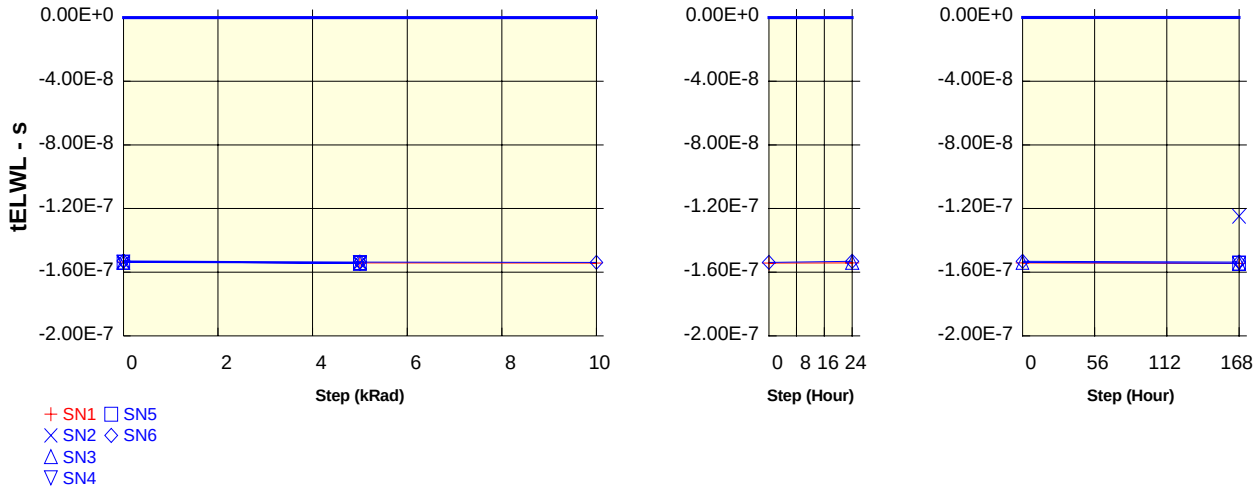
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	-4.60E-9	-4.60E-9
SN2		
SN3		
SN4		
SN5		
SN6	-4.70E-9	-4.80E-9
Statistics		
Min		-4.80E-9
Max		0.00E+0
Mean		-9.60E-10
Sigma		2.15E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	-4.60E-9	-4.50E-9
SN2		
SN3		-4.60E-9
SN4		-4.50E-9
SN5		-4.50E-9
SN6	-4.80E-9	-4.70E-9
Statistics		
Min		-4.70E-9
Max		0.00E+0
Mean		-3.66E-9
Sigma		2.05E-9

Test conditions : TID
Parameter : CE* Setup Time : tELWL
-
Unit : s
Spec Limit Max : 0.00E+0
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	-1.54E-7	-1.54E-7	-1.54E-7
SN2	-1.54E-7	-1.54E-7	
SN3	-1.54E-7	-1.54E-7	
SN4	-1.54E-7	-1.54E-7	
SN5	-1.54E-7	-1.54E-7	
SN6	-1.53E-7	-1.54E-7	-1.54E-7
Statistics			
Min	-1.54E-7	-1.54E-7	-1.54E-7
Max	-1.53E-7	-1.54E-7	0.00E+0
Mean	-1.54E-7	-1.54E-7	-3.08E-8
Sigma	3.46E-10	2.83E-10	6.88E-8

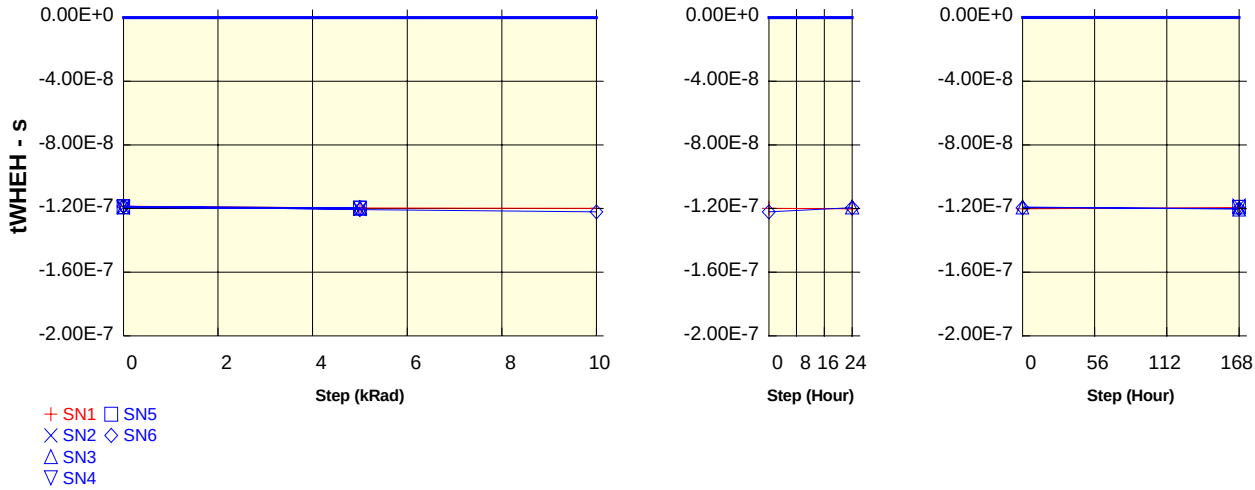
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	-1.54E-7	-1.54E-7
SN2		
SN3		-1.54E-7
SN4		
SN5		
SN6	-1.54E-7	-1.53E-7
Statistics		
Min		-1.54E-7
Max		0.00E+0
Mean		-6.14E-8
Sigma		8.41E-8

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	-1.54E-7	-1.54E-7
SN2		-1.25E-7
SN3	-1.54E-7	-1.54E-7
SN4		-1.54E-7
SN5		-1.55E-7
SN6	-1.53E-7	-1.54E-7
Statistics		
Min	-1.54E-7	-1.55E-7
Max	-1.53E-7	-1.25E-7
Mean	-1.54E-7	-1.48E-7
Sigma	4.95E-10	1.31E-8

Test conditions : TID
Parameter : CE* Hold Time : tWHEH
-
Unit : s
Spec Limit Max : 0.00E+0
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	-1.19E-7	-1.20E-7	-1.20E-7
SN2	-1.19E-7	-1.20E-7	
SN3	-1.19E-7	-1.20E-7	
SN4	-1.20E-7	-1.20E-7	
SN5	-1.19E-7	-1.20E-7	
SN6	-1.19E-7	-1.21E-7	-1.22E-7
Statistics			
Min	-1.20E-7	-1.21E-7	-1.22E-7
Max	-1.19E-7	-1.20E-7	0.00E+0
Mean	-1.19E-7	-1.20E-7	-2.44E-8
Sigma	3.67E-10	4.44E-10	5.46E-8

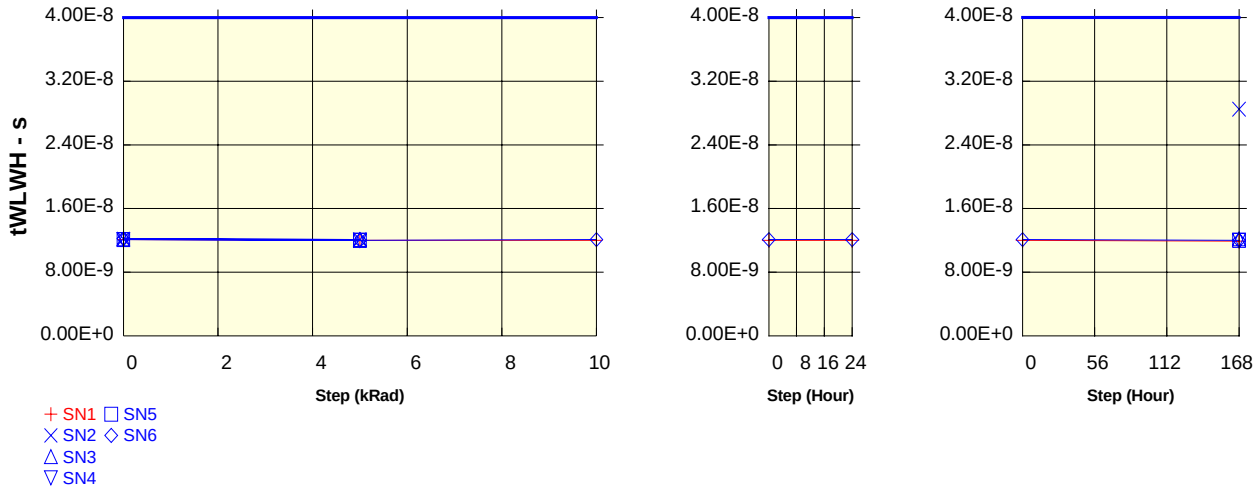
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	-1.20E-7	-1.20E-7
SN2		
SN3		-1.19E-7
SN4		
SN5		
SN6	-1.22E-7	-1.20E-7
Statistics		
Min		-1.20E-7
Max		0.00E+0
Mean		-4.77E-8
Sigma		6.53E-8

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	-1.20E-7	-1.19E-7
SN2		-1.18E-7
SN3	-1.19E-7	-1.20E-7
SN4		-1.19E-7
SN5		-1.19E-7
SN6	-1.20E-7	-1.20E-7
Statistics		
Min	-1.20E-7	-1.20E-7
Max	-1.19E-7	-1.18E-7
Mean	-1.19E-7	-1.19E-7
Sigma	3.54E-10	7.83E-10

Test conditions : TID
Parameter : Write Pulse Width : tWLWH
-
Unit : s
Spec Limit Max : 4.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	1.21E-8	1.20E-8	1.20E-8
SN2	1.22E-8	1.21E-8	
SN3	1.22E-8	1.21E-8	
SN4	1.21E-8	1.20E-8	
SN5	1.21E-8	1.20E-8	
SN6	1.22E-8	1.20E-8	1.21E-8
Statistics			
Min	1.21E-8	1.20E-8	0.00E+0
Max	1.22E-8	1.21E-8	1.21E-8
Mean	1.22E-8	1.20E-8	2.42E-9
Sigma	5.48E-11	5.48E-11	5.41E-9

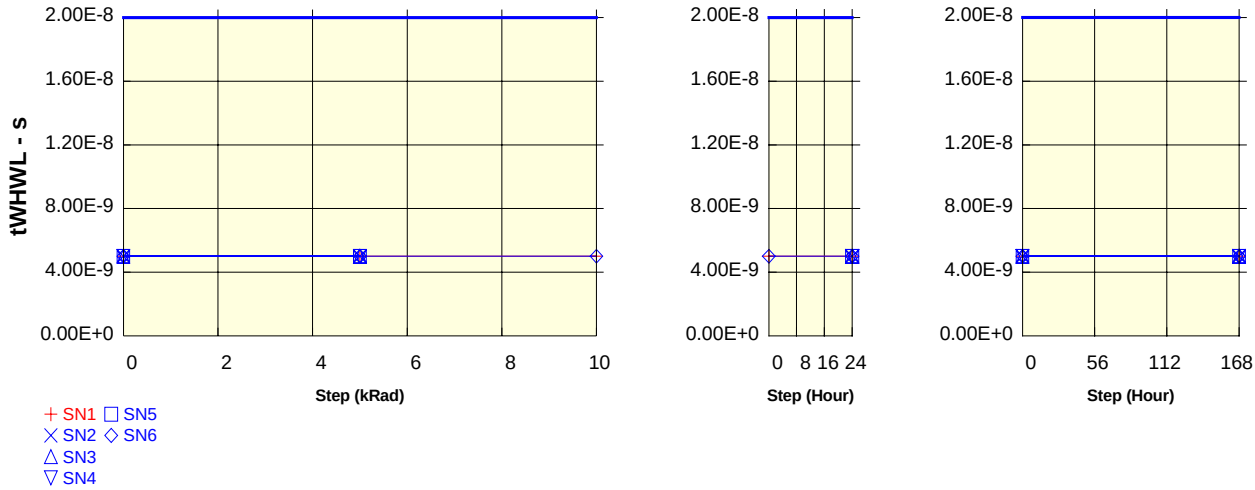
Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	1.20E-8	1.20E-8
SN2		
SN3		
SN4		
SN5		
SN6	1.21E-8	1.21E-8
Statistics		
Min		0.00E+0
Max		1.21E-8
Mean		2.42E-9
Sigma		5.41E-9

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	1.20E-8	1.19E-8
SN2		2.85E-8
SN3		1.22E-8
SN4		1.20E-8
SN5		1.20E-8
SN6	1.21E-8	1.20E-8
Statistics		
Min		1.20E-8
Max		2.85E-8
Mean		1.53E-8
Sigma		7.36E-9

Test conditions : TID
Parameter : Write Pulse Width High : tWHWL
-
Unit : s
Spec Limit Max : 2.00E-8
Spec limits are represented in bold lines on the graphic.



Test TST001 : Exposure

	0 kRad	5 kRad	10 kRad
SN1	5.00E-9	5.00E-9	5.00E-9
SN2	5.00E-9	5.00E-9	
SN3	5.00E-9	5.00E-9	
SN4	5.00E-9	5.00E-9	
SN5	5.00E-9	5.00E-9	
SN6	5.00E-9	5.00E-9	5.00E-9
Statistics			
Min	5.00E-9	5.00E-9	0.00E+0
Max	5.00E-9	5.00E-9	5.00E-9
Mean	5.00E-9	5.00E-9	1.00E-9
Sigma	0.00E+0	0.00E+0	2.24E-9

Test TST002 : Annealing 24h

	0 Hour	24 Hour
SN1	5.00E-9	5.00E-9
SN2		5.00E-9
SN3		5.00E-9
SN4		5.00E-9
SN5		5.00E-9
SN6	5.00E-9	5.00E-9
Statistics		
Min		5.00E-9
Max		5.00E-9
Mean		5.00E-9
Sigma		0.00E+0

Test TST003 : Annealing 168h

	0 Hour	168 Hour
SN1	5.00E-9	5.00E-9
SN2	5.00E-9	5.00E-9
SN3	5.00E-9	5.00E-9
SN4	5.00E-9	5.00E-9
SN5	5.00E-9	5.00E-9
SN6	5.00E-9	5.00E-9
Statistics		
Min	5.00E-9	5.00E-9
Max	5.00E-9	5.00E-9
Mean	5.00E-9	5.00E-9
Sigma	0.00E+0	0.00E+0